IV

Manufacturing Co., Ltd.

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• Please refer to "Specifications and Test Methods" at the end of each chapter of 14 - 19 .

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Part Numbering

Chip Monolithic Ceramic Capacitors

GR M 18 8 B1 1H 102 K A01 K (Part Number) 0 2 3 4 5 6 7 8 9 0

1 Product ID

2Series

Product ID	Code	Series		
	М	Tin Plated Layer		
GR	4	Only for Information Devices / Tip & Ring		
	7	Only for Camera Flash Circuit		
ER	В	High Frequency Type		
GQ	M	High Frequency for Flow/Reflow Soldering		
GM	Α	Monolithic Microchip		
GN	M	Capacitor Array		
	L Low ESL Wide Width T			
LL	Α	Eight-termination Low ESL Type		
	M	Ten-termination Low ESL Type		
GJ	М	High Frequency Low Loss Type Tin Plated Type		
GA	2	for AC250V (r.m.s.)		
GA	3	Safety Standard Recognized Type		

3Dimension (LXW)

Code	Dimension (LXW)	EIA		
02	0.4×0.2mm	01005		
03	0.6×0.3mm	0201		
05	0.5×0.5mm	0202		
08	0.8×0.8mm	0303		
11	1.25×1.0mm	0504		
15	1.0×0.5mm	0402		
18	1.6×0.8mm	0603		
1D	1D 1.4×1.4mm			
1X	Depends on individual standards.			
21	2.0×1.25mm	0805		
22	22 2.8×2.8mm			
31	31 3.2×1.6mm			
32	3.2×2.5mm	1210		
3X	Depends on individual	standards.		
42	4.5×2.0mm	1808		
43	4.5×3.2mm	1812		
52	5.7×2.8mm 2211			
55	5.7×5.0mm	2220		

4 Dimension (T)

Code	Dimension (T)			
2	0.2mm			
2	2-elements (Array Type)			
3	0.3mm			
4	4-elements (Array Type)			
5	0.5mm			
6	0.6mm			
7	0.7mm			
8	0.8mm			
9	0.85mm			
Α	1.0mm			
В	1.25mm			
С	1.6mm			
D	2.0mm			
E	2.5mm			
F	3.2mm			
М	1.15mm			
N	1.35mm			
R	1.8mm			
s	2.8mm			
Q	1.5mm			
Х	Depends on individual standards.			

With the array type GNM series, "Dimension(T)" indicates the number of elements.

Continued on the following page. $\begin{tabular}{|c|c|c|c|} \hline \end{tabular}$







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⑤Temperature Characteristics

Temperature Characteristic Codes							
Code	Public STD (Code	Referance Temperature	Temperature Range	Capacitance Change or Temperature Coefficient	Operating Temperature Range	
1X	SL *1	JIS	20°C	20 to 85°C	+350 to -1000ppm/°C	-55 to 125°C	
2C	CH *1	JIS	20°C	20 to 125°C	0±60ppm/°C	-55 to 125°C	
2P	PH *1	JIS	20°C	20 to 85°C	-150±60ppm/°C	-25 to 85°C	
2R	RH *1	JIS	20°C	20 to 85°C	-220±60ppm/°C	-25 to 85°C	
2S	SH *1	JIS	20°C	20 to 85°C	-330±60ppm/°C	-25 to 85°C	
2T	TH *1	JIS	20°C	20 to 85°C	-470±60ppm/°C	-25 to 85°C	
3C	CJ *1	JIS	20°C	20 to 125°C	0±120ppm/°C	-55 to 125°C	
3P	PJ *1	JIS	20°C	20 to 85°C	-150±120ppm/°C	-25 to 85°C	
3R	RJ *1	JIS	20°C	20 to 85°C	-220±120ppm/°C	-25 to 85°C	
38	SJ *1	JIS	20°C	20 to 85°C	-330±120ppm/°C	-25 to 85°C	
3T	TJ *1	JIS	20°C	20 to 85°C	-470±120ppm/°C	-25 to 85°C	
3U	UJ *1	JIS	20°C	20 to 85°C	-750±120ppm/°C	-25 to 85°C	
4C	CK *1	JIS	20°C	20 to 125°C	0±250ppm/°C	-55 to 125°C	
5C	C0G *1	EIA	25°C	25 to 125°C	0±30ppm/°C	-55 to 125°C	
5G	X8G *1	EIA	25°C	25 to 150°C	0±30ppm/°C	-55 to 150°C	
6C	C0H *1	EIA	25°C	25 to 125°C	0±60ppm/°C	-55 to 125°C	
6P	P2H *1	EIA	25°C	25 to 85°C	-150±60ppm/°C	-55 to 125°C	
6R	R2H *1	EIA	25°C	25 to 85°C	-220±60ppm/°C	-55 to 125°C	
6S	S2H *1	EIA	25°C	25 to 85°C	-330±60ppm/°C	-55 to 125°C	
6T	T2H *1	EIA	25°C	25 to 85°C	-470±60ppm/°C	-55 to 125°C	
7U	U2J *1	EIA	25°C	25 to 85°C	-750±120ppm/°C	-55 to 125°C	
B1	B *2	JIS	20°C	-25 to 85°C	±10%	-25 to 85°C	
В3	В	JIS	20°C	-25 to 85°C	±10%	-25 to 85°C	
C7	X7S	EIA	25°C	-55 to 125°C	±22%	-55 to 125°C	
C8	X6S	EIA	25°C	-55 to 105°C	±22%	-55 to 105°C	
F1	F *2	JIS	20°C	-25 to 85°C	+30, -80%	-25 to 85°C	
F5	Y5V	EIA	25°C	-30 to 85°C	+22, -82%	-30 to 85°C	
L8	X8L	EIA	25°C	-55 to 150°C	+15, -40%	-55 to 150°C	
R1	R *2	JIS	20°C	-55 to 125°C	±15%	-55 to 125°C	
R3	R	JIS	20°C	-55 to 125°C	±15%	-55 to 125°C	
R6	X5R	EIA	25°C	-55 to 85°C	±15%	-55 to 85°C	
R7	X7R	EIA	25°C	-55 to 125°C	±15%	-55 to 125°C -55 to 150°C	
R9	X8R	EIA	25°C	-55 to 150°C	±15%		
		**	2000	-25 to 20°C	-4700+1000/-2500ppm/°C	05.10502	
9E	ZLM	*3	20°C 20 to 85°C	-4700+500/-1000ppm/°C	-25 to 85°C		
14/0			25.0	FE 1- 10500	±10% *4	FE / 1050C	
W0	-	-	25°C	-55 to 125°C	+22, -33% *5	-55 to 125°C	

^{*1} Please refer to table for Capacitance Change under reference temperature.

Continued on the following page. $\begin{tabular}{|c|c|c|c|} \hline \end{tabular}$





^{*2} Capacitance change is specified with 50% rated voltage applied.

^{*3,*4} Murata Temperature Characteristic Code.

^{*4} Apply DC350V bias.

^{*5} No DC bias.

● Capacitance Change from each temperature

JIS Code

			Capacitance Char	nge from 20°C (%)		
Murata Code	−55°C		−25°C		−10°C	
	Max.	Min.	Max.	Min.	Max.	Min.
1X	-	-	-	-	-	-
2C	0.82	-0.45	0.49	-0.27	0.33	-0.18
2P	-	-	1.32	0.41	0.88	0.27
2R	-	-	1.70	0.72	1.13	0.48
28	_	-	2.30	1.22	1.54	0.81
2T	_	-	3.07	1.85	2.05	1.23
3C	1.37	-0.90	0.82	-0.54	0.55	-0.36
3P	-	-	1.65	0.14	1.10	0.09
3R	-	-	2.03	0.45	1.35	0.30
38	-	-	2.63	0.95	1.76	0.63
3T	-	-	3.40	1.58	2.27	1.05
3U	-	-	4.94	2.84	3.29	1.89
4C	2.56	-1.88	1.54	-1.13	1.02	-0.75

EIA Code

			Capacitance Char	nge from 25°C (%)		
Murata Code	-55	5°C	-30°C		−10°C	
	Max.	Min.	Max.	Min.	Max.	Min.
5C/5G	0.58	-0.24	0.40	-0.17	0.25	-0.11
6C	0.87	-0.48	0.59	-0.33	0.38	-0.21
6P	2.33	0.72	1.61	0.50	1.02	0.32
6R	3.02	1.28	2.08	0.88	1.32	0.56
6S	4.09	2.16	2.81	1.49	1.79	0.95
6T	5.46	3.28	3.75	2.26	2.39	1.44
7U	8.78	5.04	6.04	3.47	3.84	2.21

6 Rated Voltage

Code	Rated Voltage			
0G	DC4V			
0J	DC6.3V			
1A	DC10V			
1C	DC16V			
1E	DC25V			
1H	DC50V			
2A	DC100V			
2D	DC200V			
2E	DC250V			
YD	DC300V			
2H	DC500V			
2J	DC630V			
3A	DC1kV			
3D	DC2kV			
3F	DC3.15kV			
ВВ	DC350V (for Camera Flash Circuit)			
E2	AC250V			
GB	X2; AC250V (Safety Standard Recognized Type GB)			
GC	X1/Y2; AC250V (Safety Standard Recognized Type GC)			
GD	Y3; AC250V (Safety Standard Recognized Type GD)			
GF	Y2, X1/Y2; AC250V (Safety Standard Recognized Type GF)			

Capacitance

Expressed by three-digit alphanumerics. The unit is pico-farad (pF). The first and second figures are significant digits, and the third figure expresses the number of zeros which follow the two numbers.If there is a decimal point, it is expressed by the capital letter "R". In this case, all figures are significant digits.

Ex.)	Code	Capacitance
	R50	0.5pF
	1R0	1.0pF
	100	10pF
	103	10000pF

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8 Capacitance Tolerance

Code	Capacitance Tolerance	TC	Series	Capaci	tance Step
W	±0.05pF	СΔ	GRM/GJM	≦9.9pF	0.1pF
В	±0.1pF	СΔ	GRM/GJM	≦9.9pF	0.1pF
		СΔ	GRM/GJM	≦9.9pF	0.1pF
С	±0.25pF	except CΔ	GRM	≦5pF	* 1pF
		СΔ	ERB/GQM	≦5pF	* 1pF
		СΔ	GRM/GJM	5.1 to 9.9pF	0.1pF
D	±0.5pF	except CΔ	GRM	5.1 to 9.9pF	* 1pF
		СΔ	ERB/GQM	5.1 to 9.9pF	* 1pF
	±2%	СΔ	GJM	≥10pF	E12 Series
G		СΔ	GQM	≥10pF	E24 Series
	150/	CΔ-SL	GRM/GA3	≥10pF	E12 Series
J	±5%	СΔ	ERB/GQM/GJM	≥10pF	E24 Series
1/	.100/	D D V7D V5D 7114	GRM/GR7/GA3	E6	Series
K	±10%	B, R, X7R, X5R, ZLM	GR4	E12	Series
	±20%	Z5U	GRM	E3	Series
M		B, R, X7R, X7S	GRM/GMA/LLL/LLA/LLM	E6	Series
		X7R	GA2	E3	Series
Z	+80%, -20%	F, Y5V	GRM	E3 Series	
R	Depends on individual standards.				

^{*} E24 series is also available.

Individual Specification Code

Expressed by three figures.

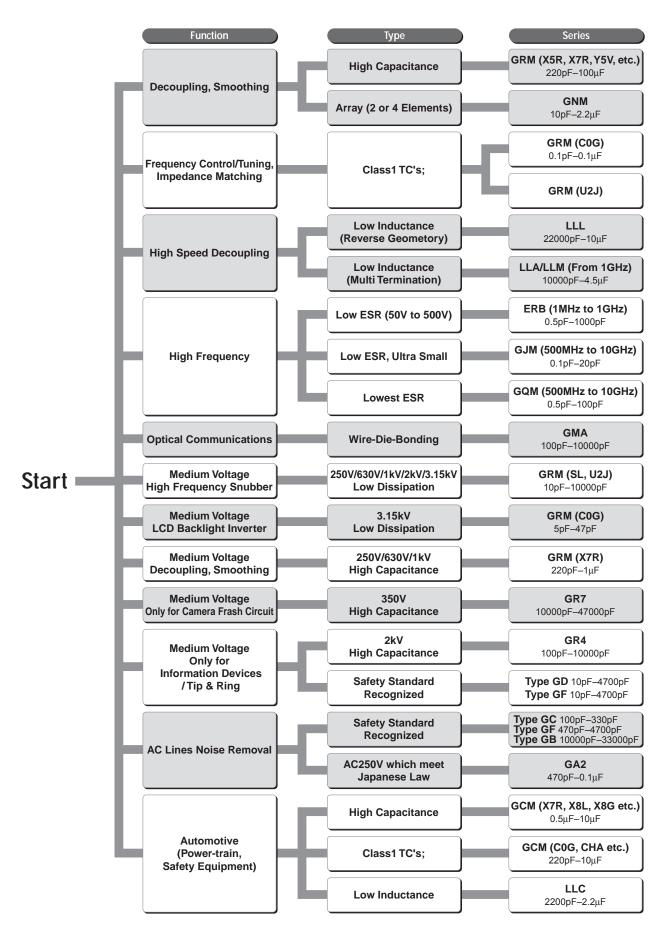
Packaging

Packaging			
ø180mm Embossed Taping			
ø180mm Paper Taping			
ø330mm Embossed Taping			
ø330mm Paper Taping			
Bulk			
Bulk Case			
Bulk Tray			

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Selection Guide of Chip Monolithic Ceramic Capacitors



Chip Monolithic Ceramic Capacitors

muRata

for General Purpose GRM15/18/21/31 Series

■ Features

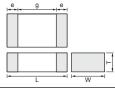
- Terminations are made of metal highly resistant to migration.
- A wide selection of sizes is available, from the miniature LxW: 1.0x0.5mm to LxW: 3.2x1.6mm.
 GRM18, 21 and GRM31 types are suited to flow and reflow soldering.
 - GRM15 type is applied to only reflow soldering.
- 3. Smaller size and higher capacitance value
- 4. High reliability and no polarity
- 5. Excellent pulse responsibility and noise reduction due to the low impedance at high frequency.
- 6. Ta replacement

Applications

Dart Number

General electronic equipment





Part Number		Dir	nensions (n	nm)	
Part Number	L	W	T	е	g min.
GRM155	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.35	0.3
GRM185	1.6 ±0.1	0.8 +0.1	0.5 +0/-0.1	0.2 to 0.5	0.5
GRM188*	1.0 ±0.1	0.6 ±0.1	0.8 ±0.1	0.2 10 0.5	0.5
GRM216			0.6 ±0.1		
GRM219	2.0 +0.1	1.25 +0.1	0.85 ±0.1	0.2 to 0.7	0.7
GRM21A	2.0 ±0.1	1.23 ±0.1	1.0 +0/-0.2	0.2 10 0.7	0.7
GRM21B			1.25 ±0.1		
GRM316			0.6 ±0.1		
GRM319	3.2 ±0.15	1.6 ±0.15	0.85 ±0.1	0.3 to 0.8	1.5
GRM31M			1.15 ±0.1	0.3 10 0.8	1.5
GRM31C	3.2 ±0.2	1.6 ±0.2	1.6 ±0.2		

^{*} Bulk Case: 1.6 ±0.07(L) × 0.8 ±0.07(W) × 0.8 ±0.07(T)

Temperature Compensating Type GRM15 Series (1.00x0.50mm) 50/25V

Part Number				GR	M15			
L x W [EIA]				1.0x0.5	[0402]			
тс	C0G (5C)	P2H (6P)	R2H (6R)	S2H (6S)		X)	T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	50 (1H)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	50 (1H)
Capacitance (Cap	acitance part n	numbering code)	and T (mm) Dim	ension (T Dimen	sion part numbe	ring code)		
3.0pF(3R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5(5)	0.5(5)
4.0pF(4R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5 (5)	0.5(5)
5.0pF(5R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5 (5)	0.5(5)
6.0pF(6R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5 (5)	0.5(5)
7.0pF(7R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5 (5)	0.5(5)
8.0pF(8R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5(5)	0.5(5)
9.0pF(9R0)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5 (5)	0.5(5)
10pF(100)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)			0.5 (5)	0.5(5)
12pF(120)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
15pF(150)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
18pF(180)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
22pF(220)	0.5(5)	0.5 (5)	0.5(5)	0.5(5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
27pF(270)	0.5(5)	0.5(5)	0.5 (5)	0.5 (5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
33pF(330)	0.5(5)		0.5(5)	0.5(5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
39pF(390)	0.5(5)			0.5 (5)	0.5(5)	0.5(5)	0.5 (5)	0.5(5)
47pF(470)	0.5(5)				0.5(5)	0.5(5)	0.5 (5)	0.5(5)
56pF(560)	0.5(5)				0.5(5)	0.5(5)	0.5 (5)	0.5(5)
68pF(680)	0.5(5)				0.5(5)	0.5(5)	0.5 (5)	0.5(5)
82pF(820)	0.5(5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
100pF(101)	0.5(5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
120pF(121)	0.5(5)				0.5(5)	0.5 (5)		0.5(5)
150pF(151)	0.5(5)				0.5(5)	0.5 (5)		0.5(5)
180pF(181)	0.5(5)				0.5(5)	0.5(5)		0.5(5)
220pF(221)	0.5(5)					0.5(5)		
270pF(271)	0.5(5)					0.5(5)		

Part Number				GRI	VI15			
L x W [EIA]				1.0x0.5	[0402]			
тс	C0G (5C)	P2H (6P)	R2H (6R)	S2H (6S)		SL I X)	T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	50 (1H)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	50 (1H)
Capacitance (Cap	pacitance part n	umbering code)	and T (mm) Dim	ension (T Dimen	sion part numbe	ering code)		
330pF(331)	0.5 (5)					0.5 (5)		
390pF(391)	0.5(5)					0.5 (5)		
470pF(471)	0.5(5)							
560pF(561)	0.5(5)							
680pF(681)	0.5(5)							
820pF(821)	0.5(5)							
1000pF(102)	0.5(5)							

The part numbering code is shown in $\ (\).$

Dimensions are shown in mm and Rated Voltage in Vdc.

Temperature Compensating Type GRM18 Series (1.60x0.80mm) 100/50V

Part Number							GR	M18						
L x W [EIA]							1.6x0.8	3 [0603]						
тс		DG C)		2H P)		2H R)		2H (S)		SL X)		2H ST)		2J U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	pacitanc	e part nu	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberir	ng code)				
0.50pF(R50)	0.8(8)													
3.0pF(3R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
4.0pF(4R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
5.0pF(5R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
6.0pF(6R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
7.0pF(7R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
8.0pF(8R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
9.0pF(9R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
10pF(100)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)		0.8(8)	
12pF(120)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
15pF(150)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
18pF(180)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
22pF(220)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
27pF(270)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
33pF(330)	0.8(8)		0.8(8)	0.8(8)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
39pF(390)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)		0.8(8)		0.8(8)		0.8(8)	
47pF(470)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)		. ,		0.8(8)	
56pF(560)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
68pF(680)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
82pF(820)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
100pF(101)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
120pF(121)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)			0.8(8)	0.8(8)	
150pF(151)	0.8(8)		, ,	0.8(8)	0.8(8)	0.8(8)	. ,	0.8(8)	0.8(8)			0.8(8)	0.8(8)	
180pF(181)	0.8(8)			. ,	.,	0.8(8)		0.8(8)	0.8(8)			0.8(8)	0.8(8)	
220pF(221)	0.8(8)					. (-,		0.8(8)	0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
270pF(271)	0.8(8)							- (-,	0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
330pF(331)	0.8(8)								0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
390pF(391)	0.8(8)								0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
470pF(471)	0.8(8)								(-)	0.8(8)		0.8(8)	(-)	0.8(8)
560pF(561)	0.8(8)									0.8(8)		(-)		0.8(8)
680pF(681)	0.8(8)									0.8(8)				0.8(8)
820pF(821)	0.8(8)				-					0.5(0)		-		0.0(0)

Part Number							GR	M18						
L x W [EIA]							1.6x0.8	3 [0603]						
тс		0G C)		2H P)		2H i R)		2H (S)		X)		2H T)		2J 'U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	pacitanc	e part nur	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberin	g code)				
1000pF(102)	0.8(8)									0.8(8)				0.8(8)
1200pF(122)		0.8(8)								0.8(8)				0.8(8)
1500pF(152)		0.8(8)								0.8(8)				0.8(8)
1800pF(182)		0.8(8)								0.8(8)				0.8(8)
2200pF(222)		0.8(8)								0.8(8)				0.8(8)
2700pF(272)		0.8(8)								0.8(8)				0.8(8)
3300pF(332)										0.8(8)				0.8(8)
3900pF(392)										0.8(8)				0.8(8)
4700pF(472)										0.8(8)				0.8(8)
5600pF(562)										0.8(8)				0.8(8)
6800pF(682)										0.8(8)				0.8(8)
8200pF(822)										0.8(8)				0.8(8)
10000pF(103)										0.8(8)				0.8(8)

The part numbering code is shown in ().

Temperature Compensating Type GRM21 Series (2.00x1.25mm) 100/50V

Part Number							GR	M21						
L x W [EIA]							2.0x1.2	5 [0805]						
тс	C((5			2H P)		2H R)		2H S)		X)		2H T)		2J 'U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	pacitance	e part nur	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberin	g code)	I.			-
33pF(330)				0.6(6)										
39pF(390)				0.6(6)		0.6(6)								
47pF(470)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
56pF(560)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
68pF(680)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
82pF(820)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
100pF(101)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
120pF(121)				0.6(6)		0.6(6)		0.6(6)			1.25(B)	0.6(6)		
150pF(151)			0.85(9)	0.6(6)		0.6(6)	0.85(9)	0.6(6)			1.25(B)			
180pF(181)			0.85(9)	0.85(9)	0.85(9)	0.6(6)	0.85(9)	0.6(6)			1.25(B)			
220pF(221)			0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.6(6)		0.6(6)	1.25(B)			0.6(6)
270pF(271)			0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)			0.6(6)				0.6(6)
330pF(331)			0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)			0.6(6)				0.6(6)
390pF(391)			1.25(B)	1.25(B)	0.85(9)	0.85(9)	0.85(9)			0.6(6)				0.6(6)
470pF(471)			1.25(B)	1.25(B)	0.85(9)	0.85(9)	0.85(9)		0.85(9)	0.6(6)			0.85(9)	0.6(6)
560pF(561)				1.25(B)	1.25(B)	0.85(9)	1.25(B)	0.85(9)	0.85(9)	0.6(6)		1.25(B)	0.85(9)	0.6(6)
680pF(681)	0.6(6)					1.25(B)		1.25(B)	0.85(9)	0.6(6)		1.25(B)	0.85(9)	0.6(6)
820pF(821)	0.6(6)							1.25(B)	1.25(B)	0.6(6)		1.25(B)	1.25(B)	0.6(6)
1000pF(102)	0.85(9)								1.25(B)	0.6(6)		1.25(B)	1.25(B)	0.6(6)
1200pF(122)	0.85(9)	0.6(6)							1.25(B)	0.6(6)		1.25(B)	1.25(B)	0.6(6)
1500pF(152)	0.85(9)	0.6(6)							1.25(B)	0.85(9)		1.25(B)	1.25(B)	0.85(9
1800pF(182)		0.6(6)							1.25(B)	0.85(9)		1.25(B)	1.25(B)	0.85(9
2200pF(222)		0.6(6)								0.85(9)				0.85(9
2700pF(272)		0.6(6)								1.25(B)				1.25(B
3300pF(332)		0.6(6)								1.25(B)				1.25(B
3900pF(392)		0.6(6)												

Dimensions are shown in mm and Rated Voltage in Vdc.

Part Number							GR	M21						
L x W [EIA]							2.0x1.2	5 [0805]						
тс	C(5)	OG C)		2H i P)		2H R)		2H S)		SL (X)		2H T)		12J 7U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	pacitance	e part nur	nbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberir	ng code)				
4700pF(472)		0.6(6)												
5600pF(562)		0.85(9)												
6800pF(682)		0.85(9)												
8200pF(822)		0.85(9)												
10000pF(103)		0.85(9)								0.6(6)				0.6(6)
12000pF(123)		0.85(9)								0.6(6)				0.6(6)
15000pF(153)		0.85(9)								0.6(6)				0.6(6)
18000pF(183)		1.25(B)								0.6(6)				0.6(6)
22000pF(223)		1.25(B)								0.85(9)				0.85(9)
27000pF(273)										0.85(9)				0.85(9)
33000pF(333)										1.0(A)				1.0(A)
39000pF(393)										1.25(B)				1.25(B)
47000pF(473)										1.25(B)				1.25(B)

The part numbering code is shown in ().

Temperature Compensating Type GRM31 Series (3.20x1.60mm) 100/50/25V

Part Number								GRM31							
L x W [EIA]							3.2	x1.6 [12	06]						
тс		C0G (5C)			2H P)		2H R)	S2 (6	2H S)	S (1	X)		2H T)	U2 (7)	
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	100 (2A)	50 (1H)										
Capacitance (Ca	pacitano	e part n	umbering	code) ar	nd T (mm) Dimens	ion (T Di	mension	part nun	nbering c	ode)				
47pF(470)												0.85(9)			
56pF(560)												0.85(9)			
68pF(680)												0.85(9)			
82pF(820)												0.85(9)			
100pF(101)												1.15(M)			
120pF(121)												1.15(M)			
150pF(151)												1.15(M)			
180pF(181)					0.6(6)							1.15(M)			
220pF(221)					0.6(6)		0.6(6)					1.15(M)			
270pF(271)					0.6(6)		0.6(6)		0.6(6)			1.15(M)			
330pF(331)					0.6(6)		0.6(6)		0.6(6)			1.15(M)			
390pF(391)				0.85(9)			0.6(6)		0.6(6)			1.15(M)			
470pF(471)				0.85(9)					0.6(6)			1.15(M)			
560pF(561)				0.85(9)		0.85(9)		0.85(9)	0.85(9)						
680pF(681)				0.85(9)		0.85(9)	0.85(9)	0.85(9)	0.85(9)						
820pF(821)				0.85(9)		0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)			1.15(M)	0.85(9)	
1000pF(102)				1.15(M)		1.15(M)	1.15(M)	0.85(9)	0.85(9)	0.85(9)			1.15(M)	0.85(9)	
1200pF(122)				1.15(M)		1.15(M)	1.15(M)	1.15(M)	1.15(M)	0.85(9)			1.15(M)	0.85(9)	
1500pF(152)					1.15(M)		1.15(M)	1.15(M)	1.15(M)	0.85(9)			1.15(M)	0.85(9)	
1800pF(182)	0.85(9)								1.15(M)	0.85(9)			1.15(M)	0.85(9)	
2200pF(222)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
2700pF(272)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
3300pF(332)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
3900pF(392)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
4700pF(472)	0.85(9)									1.15(M)				1.15(M)	
5600pF(562)	0.85(9)														

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Dimensions are shown in mm and Rated Voltage in Vdc.

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Part Number								GRM31							
L x W [EIA]							3.2	2x1.6 [12	06]						
тс		C0G (5C)		P2 (6			2H R)		2H S)		X)		2H T)		2J 'U)
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	100 (2A)	50 (1H)										
Capacitance (Ca	pacitano	ce part nu	ımbering	code) ar	nd T (mm) Dimens	ion (T Di	mension	part nun	nbering o	ode)				
18000pF(183)		0.85(9)													
22000pF(223)		0.85(9)													
27000pF(273)		0.85(9)													
33000pF(333)		0.85(9)													
39000pF(393)		1.15(M)													
47000pF(473)		1.15(M)													
56000pF(563)		1.6(C)									0.85(9)				0.85(9)
68000pF(683)		1.6(C)									1.15(M)				1.15(M)
82000pF(823)		1.6(C)									1.15(M)				1.15(M)
0.10μF(104)			1.6(C)								1.15(M)				1.15(M)

The part numbering code is shown in ().

High Dielectric Constant Type X5R (R6) Characteristics

тс										X5R (R6)									
Part Number			GRM15	5				GRM18	3			GR	M21				GRM31	l	
L x W [EIA]		1.0	x0.5 [0	402]			1.6	x0.8 [0	603]		2	2.0x1.2	5 [080	5]		3.2	x1.6 [1:	206]	
Rated Volt.	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)
Capacitance (Ca	pacita	nce pa	rt numb	pering o	code) a	nd T (n	nm) Din	nensio	n (T Din	nensior	n part r	number	ing cod	le)				•	
1000pF (102)	0.5 (5)	0.5 (5)																	
2200pF (222)	0.5 (5)	0.5 (5)																	
4700pF (472)	0.5 (5)	0.5 (5)																	
10000pF (103)						0.8													
22000pF (223)			0.5 (5)			0.8													
33000pF (333)			0.5 (5)	0.5 (5)															
47000pF (473)			0.5 (5)	0.5 (5)															
68000pF (683)			0.5 (5)	0.5 (5)															
0.10μF (104)			0.5 (5)	0.5 (5)			0.8 (8)												
0.15μF (154)				0.5* (5)	0.5* (5)														
0.22μF (224)				0.5* (5)	0.5* (5)		0.8 (8)	0.8 (8)											
0.33μF (334)				0.5* (5)	0.5* (5)														
0.47μF (474)				0.5* (5)	0.5* (5)		0.8* (8)	0.8* (8)											
0.68μF (684)				0.5* (5)	0.5* (5)														

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Dimensions are shown in mm and Rated Voltage in Vdc.

тс										X5R (R6)									
Part Number			GRM15	5				GRM18	3			GRI	W21				GRM31	I	
L x W [EIA]		1.0	x0.5 [0	402]			1.6	(0.8 [0	503]		2	.0x1.2	5 [0805	5]		3.2	x1.6 [12	206]	
Rated Volt.	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	(0G)
Capacitance (Ca	pacita	nce pa	rt numk	pering o	code) a	nd T (m	nm) Din	nensior	n (T Din	nensior	n part n	umber	ing cod	le)				-	
1.0μF (105)				0.5* (5)	0.5* (5)		0.8* (8)	0.8* (8)											
2.2μF (225)								0.8* (8)	0.8* (8)	0.8* (8)	1.25* (B)					1.15 (M)			
3.3μF (335)									0.8* (8)		1.25* (B)	1.25* (B)				1.6 (C)			
4.7μF (475)										0.8* (8)	1.25* (B)	1.25* (B)	1.25* (B)		1.6 (C)	1.6 (C)	1.6 (C)		
10μF (106)													1.25* (B)	1.25* (B)	1.6* (C)	1.6 (C)			
15μF (156)																		1.6* (C)	
22μF (226)														1.25* (B)				1.6* (C)	
47μF (476)																		1.6* (C)	
100μF (107)																		1.6* (C)	1.6* (C)

The part numbering code is shown in each ().

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type X6S (C8) Characteristics

тс						X6S (C8)							
Part Number	GR	M15	GR	M18		GR	M21			GRM31			
L x W [EIA]	1.0x0.5	5 [0402]	1.6x0.8	1.6x0.8 [0603] 2.0x1.25 [0805]						3.2x1.6 [1206]			
Rated Volt.	6.3 (0J)	4 (0G)	6.3 (0J)	4 (0G)	25 (1E)	16 (1C)	6.3 (0J)	4 (0G)	10 (1A)	6.3 (0J)	(0G)		
Capacitance (Ca	pacitance p	oart number	ing code) an	d T (mm) Di	mension (T	Dimension p	art numberi	ng code)	'				
0.15μF(154)	0.5*(5)												
0.22μF(224)	0.5*(5)												
0.33μF(334)	0.5*(5)												
0.47μF(474)	0.5*(5)												
0.68μF(684)		0.5*(5)	0.8(8)										
1.0μF(105)		0.5*(5)											
2.2μF(225)			0.8*(8)										
4.7μF(475)				0.8*(8)	1.25*(B)	1.25*(B)							
10μF(106)							1.25*(B)		1.15*(M)				
22μF(226)								1.25*(B)		1.6*(C)	1.6*(C)		
47μF(476)											1.6*(C)		

The part numbering code is shown in ().



 $^{3.3\}mu F$ and $4.7\mu F,\,6.3V$ rated are GRM21 series of L: 2±0.15, W: 1.25±0.15, T: 1.25±0.15.

T: 1.15 \pm 0.1mm is also available for GRM31 1.0 μ F for 16V.

L: 3.2 ± 0.2 , W: 1.6 ± 0.2 for GRM31 16V $1.0\mu F$ type. Also L: 3.2 ± 0.2 , W: 1.6 ± 0.2 , T: 1.15 ± 0.15 for GRM31 16V $1.5\mu F$ and $2.2\mu F$ type.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

High Dielectric Constant Type X7R (R7) Characteristics

тс												7R ? 7)										
Part Number		(GRM1	5				GR	M18					GR	M21				(GRM3	1	
L x W [EIA]		1.0x	0.5 [0	402]			1	.6x0.8	8 [060	3]			2.	0x1.2	5 [080	5]			3.2x	1.6 [1	206]	
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacita	ance p	art nu	ımberi	ng co	de) an	d T (m	m) Di	mensi	on (T I	Dimen	sion p	art nu	mberi	ng co	de)		1			1	
220pF (221)		0.5 (5)				0.8 (8)																
330pF (331)		0.5 (5)				0.8 (8)																
470pF (471)		0.5 (5)				0.8 (8)																
680pF (681)		0.5 (5)				0.8 (8)																
1000pF (102)		0.5 (5)				0.8 (8)																
1500pF (152)		0.5 (5)				0.8																
2200pF (222)		0.5 (5)				0.8																
3300pF (332)		0.5 (5)				0.8																
4700pF (472)	0.5 (5)	0.5 (5)										0.85 (9)										
6800pF (682)		0.5 (5)	0.5 (5)									0.85 (9)										
10000pF (103)		0.5 (5)	0.5 (5)									1.25 (B)										
15000pF (153)			0.5 (5)	0.5 (5)			0.8 (8)					1.25 (B)										
22000pF (223)			0.5 (5)	0.5 (5)			0.8 (8)					1.25 (B)										
33000pF (333)			0.5 (5)	0.5 (5)	0.5 (5)		0.8 (8)					1.25 (B)										
47000pF (473)			0.5 (5)	0.5 (5)	0.5 (5)		0.8 (8)					1.25 (B)										
68000pF (683)				0.5 (5)	0.5 (5)		0.8 (8)	0.8 (8)										1.15 (M)				
0.10μF (104)				0.5 (5)	0.5 (5)		0.8 (8)	0.8 (8)														
0.15μF (154)								0.8 (8)	0.8 (8)				1.25 (B)						1.15 (M)			
0.22μF (224)								0.8 (8)	0.8 (8)	0.8 (8)		1.0 (A)	1.25 (B)						0.85 (9)			
0.33μF (334)									0.8 (8)	0.8 (8)		1.0 (A)	0.85 (9)	1.25 (B)								
0.47μF (474)								0.8* (8)	0.8 (8)	0.8 (8)	0.8 (8)		1.25 (B)	0.85 (9)					1.15 (M)			
0.68μF (684)										0.8 (8)				0.85 (9)	0.85 (9)							
1.0μF (105)									0.8* (8)	0.8* (8)	0.8* (8)			1.25 (B)	1.25 (B)			1.6 (C)	1.15 (M)	1.15 (M)		
1.5μF (155)														1.25 (B)	1.25 (B)				1.6 (C)	1.15 (M)	1.15 (M)	~ [Z

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тс											X (R	7R 7)										
Part Number		(GRM1	5				GRI	M18					GRI	M21				(GRM3	1	
L x W [EIA]		1.0x0.5 [0402] 1.6x0.8 [0603]								2.	0x1.2	5 [080	5]		3.2x1.6 [1206]							
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacita	ance p	art nu	mberi	ng co	de) an	d T (m	m) Dii	mensi	on (T I	Dimen	sion p	art nu	mberi	ng co	de)				'		
2.2μF (225)										0.8* (8)				1.25* (B)	1.25* (B)				1.6 (C)		1.15 (M)	
3.3μF (335)															1.25* (B)					1.6 (C)	1.6 (C)	
4.7μF (475)															1.25* (B)	1.25* (B)				1.6 (C)	1.6 (C)	1.6 (C)
10μF (106)																1.25* (B)	1.25* (B)				1.6* (C)	

The part numbering code is shown in each ().

High Dielectric Constant Type X7S (C7) Characteristics

тс		X7S (C7)	
Part Number	GRM18	GRM21	GRM31
L x W [EIA]	1.6x0.8 [0603]	2.0x1.25 [0805]	3.2x1.6 [1206]
Rated Volt.	6.3 (0J)	10 (1A)	4 (0G)
Capacitance (Ca	apacitance part numbering code) and T (mm	n) Dimension (T Dimension part numbering o	code)
2.2μF(225)	0.8*(8)		
3.3μF(335)		1.25*(B)	
22μF(226)			1.6*(C)

The part numbering code is shown in $\ (\).$

High Dielectric Constant Type Y5V (F5) Characteristics

тс						Y5V (F5)					
Part Number			GRM15			GR	M18	GR	M21	GR	M31
L x W [EIA]		1	.0x0.5 [040	2]		1.6x0.8	8 [0603]	2.0x1.2	5 [0805]	3.2x1.6 [1206]	
Rated Volt.	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	50 (1H)	25 (1E)	50 (1H)	6.3 (0J)
Capacitance (Ca	pacitance p	art numberi	ng code) an	d T (mm) Di	mension (T	Dimension p	art number	ing code)			'
1000pF(102)	0.5(5)										
2200pF(222)	0.5(5)										
4700pF(472)	0.5(5)										
10000pF(103)	0.5(5)					0.8(8)					
22000pF(223)		0.5(5)				0.8(8)					
47000pF(473)		0.5(5)	0.5(5)			0.8(8)					
0.10μF(104)		0.5(5)	0.5(5)			0.8(8)		0.85(9)	0.6(6)		
0.22μF(224)			0.5(5)			0.8(8)	0.8(8)		0.85(9)		
0.47μF(474)			0.5(5)	0.5(5)			0.8(8)	0.85(9)	0.6(6)	1.15(M)	
1.0μF(105)				0.5*(5)	0.5*(5)						
100μF(107)											1.6*(C)

The part numbering code is shown in each ().

The tolerance will be changed to L: 3.2 ± 0.2 , W: 1.6 ± 0.2 for GRM31 16V 1.0μ F type. Also L: 3.2 ± 0.2 , W: 1.6 ± 0.2 , T: 1.15 ± 0.15 for GRM31 16V 1.5μ F and 2.2μ F type. Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

T: 1.25 \pm 0.1mm is also available for GRM21 25V or 16V 1.0 μ F type.

Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Chip Monolithic Ceramic Capacitors



for General Purpose GRM32 Series

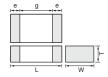
■ Features

- 1. Terminations are made of metal highly resistant to migration.
- 2. Smaller size and higher capacitance value
- 3. High reliability and no polarity
- 4. Excellent pulse responsibility and noise reduction due to the low impedance at high frequency.
- 5. Ta replacement

Applications

General electronic equipment





Part Number		D	imensions (r	nm)	
Part Number	L	W	T	е	g min.
GRM329			0.85 ±0.1		
GRM32A			1.0 +0/-0.2		
GRM32M			1.15 ±0.1		
GRM32N	3.2 +0.3	2.5 +0.2	1.35 ±0.15	0.3 min.	1.0
GRM32C	3.2 ±0.3	2.5 ±0.2	1.6 ±0.2	0.3 mm.	1.0
GRM32R			1.8 ±0.2		
GRM32D			2.0 ±0.2		
GRM32E			2.5 ±0.2		

Temperature Compensating Type GRM32 Series

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM3291X2A222JZ01	SL (JIS)	100	2200 ±5%	3.2	2.5	0.85
GRM3291X2A272JZ01	SL (JIS)	100	2700 ±5%	3.2	2.5	0.85
GRM3291X2A332JZ01	SL (JIS)	100	3300 ±5%	3.2	2.5	0.85
GRM32N1X2A562JZ01	SL (JIS)	100	5600 ±5%	3.2	2.5	1.35
GRM32N1X2A682JZ01	SL (JIS)	100	6800 ±5%	3.2	2.5	1.35

High Dielectric Constant Type GRM32 Series (3.20x2.50mm)

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (μF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM32ER61E226ME15	X5R (EIA)	25	22 ±20%*	3.2	2.5	2.5
GRM32ER61C226ME20	X5R (EIA)	16	22 ±20%*	3.2	2.5	2.5
GRM32ER61C476ME15	X5R (EIA)	16	47 ±20%*	3.2	2.5	2.5
GRM32ER61A226ME20	X5R (EIA)	10	22 ±20%*	3.2	2.5	2.5
GRM32ER61A476ME20	X5R (EIA)	10	47 ±20%*	3.2	2.5	2.5
GRM32DR60J226KA01	X5R (EIA)	6.3	22 ±10%*	3.2	2.5	2.0
GRM32DR60J336ME19	X5R (EIA)	6.3	33 ±20%*	3.2	2.5	2.0
GRM32ER60J476ME20	X5R (EIA)	6.3	47 ±20%*	3.2	2.5	2.5
GRM32ER60J107ME20	X5R (EIA)	6.3	100 ±20%*	3.2	2.5	2.5
GRM32DC81E106KA12	X6S(EIA)	25	10 ±10%	3.2	2.5	2.0
GRM32EC80J476ME64	X6S(EIA)	6.3	47 ±20%*	3.2	2.5	2.5
GRM32EC80G107ME20	X6S(EIA)	4	100 ±20%*	3.2	2.5	2.5
GRM32CR72A684KA01	X7R (EIA)	100	0.68 ±10%	3.2	2.5	1.6
GRM32CR72A105KA35	X7R (EIA)	100	1.0 ±10%	3.2	2.5	1.6
GRM32DR72A155KA35	X7R (EIA)	100	1.5 ±10%	3.2	2.5	2.0
GRM32ER72A225KA35	X7R (EIA)	100	2.2 ±10%*	3.2	2.5	2.5
GRM32ER71H105KA01	X7R (EIA)	50	1.0 ±10%	3.2	2.5	2.5
GRM32DR71H335KA88	X7R (EIA)	50	3.3 ±10%	3.2	2.5	2.0
GRM32ER71H475KA88	X7R (EIA)	50	4.7 ±10%	3.2	2.5	2.5
GRM32DR71E335KA01	X7R (EIA)	25	3.3 ±10%	3.2	2.5	2.0
GRM32DR71E475KA61	X7R (EIA)	25	4.7 ±10%	3.2	2.5	2.0
GRM32DR71E106KA12	X7R (EIA)	25	10 ±10%	3.2	2.5	2.0

 $\begin{tabular}{|c|c|c|c|}\hline \end{tabular}$ Continued from the preceding page.

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (μF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM32ER71C226ME18	X7R (EIA)	16	22 ±20%*	3.2	2.5	2.5
GRM32ER71A226ME20	X7R (EIA)	10	22 ±20%*	3.2	2.5	2.5
GRM32EF50J107ZE20	Y5V (EIA)	6.3	100 +80/-20%*	3.2	2.5	2.5

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Chip Monolithic Ceramic Capacitors

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Ultra-small GRM03 Series

■ Features

- 1. Small chip size (LxWxT: 0.6x0.3x0.3mm)
- Terminations are made of metal highly resistant to migration.
- 3. GRM03 series is suited to only reflow soldering.
- Stringent dimensional tolerances allow highly reliable, high speed automatic chip placement on PCBs
- GRM03 series is suited to miniature microwave module, portable equipment and high frequency circuits.

Part Number		Din	nensions (r	nm)	
Part Number	L	W	T	е	g min.
GRM033	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2

■ Applications

- 1. Miniature microwave module
- 2. Portable equipment
- 3. High frequency circuit

Part Number						GR	M03					
LxW						0.6x0.3	[0201]					
тс	C0G (5C)	R2H (6R)	S2H (6S)	T2H (6T)		2J 'U)		5R 86)	X6S (C8)			
Rated Volt.	25 (1E)	25 (1E)	25 (1E)	25 (1E)	50 (1 H)	25 (1E)	10 (1A)	6.3 (0J)	4 (0G)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacitance	part numb	ering code)	and T (mm) Dimensio	n (T Dimen	sion part n	umbering o	code)			
1.0pF(1R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)								
2.0pF(2R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)								
3.0pF(3R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
4.0pF(4R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
5.0pF(5R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
6.0pF(6R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
7.0pF(7R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
8.0pF(8R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
9.0pF(9R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
10pF(100)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
12pF(120)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
15pF(150)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
18pF(180)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
22pF(220)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
27pF(270)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
33pF(330)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
39pF(390)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
47pF(470)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
56pF(560)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
68pF(680)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
82pF(820)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
100pF(101)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)				0.3(3)		
150pF(151)										0.3(3)		
220pF(221)										0.3(3)		
330pF(331)										0.3(3)		
470pF(471)										0.3(3)		
680pF(681)										0.3(3)		



Part Number						GRI	M03					
LxW						0.6x0.3	8 [0201]					
тс	C0G (5C)	R2H (6R)	S2H (6S)	T2H (6T)		2J 'U)		5R 86)	X6S (C8)		X7R (R7)	
Rated Volt.	25 (1E)	25 (1E)	25 (1E)	25 (1E)	50 (1H)	25 (1E)	10 (1A)	6.3 (0J)	4 (0G)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacitance	part number	ering code)	and T (mm) Dimensio	n (T Dimen	sion part n	umbering c	ode)			•
1000pF(102)										0.3(3)		
1500pF(152)							0.3(3)			0.3(3)		0.3(3)
2200pF(222)							0.3(3)				0.3(3)	0.3(3)
3300pF(332)							0.3(3)				0.3(3)	0.3(3)
4700pF(472)							0.3(3)					0.3(3)
6800pF(682)							0.3(3)					0.3(3)
10000pF(103)							0.3(3)					0.3(3)
15000pF(153)								0.3*(3)				
22000pF(223)								0.3*(3)				
33000pF(333)								0.3*(3)				
47000pF(473)								0.3*(3)				
68000pF(683)								0.3*(3)				
0.10μF(104)								0.3*(3)	0.3(3)			

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Chip Monolithic Ceramic Capacitors

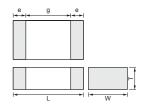


Tight Tolerance GRM03/15 Series

■ Features

- 1. Terminations are made of metal highly resistant to migration.
- 2. A wide selection of sizes is available, from the miniature LxWxT: 0.6x0.3x0.3mm or LxWxT: 1.0x0.5x0.5mm.
- 3. GRM03 type is a complete line of chip ceramic capacitors in 25V ratings, GRM15 type is a complete line of chip ceramic capacitors in 50V ratings.
- 4. These capacitors have temperature characteristics ranging C0G.
- 5. GRM03 and GRM15 type are applied to only reflow
- 6. Stringent dimensional tolerances allow highly reliable, high speed automatic chip placement on PCBs.
- 7. GRM series is available in paper tape and reel packaging for automatic placement.





Part Number		Din	nensions (r	nm)	
Part Number	L	W	T	е	g min.
GRM033	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2
GRM155	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.35	0.3

Applications

General electronic equipment

Temperature Compensating Type GRM03/15 Series

Part Number		GRM03	GRM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	pacitano	e Tolerance and T Dimension	
0.30pF(R30)	W, B	0.3(3)	0.5 (5)
0.40pF(R40)	W, B	0.3(3)	0.5(5)
0.50pF(R50)	W, B	0.3(3)	0.5(5)
0.60pF(R60)	W, B	0.3(3)	0.5(5)
0.70pF(R70)	W, B	0.3(3)	0.5(5)
0.80pF(R80)	W, B	0.3(3)	0.5(5)
0.90pF(R90)	W, B	0.3(3)	0.5(5)
1.0pF(1R0)	W, B	0.3(3)	0.5(5)
1.1pF(1R1)	W, B	0.3(3)	0.5(5)
1.2pF(1R2)	W, B	0.3(3)	0.5(5)
1.3pF(1R3)	W, B	0.3(3)	0.5(5)
1.4pF(1R4)	W, B	0.3(3)	0.5(5)
1.5pF(1R5)	W, B	0.3(3)	0.5 (5)
1.6pF(1R6)	W, B	0.3(3)	0.5 (5)
1.7pF(1R7)	W, B	0.3(3)	0.5(5)
1.8pF(1R8)	W, B	0.3(3)	0.5(5)
1.9pF(1R9)	W, B	0.3(3)	0.5(5)
2.0pF(2R0)	W, B	0.3(3)	0.5(5)
2.1pF(2R1)	W, B	0.3(3)	0.5 (5)
2.2pF(2R2)	W, B	0.3(3)	0.5(5)
2.3pF(2R3)	W, B	0.3(3)	0.5 (5)

Z Continued from	the preced	aing page.	
Part Number		GRM03	GRM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	apacitano	ce Tolerance and T Dimension	
2.4pF(2R4)	W, B	0.3(3)	0.5(5)
2.5pF(2R5)	W, B	0.3(3)	0.5(5)
2.6pF(2R6)	W, B	0.3(3)	0.5(5)
2.7pF(2R7)	W, B	0.3(3)	0.5(5)
2.8pF(2R8)	W, B	0.3(3)	0.5(5)
2.9pF(2R9)	W, B	0.3(3)	0.5(5)
3.0pF(3R0)	W, B	0.3(3)	0.5(5)
3.1pF(3R1)	W, B	0.3(3)	0.5(5)
3.2pF(3R2)	W, B	0.3(3)	0.5(5)
3.3pF(3R3)	W, B	0.3(3)	0.5(5)
3.4pF(3R4)	W, B	0.3(3)	0.5(5)
3.5pF(3R5)	W, B	0.3(3)	0.5(5)
3.6pF(3R6)	W, B	0.3(3)	0.5(5)
3.7pF(3R7)	W, B	0.3(3)	0.5(5)
3.8pF(3R8)	W, B	0.3(3)	0.5(5)
3.9pF(3R9)	W, B	0.3(3)	0.5(5)
4.0pF(4R0)	W, B	0.3(3)	0.5(5)
4.1pF(4R1) 4.2pF(4R2)	W, B W, B	0.3 (3) 0.3 (3)	0.5(5) 0.5(5)
4.2pf (4R2) 4.3pF(4R3)	W, B	0.3(3)	0.5(5)
4.4pF(4R4)	W, B	0.3(3)	0.5(5)
4.5pF(4R5)	W, B	0.3(3)	0.5(5)
4.6pF(4R6)	W, B	0.3(3)	0.5(5)
4.7pF(4R7)	W, B	0.3(3)	0.5(5)
4.8pF(4R8)	W, B	0.3(3)	0.5(5)
4.9pF(4R9)	W, B	0.3(3)	0.5(5)
5.0pF(5R0)	W, B	0.3(3)	0.5(5)
5.1pF(5R1)	W, B, C	0.3(3)	0.5(5)
5.2pF(5R2)	W, B, C	0.3(3)	0.5(5)
5.3pF(5R3)	W, B, C	0.3(3)	0.5(5)
5.4pF(5R4)	W, B, C	0.3(3)	0.5(5)
5.5pF(5R5)	W, B, C	0.3(3)	0.5 (5)
5.6pF(5R6)	W, B, C	0.3(3)	0.5(5)
5.7pF(5R7)	W, B, C	0.3(3)	0.5(5)
5.8pF(5R8)	W, B, C	0.3(3)	0.5 (5)
5.9pF(5R9)	W, B, C	0.3(3)	0.5(5)
6.0pF(6R0)	W, B, C	0.3(3)	0.5(5)
6.1pF(6R1)		0.3(3)	0.5(5)
6.2pF(6R2)	W, B, C	0.3(3)	0.5(5)
6.3pF(6R3)	W, B, C	0.3(3)	0.5(5)
6.4pF(6R4)		0.3(3)	0.5(5)
6.5pF(6R5)	W, B, C	0.3(3)	0.5(5)
6.6pF(6R6)	W, B, C	0.3(3)	0.5(5)
6.7pF(6R7)	W, B, C	0.3(3)	0.5(5)
6.8pF(6R8)	W, B, C	0.3(3)	0.5(5) 0.5(5)
6.9pF(6R9)	W, B, C	0.3(3)	0.5(5)
7.0pF(7R0) 7.1pF(7R1)	W, B, C W, B, C	0.3 (3) 0.3 (3)	0.5(5)
7.1pF(7R1) 7.2pF(7R2)		0.3(3)	0.5(5)
			0.5(5)
7.3pF(7R3)			0.5(5)
7.4pF(7R4) 7.5pF(7R5)		0.3(3)	* * * * * * * * * * * * * * * * * * * *
7.5pr(/K3)	W, B, C	0.3(3)	0.5(5)

muRata

07.2.6

Continued from the preceding page.

Part Number		GRM03	GRM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	pacitance	Tolerance and T Dimension	
7.6pF(7R6)	W, B, C	0.3(3)	0.5 (5)
7.7pF(7R7)	W, B, C	0.3(3)	0.5 (5)
7.8pF(7R8)	W, B, C	0.3(3)	0.5 (5)
7.9pF(7R9)	W, B, C	0.3(3)	0.5 (5)
8.0pF(8R0)	W, B, C	0.3(3)	0.5(5)
8.1pF(8R1)	W, B, C	0.3(3)	0.5(5)
8.2pF(8R2)	W, B, C	0.3(3)	0.5 (5)
8.3pF(8R3)	W, B, C	0.3(3)	0.5 (5)
8.4pF(8R4)	W, B, C	0.3(3)	0.5 (5)
8.5pF(8R5)	W, B, C	0.3(3)	0.5(5)
8.6pF(8R6)	W, B, C	0.3(3)	0.5(5)
8.7pF(8R7)	W, B, C	0.3(3)	0.5(5)
8.8pF(8R8)	W, B, C	0.3(3)	0.5(5)
8.9pF(8R9)	W, B, C	0.3(3)	0.5(5)
9.0pF(9R0)	W, B, C	0.3(3)	0.5 (5)
9.1pF(9R1)	W, B, C	0.3(3)	0.5 (5)
9.2pF(9R2)	W, B, C	0.3(3)	0.5 (5)
9.3pF(9R3)	W, B, C	0.3(3)	0.5(5)
9.4pF(9R4)	W, B, C	0.3(3)	0.5 (5)
9.5pF(9R5)	W, B, C	0.3(3)	0.5 (5)
9.6pF(9R6)	W, B, C	0.3(3)	0.5 (5)
9.7pF(9R7)	W, B, C	0.3(3)	0.5(5)
	W, B, C	0.3(3)	0.5 (5)
9.9pF(9R9)	W, B, C	0.3(3)	0.5 (5)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Chip Monolithic Ceramic Capacitors



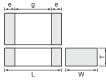
Thin Type

■ Features

- 1. This series is suited to flow and reflow soldering. Capacitor terminations are made of metal highly resistant to migration.
- 2. Large capacitance values enable excellent bypass effects to be realized.
- 3. GRM18, 21 and GRM31 types are suited to flow and reflow soldering. GRM15 and GRM32 types are applied to only reflow soldering.
- 4. Its thin package makes this series ideally suited for the production of small electronic products and for mounting underneath ICs.



Thin equipment such as IC cards



		Dir	mensions (m	nm)	
Part Number	L	W	T	e	g min.
GRM15X	101005	0.5 ±0.05	0.25 ±0.05	0.1 to 0.3	
GRM153	1.0 ±0.05		0.3 ±0.03	0.1 to 0.3	0.4
GRM216			0.6 ±0.1		
GRM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7
GRM21A			1.0 +0/-0.2		
GRM316	3.2 +0.15	1.6 +0.15	0.6 ±0.1	0.3 to 0.8	1.5
GRM319	3.2 ±0.13	1.0 ±0.15	0.85 ±0.1	0.3 10 0.8	1.5
GRM329	3.2 +0.3	2.5 ±0.2	0.85 ±0.1	0.3 min.	1.0
GRM32A	3.2 ±0.3	2.5 ±0.2	1.0 +0/-0.2	0.3 111111.	1.0

Temperature Compensating Type

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	EIA
GRM1535C1H1R0CDD5	C0G (EIA)	50	1.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H2R0CDD5	C0G (EIA)	50	2.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H3R0CDD5	C0G (EIA)	50	3.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H4R0CDD5	C0G (EIA)	50	4.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H5R0CDD5	C0G (EIA)	50	5.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H6R0DDD5	C0G (EIA)	50	6.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H7R0DDD5	C0G (EIA)	50	7.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H8R0DDD5	C0G (EIA)	50	8.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H9R0DDD5	C0G (EIA)	50	9.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H100JDD5	C0G (EIA)	50	10 ±5%	1.0	0.5	0.3	0402
GRM1535C1H120JDD5	C0G (EIA)	50	12 ±5%	1.0	0.5	0.3	0402
GRM1535C1H150JDD5	C0G (EIA)	50	15 ±5%	1.0	0.5	0.3	0402
GRM1535C1H180JDD5	C0G (EIA)	50	18 ±5%	1.0	0.5	0.3	0402
GRM1535C1H220JDD5	COG (EIA)	50	22 ±5%	1.0	0.5	0.3	0402
GRM1535C1H270JDD5	C0G (EIA)	50	27 ±5%	1.0	0.5	0.3	0402
GRM1535C1H330JDD5	C0G (EIA)	50	33 ±5%	1.0	0.5	0.3	0402
GRM1535C1H390JDD5	C0G (EIA)	50	39 ±5%	1.0	0.5	0.3	0402
GRM1535C1H470JDD5	C0G (EIA)	50	47 ±5%	1.0	0.5	0.3	0402
GRM1535C1H560JDD5	C0G (EIA)	50	56 ±5%	1.0	0.5	0.3	0402
GRM1535C1H680JDD5	C0G (EIA)	50	68 ±5%	1.0	0.5	0.3	0402
GRM1535C1H820JDD5	C0G (EIA)	50	82 ±5%	1.0	0.5	0.3	0402
GRM1535C1H101JDD5	COG (EIA)	50	100 ±5%	1.0	0.5	0.3	0402

High Dielectric Constant Type

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	EIA
GRM15XR71H221KA86	X7R (EIA)	50	220pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H331KA86	X7R (EIA)	50	330pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H471KA86	X7R (EIA)	50	470pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H681KA86	X7R (EIA)	50	680pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H102KA86	X7R (EIA)	50	1000pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H152KA86	X7R (EIA)	50	1500pF ±10%	1.0	0.5	0.25	0402
GRM15XR71E222KA86	X7R (EIA)	25	2200pF ±10%	1.0	0.5	0.25	0402
GRM219R71E105KA88	X7R (EIA)	25	1.0μF ±10%	2.0	1.25	0.85	0805
GRM15XR71C332KA86	X7R (EIA)	16	3300pF ±10%	1.0	0.5	0.25	0402
GRM15XR71C472KA86	X7R (EIA)	16	4700pF ±10%	1.0	0.5	0.25	0402
GRM15XR71C682KA86	X7R (EIA)	16	6800pF ±10%	1.0	0.5	0.25	0402
GRM15XR71C103KA86	X7R (EIA)	16	10000pF ±10%	1.0	0.5	0.25	0402
GRM216C81C105KA12	X6S(EIA)	16	1.0μF ±10%	2.0	1.25	0.6*	0805
GRM316C81C225KA12	X6S(EIA)	16	2.2μF ±10%	3.2	1.6	0.6*	1206
GRM219C81C225KA12	X6S(EIA)	16	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM319C81C475KA12	X6S(EIA)	16	4.7μF ±10%	3.2	1.6	0.85*	1206
GRM219C81A475KE34	X6S(EIA)	10	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM219C80J475KE19	X6S(EIA)	6.3	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319C80J106KE19	X6S(EIA)	6.3	10μF ±10%	3.2	1.6	0.85*	1206
GRM219C80G106KE19	X6S(EIA)	4	10μF ±10%	2.0	1.25	0.85*	0805
GRM216R61E105KA12	X5R (EIA)	25	1.0μF ±10%	2.0	1.25	0.6*	0805
GRM316R61E225KA12	X5R (EIA)	25	2.2μF ±10%	3.2	1.6	0.6*	1206
GRM219R61E225KA12	X5R (EIA)	25	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM319R61E475KA12	X5R (EIA)	25	4.7μF ±10%	3.2	1.6	0.85*	1206
GRM216R61C105KA88	X5R (EIA)	16	1.0μF ±10%	2.0	1.25	0.6*	0805
GRM316R61C225KA88	X5R (EIA)	16	2.2μF ±10%	3.2	1.6	0.6*	1206
GRM219R61C225KA88	X5R (EIA)	16	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM219R61C475KE15	X5R (EIA)	16	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319R61C475KA88	X5R (EIA)	16	4.7μF ±10%	3.2	1.6	0.85*	1206
GRM319R61C106KE15	X5R (EIA)	16	10μF ±10%	3.2	1.6	0.85*	1206
GRM216R61A225KE24	X5R (EIA)	10	2.2μF ±10%	2.0	1.25	0.6*	0805
GRM219R61A225KA01	X5R (EIA)	10	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM316R61A335KE19	X5R (EIA)	10	3.3μF ±10%	3.2	1.6	0.6*	1206
GRM219R61A335KE19	X5R (EIA)	10	3.3μF ±10%	2.0	1.25	0.85*	0805
GRM316R61A475KE19	X5R (EIA)	10	4.7μF ±10%	3.2	1.6	0.6*	1206
GRM219R61A475KE34	X5R (EIA)	10	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319R61A106KE19	X5R (EIA)	10	10μF ±10%	3.2	1.6	0.85*	1206
GRM219R60J475KE19	X5R (EIA)	6.3	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319R60J106KE19	X5R (EIA)	6.3	10μF ±10%	3.2	1.6	0.85*	1206

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30).

			cations	fer to GRM Series Specifications and Test Methods (2) (P.30).
No.	Item	Temperature Compensating Type	High Dielectric Type	Test Method
1	Operating Temperature Range	-55 to +125°C	B1, B3, F1, R6: −25 to +85°C R1, R7: −55 to +125°C C8: −55 to +105°C E4: +10 to +85°C F5: −30 to +85°C	Reference temperature: 25°C (2Δ, 3Δ, 4Δ, B1, B3, F1, R1: 20°C)
2	Rated Voltage	See the previous pages.		The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{O-P} , whichever is larger, should be maintained within the rated voltage range.
3	Appearance	No defects or abnormalities		Visual inspection
4	Dimensions	Within the specified dimensions		Using calipers (GRM02 size is based on Microscope)
5	Dielectric Strength	No defects or abnormalities		No failure should be observed when 300%* of the rated voltage (temperature compensating type) or 250% of the rated voltage (high dielectric constant type) is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA. *200% for 500V
6	Insulation Resistance	C≦0.047μF: More than 10,000M C>0.047μF: 500Ω · F	MΩ C: Nominal Capacitance	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 20/25℃ and 75%RH max. and within 2 minutes of charging, provided the charge/ discharge current is less than 50mA.
7	Capacitance	Within the specified tolerance		
8	Q/ Dissipation Factor (D.F.)	30pF and over: Q≥1000 30pF and below: Q≥400+20C C: Nominal Capacitance (pF)	[R6, R7, C8] W.V.: 100V : 0.025 max. (C<0.068μF) : 0.05 max. (C≥0.068μF) W.V.: 50/25V : 0.025 max. (C<10μF) : 0.035 max. (C≥10μF) W.V.: 16/10V: 0.035 max. W.V.: 6.3/4V : 0.05 max. (C≥3.3μF) : 0.1 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.025 max. [F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF) : 0.09 max. (C≥0.1μF) W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.	The capacitance/Q/D.F. should be measured at 20/25°C at the frequency and voltage shown in the table. Char. ΔC to 7U, 1X (more than 1000pF) R6, R7, C8, F5, B1, B3, F1 Frequency 1±0.1MHz 1±0.1kHz 120±24kHz 1±0.1kHz Voltage 0.5 to 5Vrms 1±0.2Vrms 0.5± 0.05Vrms





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30). Continued from the preceding page.

	Continued fr	om the prece		d in capacitance table, please re ications	erer to GRIM Se	ries Specifications and 16	est Methods (2) (P.30).
No.	lt∈	em	Temperature Compensating Type	High Dielectric Type	-	Test Method	
		No bias	Within the specified tolerance (Table A-1)	B1, B3: Within $\pm 10\%$ (-25 to $+85\%$) R1, R7: Within $\pm 15\%$ (-55 to $+125\%$) R6: Within $\pm 15\%$ (-55 to $+85\%$) E4: Within $\pm 22/-56\%$ (± 10 to $\pm 85\%$) F1: Within $\pm 30/-80\%$ ($\pm 22/-82\%$ (± 30 to $\pm 85\%$) F5: Within $\pm 22/-82\%$ (± 30 to $\pm 85\%$) C8: Within $\pm 22\%$ (± 55 to $\pm 105\%$)	each specified (1)Temperature The temperature capacitance in When cycling 5 (5C: +25 to +25 to +85°C the specified in capacitance of the capacitan	nce change should be mean the temp. stage. The Compensating Type ure coefficient is determine neasured in step 3 as a refute temperature sequentia +125°C/ΔC: +20 to +125°C/+20 to +85°C) the capacitate tolerance for the temperature shange as Table A-1. The ced drift is calculated by diversity maximum and minimum means to the cap. Value in step	d using the erence. Illy from step 1 through c: other temp. coeffs.: ance should be within re coefficient and iding the differences asured values in the 3.
		50% of the Rated Voltage		B1: Within +10/–30% R1: Within +15/–40% F1: Within +30/–95%	1 2 3 4	Reference Te -55±3 (for ΔC to -30±3 (for F5) -25±3 (fo Reference Te 125±3 (for ΔC/R7 85±3 (for	mperature ±2 7U/1X/R6/R7/C8) , 10±3 (for E4) r other TC) mperature ±2 '), 105±3 (for C8) other TC)
9	Capacitance Temperature Characteristics	Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger.) *Do not apply to 1X/25V	*Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and then set for 24±2 hours at room temperature. Perform the initial measurement.	The ranges of value over the be within the In case of approximation of the state of	Reference Telectric Constant Type f capacitance change completemperature ranges show specified ranges.* Solying voltage, the capacitater 1 more min. with applying feach temp. stage. Temperature (°C) Reference Temperature ±2 -55±3 (for R1, R7, R6) -25±3 (for B1, B3, F1) 30±3 (for F5)/10±3 (for E4) Reference Temperature ±2 125±3 (for R1, R7)/ 85±3 (for R1, R7)/ Reference Temperature ±2 -55±3 (for R1, R7)/ Reference Temperature ±2 -25±3 (for R1)/ -25±3 (for R1)/ Reference Temperature ±2 125±3 (for R1)/ Reference Temperature ±2 125±3 (for R1)/ Reference Temperature ±2 125±3 (for R1)/ Reference Temperature ±2	n in the table should nce change should be g voltage in Applying Voltage (V)
10	Adhesive of Termin	Strength ation	No removal of the terminations	or other defect should occur. C Solder resist Baked electrode or copper foil	Fig. 1a using parallel with the soldering reflow method soldering is un	pacitor to the test jig (glass an eutectic solder. Then ap the test jig for 10±1 sec. should be done either with diand should be conducted niform and free of defects solder. Note that the diand should be conducted niform and free of defects solder. Note that the diangle of th	(in mm) (in





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30). $\begin{tabular}{|c|c|c|c|c|c|c|}\hline \end{tabular}$ Continued from the preceding page.

		<u> </u>		ications			(=) (- 100)
No.	Ite	·m	Temperature Compensating Type	High Dielectric Type	Tes	t Method	
		Appearance	No defects or abnormalities				
		Capacitance	Within the specified tolerance				
11	Vibration Resistance	Q/D.F.	30pF and over: Q≥1000 30pF and below: Q≥400+20C C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.025 max. (C<0.068μF) : 0.05 max. (C≥0.068μF) W.V.: 50/25V : 0.025 max. (C≥10μF) : 0.035 max. (C≥10μF) W.V.: 16/10V: 0.035 max. W.V.: 6.3/4V : 0.05 max. (C≥3.3μF) : 0.1 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.025 max. [F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF) : 0.09 max. (C≥0.1μF) W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.	Solder the capacitor on the t same manner and under the The capacitor should be sub having a total amplitude of 1 uniformly between the appro- frequency range, from 10 to be traversed in approximatel applied for a period of 2 hou perpendicular directions (total	same conditions a sected to a simple had been same, the frequency simate limits of 10 pdf. and return to y 1 minute. This makes in each of 3 mutters and sections are sections.	s (10). narmonic motion by being varied and 55Hz. The 10Hz, should otion should be
12	Deflection	٦	No crack or marked defect sho	0 Pressurizing speed: 1.0mm/sec. Pressurize Flexure: ≤1	Type a GRM02 0.2 GRM03 0.3 GRM15 0.4 GRM18 1.0 GRM21 1.2 GRM31 2.2 GRM32 2.2 GRM32 2.2 GRM43 3.5 GRM55 4.5	older. Then apply a 5±1 sec. The solo nd should be cond	a force in the dering should be ucted with care cts such as heat
13	Solderabi Terminatio		75% of the terminations are to continuously.	be soldered evenly and	Immerse the capacitor in a s rosin (JIS-K-5902) (25% rosin Preheat at 80 to 120°C for 10 After preheating, immerse in 2±0.5 seconds at 230±5°C of c 2±0.5 seconds at 245±5	n in weight proport to 30 seconds. an eutectic solder r Sn-3.0Ag-0.5Cu	solution for





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30). Continued from the preceding page.

	Continued ii	om the pres-		cations	erer to GRM Series Specifications and Test Methods (2) (P.30).
No.	Ite	em	Temperature	dutoris	Test Method
			Compensating Type	High Dielectric Type	
			The measured and observed ch specifications in the following ta	-	
		Appearance	No defects or abnormalities		
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±7.5% F1, F5, E4: Within ±20%	
14	Resistance to Soldering Heat	Q/D.F.	30pF and over: Q≧1000 30pF and below: Q≥400+20C C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.025 max. (C<0.068μF) : 0.05 max. (C≥0.068μF) W.V.: 50/25V : 0.025 max. (C<10μF) : 0.035 max. (C≥10μF) W.V.: 16/10V: 0.035 max. W.V.: 6.3/4V : 0.05 max. (C<3.3μF) : 0.1 max. (C≥3.3μF)	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in an eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds. Set at room temperature for 24±2 hours, then measure. •Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. •Preheating for GRM32/43/55 Step Temperature Time
				W.V.: 25Vmin: 0.025 max.	1 100 to 120°C 1 min.
				[F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF)	2 170 to 200°C 1 min.
				: 0.09 max. (C≥0.1µF) : 0.09 max. (C≥0.1µF) W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.	
		I.R.	More than 10,000M Ω or 500 Ω	F (Whichever is smaller)	
		Dielectric Strength	No defects		
			The measured and observed chapecifications in the following ta	-	
		Appearance	No defects or abnormalities		
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±7.5% F1, F5, E4: Within ±20%	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles according to the four heat treatments
				[R6, R7, C8]	shown in the following table.
				W.V.: 100V : 0.05 max. (C<0.068µF)	Set for 24±2 hours at room temperature, then measure. Step 1 2 3 4
				: 0.075 max. (C≧0.068µF) W.V.: 50/25/16/10V	Min. Room Max. Room
				: 0.05 max.	Temp. (°C) Operating Temp. Operating Temp. T
15	Temperature Cycle		30pF and over: Q≧1000	W.V.: 6.3/4V	Time (min.) 30±3 2 to 3 30±3 2 to 3
	Cycle	Q/D.F.	30pF and below: Q≧400+20C	: 0.075 max. (C<3.3μF) : 0.125 max. (C≧3.3μF)	Initial measurement for high dielectric constant type
				[E4]	Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours.
			C: Nominal Capacitance (pF)	W.V.: 25Vmin: 0.05 max. [F1, F5]	Perform the initial measurement.
				W.V.: 25V min.	
				: 0.05 max. (C<0.1µF) : 0.09 max. (C≧0.1µF)	
				W.V.: 16/10V: 0.125 max.	
		1.0	M th 40 000M0 5000	W.V.: 6.3V: 0.15 max.	
		I.R.	More than $10,000M\Omega$ or 500Ω	r (vvnicnever is smaller)	-
		Dielectric Strength	No defects		





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30). Continued from the preceding page.

		Specif	cations	
O. I	em	Temperature Compensating Type	High Dielectric Type	Test Method
		The measured and observed chapecifications in the following ta	•	
	Appearance	No defects or abnormalities		
	Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±12.5% F1, F5, E4: Within ±30%	
Humidity 6 (Steady State)	Q/D.F.	30pF and over: Q≥350 10pF and over 30pF and below: Q≥275+2.5C 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	[R6, R7, C8] W.V.: 100V : 0.05 max. (C<0.068μF) : 0.075 max. (C≥0.068μF) W.V.: 50/25/16/10V : 0.05 max. W.V.: 6.3/4V : 0.075 max. (C≥3.3μF) : 0.125 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.05 max. [F1, F5] W.V.: 25V min. : 0.075 max. (C<0.1μF) : 0.125 max. (C≥0.1μF) W.V.: 16/10V: 0.15 max. W.V.: 6.3V: 0.2 max.	Set the capacitor at 40±2°C and in 90 to 95% humidity for 500±12 hours. Remove and set for 24±2 hours at room temperature, then measure.
	I.R.	More than 1,000M Ω or 50 Ω · F	(Whichever is smaller)	
		The measured and observed chapecifications in the following ta	-	
	Appearance	No defects or abnormalities		
		THE GOLOGIC OF GENERALISE		
	Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±12.5% F1, F5, E4: Within ±30% [W.V.: 10V max.] F1, F5: Within +30/-40%	
7 Humidity Load		Within ±7.5% or ±0.75pF	: Within ±12.5% F1, F5, E4: Within ±30% [W.V.: 10V max.]	Apply the rated voltage at 40±2°C and 90 to 95% humidity fo 500±12 hours. Remove and set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement for F1, F5/10V max. Apply the rated DC voltage for 1 hour at 40±2°C. Remove and set for 24±2 hours at room temperature. Perform initial measurement.





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table.

Continued from the preceding page. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30).

			Specifi	ications					
No.	It∈	em	Temperature Compensating Type	High Dielectric Type	Test Method				
			The measured and observed characteristics should satisfy the specifications in the following table.						
		Appearance	No defects or abnormalities						
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±12.5% F1, F5, E4: Within ±30% [Except 10V max. and. C≥1.0µF] F1, F5: Within +30/−40% [10V max. and C≥1.0µF]	Apply 200%* of the rated voltage at the maximum operating temperature ±3℃ for 1000±12 hours.				
18	High Temperature Load	Q/D.F.	30pF and over: Q≥350 10pF and over 30pF and below: Q≥275+2.5C 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.05 max. (C<0.068μF) : 0.075 max. (C≥0.068μF) W.V.: 50/25/16/10V : 0.05 max. W.V.: 6.3/4V : 0.075 max. (C≤3.3μF) : 0.125 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.05 max. [F1, F5] W.V:: 25V min. : 0.075 max.(C<0.1μF) : 0.125 max.(C≥0.1μF) W.V.: 16/10V: 0.15 max. W.V.: 16/10V: 0.15 max. W.V.: 6.3V: 0.2 max.	Set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage at the maximum operating temperature ±3°C for one hour. Remove and set for 24±2 hours at room temperature. Perform initial measurement. *150% for 500V				
		I.R.	More than 1,000M Ω or 50 Ω · F	(Whichever is smaller)					

Table A-1

		Capacitance Change from 25℃ (%)						
Char.	Nominal Values (ppm/℃)*1	- 55		-30		-10		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0± 30	0.58	-0.24	0.40	-0.17	0.25	-0.11	
6C	0± 60	0.87	-0.48	0.59	-0.33	0.38	-0.21	
6P	-150± 60	2.33	0.72	1.61	0.50	1.02	0.32	
6R	-220± 60	3.02	1.28	2.08	0.88	1.32	0.56	
6S	-330± 60	4.09	2.16	2.81	1.49	1.79	0.95	
6T	-470± 60	5.46	3.28	3.75	2.26	2.39	1.44	
7U	-750±120	8.78	5.04	6.04	3.47	3.84	2.21	
1X	+350 to -1000	_	_	_	_	_	_	

^{*1:} Nominal values denote the temperature coefficient within a range of 25°C to 125°C (for △C)/85°C (for other TC).

1	1	,
(2	
,		

		Capacitance Change from 20℃ (%)						
Char.	Nominal Values (ppm/°C)*2	- 55		— 25		-10		
		Max.	Min.	Max.	Min.	Max.	Min.	
2C	0± 60	0.82	-0.45	0.49	-0.27	0.33	-0.18	
3C	0±120	1.37	-0.90	0.82	-0.54	0.55	-0.36	
4C	0±250	2.56	-1.88	1.54	-1.13	1.02	-0.75	
2P	-150± 60	_	_	1.32	0.41	0.88	0.27	
3P	-150±120	_	_	1.65	0.14	1.10	0.09	
4P	-150±250	_	_	2.36	-0.45	1.57	-0.30	
2R	-220± 60	_	_	1.70	0.72	1.13	0.48	
3R	-220±120	_	_	2.03	0.45	1.35	0.30	
4R	-220±250	_	_	2.74	-0.14	1.83	-0.09	
2S	-330± 60	_	_	2.30	1.22	1.54	0.81	
3S	-330±120	_	_	2.63	0.95	1.76	0.63	
4S	-330±250	_	_	3.35	0.36	2.23	0.24	
2T	-470± 60	_	_	3.07	1.85	2.05	1.23	
3T	-470±120	_	_	3.40	1.58	2.27	1.05	
4T	-470±250	_	_	4.12	0.99	2.74	0.66	
3U	-750±120	_	_	4.94	2.84	3.29	1.89	
4U	-750±250	_	_	5.65	2.25	3.77	1.50	

^{*2:} Nominal values denote the temperature coefficient within a range of 20°C to 125°C (for △C)/85°C (for other TC).

Below GRM Series Specifications and Test Methods (2) are applied to "*" PNs in capacitance table. In case "*" is not added in capacitance table, please refer to GRM Series Specifications and Test Methods (1) (P.24).

No.	Ite	em	Specifications		Test Method		
1	Operating Temperat Range	•	B1, B3, F1: -25 to +85°C R6: -55 to +85°C R7, C7: -55 to +125°C F5: -30 to +85°C C8: -55 to +105°C,	Reference (B1, B3, F1	temperature: 25℃ l: 20℃)		
2	Rated Vo	ltage	See the previous pages.	The rated voltage is defined as the maximum voltage will may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} of whichever is larger, should be maintained within the rate voltage range.			
3	Appearan	nce	No defects or abnormalities	Visual insp	ection		
4	Dimensio	ns	Within the specified dimensions	Using calip	ers		
5	Dielectric	Strength	No defects or abnormalities	is applied b	should be observed when 250% between the terminations for 1 to be charge/discharge current is le	to 5 seconds,	
6	Insulation Resistance		More than $50\Omega \cdot F$	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at reference temperature and 75%RH max. and within 1 minutes of charging, provided the charge/discharge current is less than 50mA.			
7	Capacitar	nce	Within the specified tolerance		itance/D.F. should be measured		
8	Dissipatio (D.F.)	on Factor	B1, B3, R6* ² , R7, C7, C8: 0.1 max. F1, F5: 0.2 max.	temperature at the frequency and voltage shown in the to Capacitance Frequency Voltage C≤10µF (10V min.)*1 1±0.1kHz 1.0±0.2V C≤10µF (6.3V max.) 1±0.1kHz 0.5±0.1V C>10µF 120±24Hz 0.5±0.1V 120±24Hz 1.0±0.1V 120±0.1V 120±			
		No bias	B1, B3: Within ±10% (-25 to +85°C) F1 : Within +30/-80% (-25 to +85°C) R6 : Within ±15% (-55 to +85°C) R7 : Within ±15% (-55 to +125°C) F5 : Within +22/-82% (-30 to +85°C) C7 : Within ±22% (-55 to +125°C) C8 : Within ±22% (-55 to +105°C)	The capacitance change should be me each specified temp. stage. The ranges of capacitance change cor reference temperature value over the t shown in the table should be within the In case of applying voltage, the capaci measured after 1 more min. with apply equilibration of each temp. stage.		pared with the mperature ranges specified ranges.* ance change should be	
				**CDM42.F	GRM43 B1/R6 0J/1A 336/476 only: 1.0±0.2Vrms		
				Step	Temperature (°C)	Applying Voltage (V)	
				1	Reference temperature ±2	rippiying voltage (v)	
9	Capacitance Temperature			2	-55±3 (for R6, C7, C8)/ -25±3 (for B1, B3, F1) -30±3 (for F5)		
	Characteristics			3	Reference temperature ±2	No bias	
		50% of the Rated Voltage	B1: Within +10/-30% F1: Within +30/-95%	4	85±3 (for B1, B3, F1, R6, F5) 125±3 (for C7)/ 105±3 (for C8)		
				5	20±2		
				6	–25±3 (for B1, F1)	50% of the rated	
				7	20±2	voltage	
				8	85±3 (for B1, F1)		
				Perform a then set for	isurement for high dielectric co heat treatment at 150 +0/–10° r 24±2 hours at room temperat e initial measurement.	C for one hour and	

*2: GRM31CR60J107: 0.15 max.





Below GRM Series Specifications and Test Methods (2) are applied to "*" PNs in capacitance table. Continued from the preceding page. In case "*" is not added in capacitance table, please refer to GRM Series Specifications and Test Methods (1) (P.24). Specifications No. Item Test Method No removal of the terminations or other defects should occur. Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 1a using an eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *5N: GRM15/GRM18, 2N: GRM03 Type b Adhesive Strength GRM02 0.2 0.56 0.23 10 of Termination GRM03 0.3 0.9 0.3 GRM15 0.4 0.5 15 Solder resist GRM18 1.0 3.0 1.2 Baked electrode or GRM21 1.2 1.65 4.0 copper foil GRM31 5.0 2.0 2.2 Fig. 1a GRM32 22 5.0 29 GRM43 3.5 7.0 3.7 GRM55 4.5 8.0 No defects or abnormalities Appearance Solder the capacitor on the test jig (glass epoxy board) in the same manner and under the same conditions as (10). Capacitance Within the specified tolerance The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied Vibration uniformly between the approximate limits of 10 and 55Hz. The B1, B3, R6*2, R7, C7, C8: 0.1 max. frequency range, from 10 to 55Hz and return to 10Hz, should D.F. F1, F5: 0.2 max. be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours). No cracking or marking defects should occur. Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 2a using an eutectic solder. Then apply a force in the direction shown in Fig. 3a for 5±1 sec. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed : 1.0mm/sec Pressurize R230 Flexure : ≤1 t: 1.6mm Deflection Fig. 2a 45 45 (GRM03/15: t: 0.8mm)

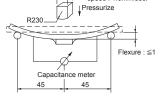


Fig.3a

Type	а	b	С
GRM02	0.2	0.56	0.23
GRM03	0.3	0.9	0.3
GRM15	0.4	1.5	0.5
GRM18	1.0	3.0	1.2
GRM21	1.2	4.0	1.65
GRM31	2.2	5.0	2.0
GRM32	2.2	5.0	2.9
GRM43	3.5	7.0	3.7
GRM55	4.5	8.0	5.6

Solderability of 75% of the terminations is to be soldered evenly and 13 Termination continuously

Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion) Preheat at 80 to 120°C for 10 to 30 seconds.

After preheating, immerse in an eutectic solder solution for 2±0.5 seconds at 230±5℃ or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.





^{*2:} GRM31CR60J107: 0.15 max.

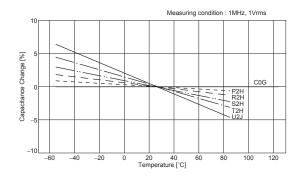
Below GRM Series Specifications and Test Methods (2) are applied to "*" PNs in capacitance table. Continued from the preceding page. In case "*" is not added in capacitance table, please refer to GRM Series Specifications and Test Methods (1) (P.24).

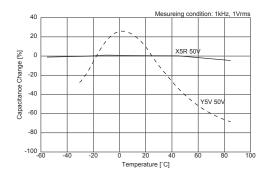
No. Ite	em	Specifications		Tes	st Metho	d		
	Appearance Capacitance Change	No defects or abnormalities B1, B3, R6, R7, C7, C8: Within ±7.5% F1, F5: Within ±20%	Immerse the o	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in an eutectic solder or Sn-3.0Ag-0.5 solder solution at 270±5°C for 10±0.5 seconds. Set at room				
	D.F.	B1, B3, R6*2, R7, C7, C8: 0.1 max. F1, F5: 0.2 max.		temperature for 24±2 hours, then measure. *Do not apply to GRM02.				
Resistance	I.R.	More than $50\Omega \cdot F$				c constant type		
Soldering Heat	Dielectric		then set at roo Perform the in	Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement.				
	Strength	No defects		*Preheating for GRM32/43/55 Step Temperature Time				
			1		o 120°C		min.	
			2		0 200℃		min.	
	Appearance	No defects or abnormalities	Fix the capac	itor to the supp	orting jig	in the same m	anner an	
	Capacitance Change	B1, B3, R6, R7, C7, C8: Within ±7.5% F1, F5: Within ±20%	Perform the fi	under the same conditions as (10). Perform the five cycles according to the four heat treatments shown in the following table.				
	D.F.	B1, B3, R6*2, R7, C7, C8: 0.1 max. F1, F5: 0.2 max.	Set for 24±2	hours at room	temperat	ure, then meas		
Temperature	I.R.	More than $50\Omega \cdot F$	Step	1 Min.	2	3 Max.	4	
5 Sudden Change			Temp. (℃)	Operating Temp. +0/-3	Room Temp.	Operating Temp. +3/-0	Room Temp.	
	Dielectric Strength	No defects	•Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/−10℃ for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement.					
	Appearance	No defects or abnormalities		Apply the rated voltage at 40±2℃ and 90 to 95% humidity for				
High	Capacitance Change	B1, B3, R6, R7, C7, C8: Within ±12.5% F1, F5: Within ±30%		■ Initial measurement Perform a heat treatment at 150+0/−10°c for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement.			than 50m	
Temperature High Humidity	D.F.	B1, B3, R6, R7, C7, C8: 0.2 max. F1, F5: 0.4 max.	Perform a hea					
(Steady)	I.R.	More than 12.5 $\Omega \cdot F$	Measurement after test Perform a heat treatment at 15			50+0/—10°C for one hour and oom temperature, then measure.		
	Appearance	No defects or abnormalities			-	000±12 hours		
	Capacitance Change	B1, B3, R6, R7, C7, C8: Within ±12.5% F1, F5: Within ±30%	room tempera	maximum operating temperature ±3°C. Let sit for 24 room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement		±2 hours		
	D.F.	B1, B3, R6, R7, C7, C8: 0.2 max. F1, F5: 0.4 max.	•Initial measu					
17 Durability	I.R.	More than $25\Omega \cdot F$	then let sit for initial measure •Measuremer Perform a hea	24±2 hours at ement. at after test at treatment at	room ter 150+0/-	10℃ for one homperature. Performed for one homperature, ther	orm the	

^{*2:} GRM31CR60J107: 0.15 max.

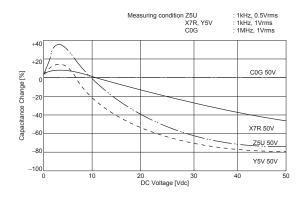
GRM Series Data

■ Capacitance - Temperature Characteristics

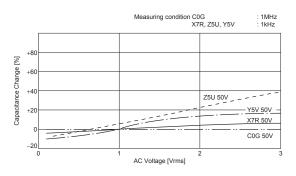




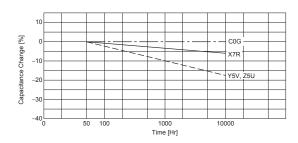
■ Capacitance - DC Voltage Characteristics



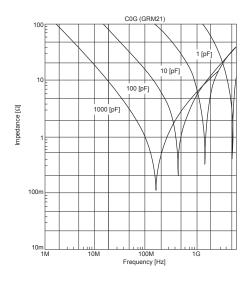
■ Capacitance - AC Voltage Characteristics



■ Capacitance Change - Aging



■ Impedance - Frequency Characteristics



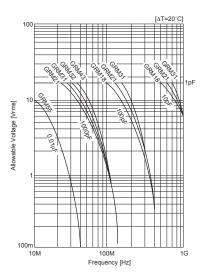




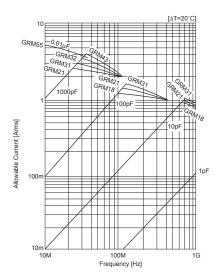
GRM Series Data

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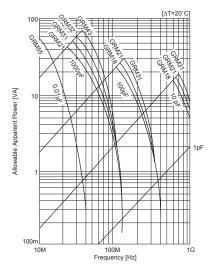
■ Allowable Voltage - Frequency



■ Allowable Current - Frequency



■ Allowable Apparent Power - Frequency



Chip Monolithic Ceramic Capacitors



Microchips GMA Series

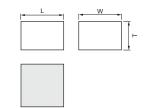
■ Features

- 1. Better microwave characteristics
- 2. Suitable for by-passing
- 3. High density mounting

Applications

- 1. Optical device for telecommunication
- 2. IC, IC packaging built-in
- 3. Measuring equipment





Part Number		Dimensions (mm)	
Part Number	L	W	T
GMA05X	0.5 ±0.05	0.5 ±0.05	0.35 ±0.05
GMA085	0.8 ±0.05	0.8 ±0.05	0.5 ±0.1

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)
GMA05XR72A101MD01	X7R (EIA)	100	100pF ±20%	0.5	0.5	0.35
GMA05XR72A151MD01	X7R (EIA)	100	150pF ±20%	0.5	0.5	0.35
GMA05XR72A221MD01	X7R (EIA)	100	220pF ±20%	0.5	0.5	0.35
GMA05XR72A331MD01	X7R (EIA)	100	330pF ±20%	0.5	0.5	0.35
GMA085R72A331MD01	X7R (EIA)	100	330pF ±20%	0.8	0.8	0.5
GMA085R72A471MD01	X7R (EIA)	100	470pF ±20%	0.8	0.8	0.5
GMA085R72A681MD01	X7R (EIA)	100	680pF ±20%	0.8	0.8	0.5
GMA085R72A102MD01	X7R (EIA)	100	1000pF ±20%	0.8	0.8	0.5
GMA05XR71H161MD01	X7R (EIA)	50	160pF ±20%	0.5	0.5	0.35
GMA05XR71H331MD01	X7R (EIA)	50	330pF ±20%	0.5	0.5	0.35
GMA05XR71H471MD01	X7R (EIA)	50	470pF ±20%	0.5	0.5	0.35
GMA05XR71C431MD01	X7R (EIA)	16	430pF ±20%	0.5	0.5	0.35
GMA05XR71C471MD01	X7R (EIA)	16	470pF ±20%	0.5	0.5	0.35
GMA05XR71C681MD01	X7R (EIA)	16	680pF ±20%	0.5	0.5	0.35
GMA05XR71C102MD01	X7R (EIA)	16	1000pF ±20%	0.5	0.5	0.35
GMA085R71C102MD01	X7R (EIA)	16	1000pF ±20%	0.8	0.8	0.5
GMA05XR71C152MD01	X7R (EIA)	16	1500pF ±20%	0.5	0.5	0.35
GMA085R71C152MD01	X7R (EIA)	16	1500pF ±20%	0.8	0.8	0.5
GMA05XR71C222MD01	X7R (EIA)	16	2200pF ±20%	0.5	0.5	0.35
GMA085R71C222MD01	X7R (EIA)	16	2200pF ±20%	0.8	0.8	0.5
GMA085R71C332MD01	X7R (EIA)	16	3300pF ±20%	0.8	0.8	0.5
GMA085R71C472MD01	X7R (EIA)	16	4700pF ±20%	0.8	0.8	0.5
GMA085R71C682MD01	X7R (EIA)	16	6800pF ±20%	0.8	0.8	0.5
GMA085R71C103MD01	X7R (EIA)	16	10000pF ±20%	0.8	0.8	0.5

No.	Ite	em	Specifications Test Method										
1	Operating Temperating Range	,	R7: −55 to +125°C	Reference Temperature: 25°C									
2	Rated Vo	ltage	See the previous pages.	The rated voltage is defined as the maximum voltage whimay be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or whichever is larger, should be maintained within the rated vi									
3	Appearar	nce	No defects or abnormalities	Using calip	pers								
4	Dimensio	ns	Within the specified dimersions	Visual insp	pection								
5	Dielectric	Strength	No defects or abnormalities	rated volta	should be observed when a voge is applied between the both provided the charge/discharge	h terminations for 1 to 5							
6	Insulation	Resistance	10,000MΩ min.	voltage no	tion resistance should be mea t exceeding the rated voltage ity and within 2 minutes of cha	at normal temperature							
7	Capacita	nce	Within the specified tolerance		itance/D.F. should be measur								
8	Dissipatio (D.F.)	n Factor	R7: 0.035 max.	Freque		kHz							
		mperature No bias R7: Within +/-15% (-55 to +125°C)		each speci •The range Reference shown in the shown ind	itance change should be mea ified temp. stage. es of capacitance change con Temperature value over the the table should be within the sapplying voltage, the capacite after 1 more min. with applying on of each temp. stage.	npared with the temperature ranges specified ranges.* unce change should be							
	Capacitance		No bias	No bias	No bias		Step 1	Temperature (°C) Reference Temperature±2	Applying Voltage (V)				
9	Temperature Characteristics					No bias	No bias	R7: Within +/–15% (–55 to +125°C)	2	-55±3 (for R7) -30±3 (for F5)	No bias		
									3	Reference Temperature±2	⊢		
									4	125±3 (for R7) 85±3 (for F5)			
10	Mechanical	Bond Strength	Pull force: 0.03N min.	MIL-STD-883 Method 2011 Condition D Mount the capacitor on a gold metallized alumina substrate with Au-Sn (80/20) and bond a 25µm (0.0008 inch) gold wire to the capacitor terminal using an ultrasonic ball bond. Then, pull wire. MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina substrate with Au-Sn (80/20). Apply the force parallel to the substrate.									
	Strength	Die Shear Strength	Die Shear force: 2N min.										
		Appearance	No defects or abnormalities		uency from 10 to 55Hz then r								
11	1 Vibration Resistance Capacitance D.F. Capacitance D.F. R7: 0.035 max.		Within the specified tolerance		Amplitude: 1.5 mm (0.06 inch) motion for a period of 2 hours								
			 Apply this motion for a period of 2 hours in each of 3 mutually perpendicular directions (total 6 hours). 										
		Appearance	No defects or abnormalities		itor should be set for 24±2 ho								
		Capacitance Change	R7: Within ±7.5%	then meas the suppor	re after one hour heat of treati ure for the initial measuremer ting jig in the same manner a	nt. Fix the capacitor to nd under the same							
	Temperature	D.F.	R7: 0.035 max.	_	as (11) and conduct the five o								
12	Temperature Cycle	I.R.	10,000M Ω min.		res and time shown in the folk is at room temperature, then r	•							
		Dielectric Strength	No defects	Step Temp. (°	1 2 C) Min. Operating Room Temp. +0/-3 Temp. T	3 4 ax. Operating Room Temp. +3/-0 Temp. 30±3 2 to 3							
			•										

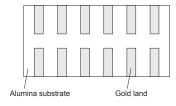


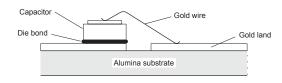


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No.	Ite	<u> </u>	Specifications	Test Method
		Appearance	No defects or abnormalities	
13	Humidity (Standy State)	Capacitance Change	R7: Within ±12.5%	Set the capacitor for 500±12 hours at 40±20°C, in 90 to 95% humidity.
	(Steady State)	D.F.	R7: 0.05 max.	Take it out and set it for 24±2 hours at room temperature, then measure.
		I.R.	1,000M Ω min.	
		Appearance	No defects or abnormalities	
14	Humidity	Capacitance Change	R7: Within ±12.5%	Apply the rated voltage for 500±12 hours at 40±2°C, in 90 to 95% humidity and set it for 24±2 hours at room
	Load	D.F.	R7: 0.05 max.	temperature,then measure. The charge/discharge current is less than 50mA.
		I.R.	500M Ω min.	
		Appearance	No defects or abnormalities	A voltage treatment should be given to the capacitor, in which a
	High	Capacitance Change	R7: Within ±12.5%	DC voltage of 200% the rated voltage is applied for one hour at the maximum operating temperature ±3°C then it should be set for 24±2 hours at room temperature and the initial measurement
15	Temperature	D.F.	R7: 0.05 max.	should be conducted.
	Load	I.R.	1,000MΩ min.	Then apply the above mentioned voltage continuously for 1000±12 hours at the same temperature, remove it from the bath, and set it for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.

Mounting for testing: The capacitors should be mounted on the substrate as shown below using die bonding and wire bonding when tests No.11 to 15 are performed.





Chip Monolithic Ceramic Capacitors



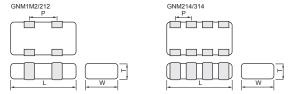
Capacitor Arrays GNM Series

■ Features

- 1. High density mounting due to mounting space saving
- 2. Mounting cost saving

■ Applications

General electronic equipment



Part Number	Dimensions (mm)							
Part Number	L	W	T	Р				
GNM1M2	1.37 +0.15	1.0 ±0.15	0.6 ±0.1	0.64 +0.05				
GINIVITIVIZ	1.37 ±0.13	1.0 ±0.15	0.8 +0/-0.15	0.04 ±0.05				
GNM212	2.0 +0.15	1.25 +0.15	0.85 ±0.1	1.0 ±0.1				
GNM214	2.0 ±0.13	1.25 ±0.15	0.6 ±0.1	0.5 ±0.05				
GNM314	3.2 +0.15	1.6 +0.15	0.8 ±0.1	0.8 +0.1				
GINIVIS 14	3.2 ±0.13	1.0 ±0.15	1.0 ±0.1	0.6 ±0.1				

Temperature Compensating Type

Part Number		GNM1M	GNM21	GN	M31
LxW		1.37x1.0	2.0x1.25	3.2	x1.6
TC		C0G (5C)	C0G (5C)		0G (C)
Rated Volt.		50 (1H)	50 (1H)	100 (2A)	50 (1H)
Capacitance, Ca	pacitano	e Tolerance and T Dimension			
10pF(100)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
15pF(150)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
22pF(220)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
27pF(270)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
33pF(330)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
39pF(390)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
47pF(470)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
68pF(680)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
100pF(101)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
150pF(151)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
220pF(221)	K	0.6(2)	0.6(4)		0.8(4)
270pF(271)	K				0.8(4)
330pF(331)	K				0.8(4)

The part numbering code is shown in each (). The (4) code in T (mm) means number of elements (four). Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type GNM1M Series

Part Number		GNM1M							
LxW					1.37x1.0				
тс	C X5R (R6)								
Rated Volt.		16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	
Capacitance, Ca	pacitanc	e Tolerance and	T Dimension	1	'	1	1		
1000pF(102)	М				0.6(2)				
2200pF(222)	K, M					0.6(2)			
4700pF(472)	K, M					0.6(2)			
10000pF(103)	М					0.6(2)			
22000pF(223)	K, M	0.6(2)	0.6(2)				0.6(2)	0.6(2)	

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Part Number					GNM1M			
LxW					1.37x1.0			
TC	тс		X5R (R6) X7R (R7)					
Rated Volt.	Rated Volt.		10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance, Ca	pacitano	e Tolerance and	T Dimension					
47000pF(473) K , M 0.6(2) 0.6(2)					0.6(2)	0.6(2)		
0.10μF(104) M			0.6(2)					
1.0μF(105)	М	0.8(2)	0.8(2)	0.8(2)				

The part numbering code is shown in each (). The (2) code in T (mm) means number of elements (two).

High Dielectric Constant Type GNM21 Series

Part Number		GNM21					
LxW				2.0x1.25			
тс		X5R (R6) X7R (R7)					
Rated Volt. 16 (1C)		10 (1A)	50 25 (1 H) (1 E)		16 (1C)		
Capacitance, Ca	pacitano	e Tolerance and T Dime	nsion				
1000pF(102)	М			0.6(4)			
2200pF(222)	K, M				0.6(4)		
4700pF(472)	K, M				0.6(4)		
10000pF(103)	М				0.6(4)		
22000pF(223)	K, M					0.85(4)	
47000pF(473)	K, M					0.85(4)	
0.10μF(104)	М					0.85(4)	
0.47μF(474)	М	0.85(2)					
1.0μF(105)	М	0.85(2)	0.85(4)				
2.2μF(225)	K, M		0.85(2)				

The part numbering code is shown in each (). The (2) code in T (mm) means number of elements (two).

High Dielectric Constant Type GNM31 Series

Part Number		GNM31					
LxW		3.2x1.6					
тс			X7R (R7)		X5R (R6)		
Rated Volt.		100 (2A)	50 (1H)	16 (1C)	10 (1A)		
Capacitance, Ca	pacitanc	e Tolerance and T Dimension					
220pF(221)	K, M	0.8(4)					
330pF(331)	K, M	0.8(4)					
470pF(471)	K, M	0.8(4)	0.8(4)				
680pF(681)	K, M	0.8(4)	0.8(4)				
1000pF(102)	K, M	0.8(4)	0.8(4)				
1500pF(152)	K, M	0.8(4)	0.8(4)				
2200pF(222)	K, M	0.8(4)	0.8(4)				
3300pF(332)	K, M	0.8(4)	0.8(4)				
4700pF(472)	K, M	0.8(4)	0.8(4)				
6800pF(682)	K, M		0.8(4)				
10000pF(103)	K, M		0.8(4)				

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Methods (2) about $1.0\mu F$ products.

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Methods (2) about X5R, 10V products.

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Part Number			GNM31				
LxW		3.2x1.6					
тс			X7R (R7)				
Rated Volt.		100 (2A)	50 (1H)	16 (1C)	10 (1A)		
Capacitance, Ca	pacitanc	e Tolerance and T Dimension					
15000pF(153)	K, M		0.8(4)				
22000pF(223)	K, M			0.8(4)			
33000pF(333)	K, M			0.8(4)			
47000pF(473)	K, M			1.0(4)			
68000pF(683)	K, M			1.0(4)			
0.10μF(104)	K, M			1.0(4)			
1.0μF(105)	М				0.85(4)		

The part numbering code is shown in each (). The (4) code in T (mm) means number of elements (four). Dimensions are shown in mm and Rated Voltage in Vdc.

GNM Series Specifications and Test Methods (1)

No.	Ite	em		Specifications	Test Method		
			Temperature Compensating Type	High Dielectric Type			
1	Operating Temperating Range		5C: -55 to +125°C	R7: -55 to +125°C R6: -30 to +85°C			
2	Rated Vo	ltage	See the previous page	ges.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{0,p} , whichever is larger, should be maintained within the rated voltage range.		
3	Appearance No defects or abnormalities				Visual inspection		
4	Dimensio	ns	Within the specified	dimensions	Using calipers		
5	Dielectric Strength No defects or abnormalities			nalities	No failure should be observed when 300% of the rated voltage (5C) or 250% of the rated voltage (R7) is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.		
6	Insulation Resistant		More than 10,000MΩ (Whichever is smalle		The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°C and 75%RH max. and within 2 minutes of charging.		
7	Capacita	nce	Within the specified t	olerance	The capacitance/Q/D.F. should be measured at 25°C at the		
	Q/		30pF min.: Q≥1000 30pF max.:	Char. 25V min. 16V 10V 6.3V	frequency and voltage shown in the table. Char. 5C R7		
8	Dissipation	on Factor	Q≧400+20C	R7, R6 0.025 0.035 0.035 0.05 max. max. max. max.	Item 750 The Trequency 1±0.1MHz 1±0.1kHz		
	(D.F.)		C: Nominal Capacitance (pF)	max. max. max.	Voltage 0.5 to 5Vrms 1.0±0.2Vrms		
9	Capacitance Temperature	Capacitance Change	Within the specified tolerance (Table A) Within the specified tolerance (Table A)	Char. Temp. Range Reference Temp. Change R7 -55°C to +125°C 25°C Within ±15% R6 -55°C to +85°C 25°C ±15%	The capacitance change should be measured after 5 min. at each specified temperature stage. (1) Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step1 through 5, the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the steps 1, 3 and 5 by the cap. value in step 3.		
	Characteristics	Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger.)		Step Temperature (°C) 1 25±2 2 -55±3 (for 5C/R7), -30±3 (for F5) 3 25±2 4 125±3 (for 5C/R7), 85±3 (for F5) 5 20±2 (2) High Dielectric Constant Type The ranges of capacitance change compared with the above 25°C value over the temperature ranges shown in the table should be within the specified ranges.		
10	Adhesive Strength of Termination No removal of the terminations or other defect should occur. GNM 4 GNM 2 By Solder resist Copper foil		GNM 2 By Solder resist Copper foil	Solder the capacitor to the test jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 5N force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c d GNM1M2 0.5 1.6 0.32 0.32 GNM212 0.6 1.8 0.5 0.5 0.5 GNM214 0.6 2.0 0.25 0.25 GNM214 0.6 2.0 0.25 0.25 GNM314 0.8 2.5 0.4 0.4 (in mm)			



GNM Series Specifications and Test Methods (1)

Continued from the preceding page.

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				Specifications			
No.	Ite	em	Temperature Compensating Type	High Dielectric Type	Test Method		
		Appearance	No defects or abnorr	nalities	Solder the capacitor to the test jig (glass epoxy board) in the		
		Capacitance	Within the specified t	olerance	same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion		
11	Vibration Resistance	Q/D.F.	30pF min.: Q≥1000 30pF max.: Q≥400+20C C: Nominal Capacitance (pF)	Char. 25V min. 16V 10V 6.3V R7, R6 0.025 max. 0.035 max. 0.035 max. 0.05 max.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).		
			No cracking or marki	ng defects should occur.	Solder the capacitor on the test jig (glass epoxy board) shown		
			•GNM□□4	•GNM□□2	in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3 for 5±1 sec. The soldering should be done by the reflow method and should		
			7 100	100	be conducted with care so that the soldering is uniform and free of defects such as heat shock.		
12	2 Deflection		n t t t t t t t t t t t t t t t t t t t		20 50 Pressurizing speed : 1.0mm/sec. Pressurize		
			Туре	t=0.8mm	Flexure : ≤1 Capacitance meter		
				.0±0.05 0.5±0.05 0.32±0.05 0.32±0.05 0.5±0.05 0.5±0.05 0.5±0.05	45 45		
			GNM214 2	.0±0.05			
			GINIVI314 2	(in mm)	Fig. 3		
				Fig. 2			
13	Solderabi Terminati	,	75% of the termination continuously.	ons are to be soldered evenly and	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.		
	Resistanc Soldering		The measured and o specifications in the	bserved characteristics should satisfy the following table.			
		Appearance	No marking defects				
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7, R6: Within ±7.5%	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds. Let sit at room		
14		Q/D.F.	30pF min.: Q≥1000 30pF max.: Q≥400+20C C: Nominal	Char. 25V min. 16V 10V 6.3V R7, R6 0.025 max. 0.035 max. 0.035 max. 0.05 max.	Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement.		
			Capacitance (pF)				
		I.R.	More than 10,000Ms	2 or 500Ω · F (Whichever is smaller)	_		
	Dielectric Strength No failure						



GNM Series Specifications and Test Methods (1)

7	Continued f	rom the prec	eding page.									
NIO	1+.	em		Specification	ıs				Tor	st Metho	d	
No.	110	=111	Temperature Compensating Type		High Die	electric T	Гуре		restivietiou			
	Tempera Cycle	ture	The measured and conspecifications in the		eristics st	nould sat	tisfy the	Fix the capacitor to the supporting jig in the same manner and				
		Appearance	No marking defects					under the same conditions as (10). Perform the five cycles				
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7, R6: Within	±7.5%			according to the four heat treatments listed in the following table. Let sit for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure.				ating type)
15			30pF min.: Q≧1000					Step	1 Min.	2	Max.	4
13		Q/D.F.	30pF max.: Q≥400+20C	Char. 25V mii	1. 16V 0.035	10V 0.035	6.3V 0.05	Temp. (°C)	Operating Temp. +0/–3	Room Temp.	Operating Temp. +3/–0	Room Temp.
		Q/D.I .	C:Nominal	R7, R6 max.	max.	max.	max.	Time (min.)	30±3	2 to 3	30±3	2 to 3
			Capacitance (pF)					Initial measurement for high dielectric constant type				
		I.R.	More than 10,000Mg	2 or 500Ω · F (W	nichever	is smalle	er)		eat treatment a r 24±2 hours a		·10°C for one h	our and
		Dielectric Strength	No failure						initial measure		omporataro.	
	Humidity State		The measured and o		eristics st	nould sat	tisfy the					
		Appearance	No marking defects					-				
			Within ±5%					-				
		Capacitance Change	or ±0.5pF (Whichever is larger)	R7, R6: Within	±12.5%							
16		Q/D.F.	30pF and over: Q≥350 10pF and over, 30pF and obelow: Q≥275+5C/2 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	Char. 25V n R7, R6 0.09 max	5 0.0	5	0V/6.3V 0.05 max.	Sit the capacitor at 40±2°C and 90 to 95% humidity for 500 hours. Remove and let sit for 24±2 hours at room temperature, the measure.				
		I.R.	More than 1,000MΩ	or 50Ω · F (Whic	never is	smaller)						
		Dielectric Strength	No failure									
	Humidity	Load	The measured and o		eristics st	nould sat	tisfy the					
		Appearance	No marking defects									
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	R7, R6: Within	±12.5%				•)±2°C an	nd 90 to 95% hu	umidity for
17		Q/D.F.	30pF and over: Q≥200 30pF and below: Q≥100+10C/3 C: Nominal	Char. 25V m R7, R6 0.05 max	0.0	5 (V/6.3V 0.05 max.	 500±12 hours. Remove and let sit for 24±2 hours at room temperature, the measure. The charge/discharge current is less than 50mA. 			ture, then	
		I.R.	Capacitance (pF) More than 500MΩ or	250 · E /\//biob	ver is so	naller\		-				
		Dielectric	No failure	ZOZZ . L (ANUICUE	vei is sn	ialiel)		_				
		Strength	idildi o									



Continued from the preceding page

	Oomanaca n	on the preci	curry page.		
				Specifications	
No.			Temperature Compensating Type	High Dielectric Type	Test Method
	High Temperature Load The measured and observed characteristics should satisfy the specifications in the following table.		,		
		Appearance	No marking defects		
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	R7, R6: Within ±12.5%	Apply 200% of the rated voltage for 1000±12 hours at the maximum operating temperature ±3°C. Let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.
18		Q/D.F.	30pF and over:		Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage for one hour at the maximum operating temperature ±3°C. Remove and let sit for 24±2 hours at room temperature. Perform initial measurement.
		I.R.	More than 1,000M Ω	or $50\Omega \cdot F$ (Whichever is smaller)	

Table A

	Nominal Values (ppm/°C) Note 1	Capacitance Change from 25℃ (%)						
Char.		− 55℃		-30°C		−10°C		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11	

Note 1: Nominal values denote the temperature coefficient within a range of 25 to 125°C.

GNM Series Specifications and Test Methods (2)

No.	Ite	em	Specifications		Test Method		
1	Operating Temperatu	ıre Range	R6: -55°C to +85°C				
2	Rated Vo	ltage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, VP-P or VO-P, whichever is larger, should be maintained within the rated voltage range.			_{P-P} or V ^{o-P} ,
3	Appearar	nce	No defects or abnormalities	Visual inspection			
4	Dimensio	ns	Within the specified dimension	Using calipers			
5	Dielectric	Strength	No defects or abnormalities	No failure should be is applied between the provided the charge/o	e terminations for 1	to 5 secor	nds,
6	Insulation	Resistance	50Ω · F min.	The insulation resistate voltage not exceeding max. and within 1 min	g the rated voltage a		
7	Capacita	nce	Within the specified tolerance	The capacitance/D.F			at the
	Dissipation	n Footor		frequency and voltag	e snown in the table). 	
8	Dissipation (D.F.)	0.1 max.		Capacitance R6	Frequency 1±0.1kHz		tage .1Vrms
					TEU.TRITZ	0.5±0	. 1 V11115
	Capacitance Temperature Characteristics			The capacitance change should be measured affter 5 min.a each specified temperature stage. Step Temperature (°C) 1 25±2 2 -55±3 3 25±2			5 IIIII.at
			Charles Reference	4	25: 85:		
9			Char. Temp. Range Temp. Cap. Change	5	25:		
			R6	The ranges of capac value over the tempe within the specified ra Initial measurement Perform a heat treat then set for 24±2 hc Perform the initial m	rature ranges showr anges. for high dielectric co ment at 150+0/-10°0 ours at room tempera	n in the tab onstant typ C for one h	le should be e.
			No removal of the terminations or other defects should occur.	Solder the capacitor to	o the test jig (glass e	ooxy board) shown in
10	Adhesive of Termin	•	b a b b b b b b b b b b b b b b b b b b	Fig. 1 using a eutectic Then apply 5N force is soldering should be do method and should be is uniform and free of	n parallel with the tes one either with an iro e conducted with care	n or using e so that th	the reflow
			Solder resist — Copper foil	GNM1M2	0.5 1.6	0.32	0.32
			— сорры топ	GNM212	0.6 1.8	0.5	0.5
			Fig. 1				(in mm)
		Appearance	No defects or abnormalities	Solder the capacitor	to the test jig (glass	epoxy boa	rd) in
		Capacitance	Within the specified tolerance	the same manner and	d under the same co	onditions a	s (10).
11	Vibration	D.F.	0.1 max.	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).			eing varied 55Hz. 10Hz, s motion





GNM Series Specifications and Test Methods (2)

Vo.	J†c	em	Specifications	Test Method				
	ne	2111	No cracking or marking defects should occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.				
12	Deflection	n	20 50 Pressurizing speed: 1.0mm/sec. Pressurize R230 Flexure: ≤1 Capacitance meter 45 45	Thickness: 0.8mm				
			Fig. 3	Type a b c d GNM1M2 2.0±0.5 0.5±0.05 0.32±0.05 0.32±0.05 GNM212 2.0±0.05 0.6±0.05 0.5±0.05 0.5±0.05 (in mm) Fig. 2				
				Immerse the capacitor in a solution of ethanol (JIS-K-8101) and				
13	Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.	rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.				
		Appearance	No marking defects	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse				
	Resistance	Capacitance Change	R6: Within ±7.5%	the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds.				
14	to Soldering Heat	D.F.	0.1 max.	Let sit at room temperature for 24±2 hours, then measure. • Initial measurement				
		I.R.	$50\Omega \cdot$ F min.	Perform a heat treatment at 150 +0/-10°C for one hour and				
		Dielectric Strength	No failure	then let sit for 24±2 hours at room temperature. Perform the initial measurement.				
		Appearance	No marking defects	Fix the capacitor to the supporting jig in the same manner and				
		Capacitance Change	R6: Within ±12.5%	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table.				
		D.F.	0.1 max.	Let sit for 24±2 hours at room temperature, then measure.				
	Temperature	I.R.	50Ω · F min.	Step 1 2 3 4				
15	Cycle	Dielectric Strength	No failure	Temp. (°C) Min. Operating Temp. Room Temp. Temp. Time (min.) 30±3 2 to 3 30±3 2 to 3 • Initial measurement Perform a heat treatment at 150 +0/-10 °C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement.				
		Appearance	No marking defects	Apply the rated voltage at 40±2°C and 90 to 95% humidity for				
	High Temperature	Capacitance Change	R6: Within ±12.5%	500±12 hours. The charge/discharge current is less than 50mA • Initial measurement Perform a heat treatment at 150 +0/-10°C for one hour				
16	High	D.F.	0.2 max.	and then let sit for 24±2 hours at room temperature.				
. 5	Humidity (Steady)	I.R.	12.5Ω · F min.	Perform the initial measurement. • Measurement after test				
	(o.oaaj)	Dielectric Strength	No failure	Perform a heat treatment at 150 +0/-10°C for one hour and then let sit for 24±2 hours at room temperature, then measure.				
		Appearance	No marking defects	Apply 125% of the rated voltage for 1000±12 hours at the				
		Capacitance Change	R6: Within ±12.5%	maximum operating temperature ±3°C. Let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.				
		D.F.	0.2 max.	Initial measurement				
17	Durability	I.R.	$25\Omega \cdot$ F min.	Perform a heat treatment at 150 +0/-10°C for one hour				
		Dielectric Strength	No failure	 and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test Perform a heat treatment at 150 +0/-10°C for one hour and then let sit for 24±2 hours at room temperature, then measure. 				

Chip Monolithic Ceramic Capacitors



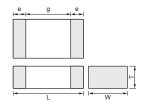
for Ultrasonic Sensors GRM Series

- Features
- 1. Proper to compensate for ultrasonic sensor
- 2. Small chip size and high cap. value
- Applications

Ultrasonic sensor

(Back sonar, Corner sonar, etc.)





Part Number	Dimensions (mm)						
Part Number	L	W	T	е	g min.		
GRM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7		

Part Number	TC Code	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM2199E2A102KD42	ZLM (Murata)	100	1000 ±10%	2.0	1.25	0.85
GRM2199E2A152KD42	ZLM (Murata)	100	1500 ±10%	2.0	1.25	0.85

No.	Ite	em	Specifications		Test Method		
1	Operating Temperat		−25 to +85°C	Reference Tempera	ature: 20°C		
2	Rated Vo	ltage	See the previous pages.	may be applied conf When AC voltage is	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{C-P} , whichever is larger, should be maintained within the rated voltage range.		
3	Appearar	nce	No defects or abnormalities	Visual inspection			
4	Dimensio	ns	Within the specified dimensions	Using calipers			
5	Dielectric	Strength	No defects or abnormalities	is applied between t	e observed when 300% of the rated voltage the terminations for 1 to 5 seconds, provid- arge current is less than 50mA.		
6	Insulation (I.R.)	Resistance	More than 10,000M Ω		tance should be measured with a DC volthe rated voltage at 20°C and 75%RH max. s of charging.		
7	Capacita	nce	Within the specified tolerance	The capacitance/D I	F. should be measured at 20℃ with		
8	Dissipatio (D.F.)	n Factor	0.01 max.		ncy and 1±0.2Vrms in voltage.		
9	Capacitance		Within −4,700 ^{±1} .200 ppm/°C (at −25 to ±20°C) Within −4,700 ^{±500} .000 ppm/°C (at ±20 to ±85°C)	capacitance measur When cycling the te 5, the capacitance s the temperature coe The capacitance chi each specified temp	ange should be measured after 5 min. at perature stage.		
	Character		Within −4,700 ±1,000 ppm/ € (at +20 to +85 €)	Step 1	Temperature (℃) 20±2		
				2	——————————————————————————————————————		
				3	20±2		
				4	85±3		
				5	20±2		
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Fig.1 using a eutect direction of the arrow The soldering shoul- reflow method and s	d be done either with an iron or using the should be conducted with care so that the and free of defects such as heat shock. Solder resist Baked electrode or copper foil a b c 1.2 4.0 1.65 (in mm)		
		Annos	No defects or obverselities	Colder the	Fig. 1		
		Appearance	No defects or abnormalities		r to the test jig (glass epoxy board) in the inder the same conditions as (10).		
11	Vibration Resistance	D.F.	0.01 max.	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).			





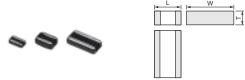
\overline{A}	Continued fr	om the prec	eding page.				
No.	Ite	em	Specifications	Test Method			
			No cracking or marking defects should occur.	Solder the capacitor to the test jig (glass epoxy boards) shown in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and should			
12	2 Deflection		Type a b c GRM21 1.2 4.0 1.65 (in mm)	be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/sec. Pressurize R230 Flexure: ≤1 Capacitance meter 45 Fig.3			
13	Solderability of Termination 75% of the terminations are to be soldered evenly and continuously.			Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5℃ or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5℃.			
		Appearance	No defects or abnormalities				
	Resistance	Capacitance Change	Within ±7.5%	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution			
14	to Soldering Heat	D.F.	0.01 max.	at 270±5°C for 10±0.5 seconds. Let sit at room temperature for			
	пеаі	I.R.	More than 10,000M Ω	24±2 hours, then measure.			
		Dielectric Strength	No failure				
		Appearance	No defects or abnormalities	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (11).			
	Temperature	Capacitance Change	Within ±7.5%	Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room temperature, then measure.			
15	Cycle	D.F.	0.01 max.				
		I.R.	More than 10,000M Ω	Step 1 2 3 4 Temp. (°C) -25^{+3}_{-3} Room Temp. 85^{+3}_{-3} Room Temp.			
		Dielectric Strength	No failure	Time (min.) 30±3 2 to 3 30±3 2 to 3			
		Appearance	No defects or abnormalities				
	Humidity,	Capacitance Change	Within ±12.5%	Sit the capacitor at 40±2°C and 90 to 95% humidity for 500±12 hours.			
16	Steady State	D.F.	0.02 max.	Remove and let sit for 24±2 hours at room temperature, then			
	State	I.R. Dielectric	More than 1,000M Ω No failure	measure.			
		Strength					
		Appearance	No defects or abnormalities	Apply the rated voltage at 40±2°C and 90 to 95% humidity for			
17	Humidity Load	Capacitance Change	Within ±12.5%	500±12 hours. Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less			
		D.F.	0.02 max.	than 50mA.			
		I.R.	More than $500M\Omega$				
		Appearance	No defects or abnormalities				
18	High Temperature	Capacitance Change	Within ±12.5%	Apply 200% of the rated voltage for 1,000±12 hours at 85±3°C. Let sit for 24±2 hours at room temperature, then measure.			
	Load	D.F.	0.02 max.	The charge/discharge current is less than 50mA.			
		I.R.	More than 1,000M Ω				

Chip Monolithic Ceramic Capacitors



Low ESL LLL/LLA/LLM Series

- Features (Reversed Geometry Low ESL Type)
- 1. Low ESL, good for noise reduction for high frequency
- 2. Small, high cap
- Applications
- 1. High speed microprocessor
- 2. High frequency digital equipment



Part Number		Dimensions (mm))	
Fait Number	L	W	Т	
LLL153	0.5 ±0.05	1.0 ±0.05	0.3 ±0.05	
LLL185	0.8 ±0.1	1.6 ±0.1	0.6 max.	
LLL215			0.5 +0/-0.15	
LLL216	1.25 ±0.1	2.0 ±0.1	0.6 ±0.1	
LLL219			0.85 ±0.1	
LLL315			0.5 +0/-0.15	
LLL317	1.6 +0.15	3.2 +0.15	0.7 ±0.1	
LLL31M	1.0 ±0.15	3.2 ±0.13	1.15 ±0.1	
LLL31B	1		1.25 +0.15/-0.05	

Reversed Geometry Low ESL Type

Part Number	LLL15			LL	L18					LL	L21					LLI	L31		
LxW	0.5x1.0			0.8	x1.6					1.25	x2.0					1.62	x3.2		
тс	X6S (C8)			X7R (R7)			X7S (C7)			X7R (R7)			X7S (C7)			X7R (R7)			X7S (C7)
Rated Volt.	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)
Capacitance (Ca	apacita	nce pa	rt numb	pering o	code) a	nd T (n	nm) Din	nensior	n (T Din	nensior	n part n	umber	ing cod	de)					
2200pF (222)		0.5 (5)																	
4700pF (472)		0.5 (5)						0.6 (6)											
10000pF (103)			0.5 (5)					0.6 (6)						0.7 (7)					
22000pF (223)			0.5 (5)					0.6 (6)						0.7 (7)					
47000pF (473)				0.5 (5)					0.6 (6)					0.7 (7)					
0.10μF (104)	0.3 (3)				0.5 (5)				0.6 (6)					1.15 (M)	0.7 (7)				
0.22μF (224)						0.5 (5)				0.85 (9)	0.6 (6)				1.15 (M)	0.7 (7)			
0.47μF (474)							0.5 (5)				0.85 (9)				1.15 (M)	0.7 (7)			
1.0μF (105)							0.5 (5)					0.85 (9)				1.15 (M)	0.7 (7)		
2.2μF (225)							0.5 (5)						0.85 (9)				1.15 (M)	0.7 (7)	
4.7μF (475)																		1.15 (M)	
10μF (106)																			1.25 (B)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Method (2) about LLL15 Series and LLL18 Series 1.0 μ F/2.2 μ F type.

Reversed Geometry Low ESL Type Low Profile

Part Number		LLI	L18				LLI	L21				LL	L31	
LxW		0.8	x1.6				1.25	x2.0				1.6	x3.2	
TC		X7R (R7)		X7S (C7)			X7R (R7)			X7S (C7)			7R ?7)	
Rated Volt.	25 (1E)	16 (1C)	10 (1A)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacitance	e part nur	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberin	g code)				
1000pF(102)					0.5(5)									
2200pF(222)					0.5(5)									
4700pF(472)					0.5(5)									
10000pF(103)	0.5(5)				0.5(5)						0.5(5)			
22000pF(223)		0.5(5)				0.5(5)					0.5(5)			
47000pF(473)		0.5(5)					0.5(5)					0.5(5)		
0.10μF(104)			0.5(5)				0.5(5)					0.5(5)		
0.22μF(224)				0.5(5)				0.5(5)					0.5(5)	
0.47μF(474)									0.5(5)					0.5(5)
1.0μF(105)										0.5(5)				

The part numbering code is shown in ().

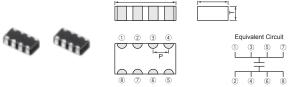
Dimensions are shown in mm and Rated Voltage in Vdc.

■ Features (Eight Terminals Low ESL Type)

- Low ESL(100pH), suitable to decoupling capacitor for 1GHz clock speed IC.
- 2. Small, large cap

■ Applications

- 1. High speed microprocessor
- 2. High frequency digital equipment



			. , ,						
Part Number	Dimensions (mm)								
Part Number	L	W	T	Р					
LLA185	1.6 ±0.1	0.8 ±0.1	0.5 +0.05/-0.1	0.4 ±0.1					
LLA215	2.0 ±0.1	1.25 ±0.1	0.5 +0.05/-0.1	0.5 ±0.05					
LLA219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.5 ±0.05					
LLA315	3.2 ±0.15	1.6 ±0.15	0.5 +0.05/-0.1	0.8 ±0.1					
LLA319	3.2 ±0.15	1.6 ±0.15	0.85 ±0.1	0.8 ±0.1					
LLA31M	3.2 ±0.15	1.6 ±0.15	1.15±0.1	0.8 ±0.1					

Eight Terminals Low ESL Type

Part Number	LLA18			LLA21				LLA31	
LxW	1.6x0.8			2.0x1.25				3.2x1.6	
тс	X7S (C7)			7R R7)		X7S (C7)		X7R (R7)	
Rated Volt.	4 (0G)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	16 (1C)	10 (1A)	4 (0G)
Capacitance (Ca	pacitance par	t numbering co	ode) and T (mn	n) Dimension (1	Dimension pa	rt numbering o	ode)	<u>'</u>	
10000pF(103)		0.85(9)							
22000pF(223)		0.85(9)							
47000pF(473)		0.85(9)							
0.10μF(104)	0.5(5)		0.85(9)				0.85(9)		
0.22μF(224)	0.5 (5)		0.85(9)				0.85(9)		
0.47μF(474)	0.5 (5)			0.85(9)			0.85(9)		
1.0μF(105)	0.5 (5)				0.85(9)			0.85(9)	
2.2μF(225)	0.5 (5)					0.85(9)		1.15(M)	0.85(9)
4.7μF(475)						0.85(9)			

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Method (2) about LLA18 Series $1.0\mu F/2.2\mu F$ type and LLA21 Series $4.7\mu F$ type.



Eight Terminals Low ESL Type Low Profile

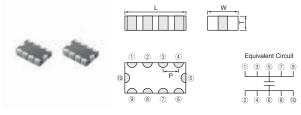
Part Number			LLA21				LLA31	
LxW	2.0x1.25 3.2x				3.2x1.6			
тс							X7R (R7)	
Rated Volt.	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	16 (1C)	10 (1A)	6.3 (0J)
Capacitance (Cap	pacitance part n	numbering code)	and T (mm) Dim	ension (T Dimer	sion part numbe	ring code)		
10000pF(103)	0.5(5)							
22000pF(223)	0.5(5)							
47000pF(473)		0.5(5)						
0.10μF(104)		0.5 (5)				0.5(5)		
0.22μF(224)			0.5 (5)	0.5(5)		0.5(5)		
0.47μF(474)				0.5(5)			0.5(5)	
1.0μF(105)					0.5(5)			0.5(5)
2.2μF(225)					0.5(5)			0.5(5)
4.7μF(475)					0.5(5)			

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Method (2) about LLA21 Series (Low Profile) 2.2μF/4.7μF type.

- Features (Ten Terminals Low ESL Type)
- 1. Low ESL(45pH), suitable to decoupling capacitor for 2GHz clock speed IC.
- 2. Small, large cap
- Applications
- 1. High speed microprocessor
- 2. High frequency digital equipment



Part Number	Dimensions (mm)								
Part Number	L	W	Т	Р					
LLM215	2.0 ±0.1	1.25 ±0.1	0.5 +0.05/-0.1	0.5 ±0.05					
LLM315	3.2 ±0.15	1.6 ±0.15	0.5 +0.05/-0.1	0.8 ±0.1					

Ten Terminals Low ESL Type Low Profile

Part Number		LLI	W21			LLM31	
LxW		2.0x	1.25			3.2x1.6	
тс		X7R (R7)		X7S (C7)		X7R (R7)	
Rated Volt.	25 (1E)	16 (1C)	6.3 (0J)	4 (0G)	16 (1C)	10 (1A)	6.3 (0J)
Capacitance (Ca	pacitance part nur	mbering code) and	T (mm) Dimension	(T Dimension part	numbering code)		
10000pF(103)	0.5 (5)						
22000pF(223)	0.5 (5)						
47000pF(473)		0.5 (5)					
0.10μF(104)		0.5 (5)			0.5 (5)		
0.22μF(224)			0.5(5)		0.5 (5)		
0.47μF(474)			0.5 (5)			0.5(5)	
1.0μF(105)				0.5 (5)			
2.2μF(225)				0.5 (5)			0.5(5)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Method (2) about LLM21 Series (Low Profile) $2.2\mu F$ type.



LLL/LLA/LLM Series Specifications and Test Methods (1)

No.	Ite	em	Specifications	Test Method					
1	Operating Temperating Range		R7, C7: -55 to +125°C						
2	Rated Vo	Itage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{O-P} , whichever is larger, should be maintained within the rated voltage range.					
3	Appearar	nce	No defects or abnormalities	Visual inspection					
4	Dimensio	ns	Within the specified dimension	Using calipers					
5	Dielectric	Strength	No defects or abnormalities	No failure should be observed when 250% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.					
6	Insulation Resistant		More than 10,000M Ω or 500 Ω · F (Whichever is smaller)	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°C and 75%RH max. and within 2 minutes of charging.					
7	Capacita	nce	Within the specified tolerance	The capacitance/D.F. should be measured at 25°C at the frequency and voltage shown in the table.					
8	Dissipatio (D.F.)	n Factor	W.V.: 25V min.; 0.025 max. W.V.: 16V max.; 0.035 max. *1	Capacitance Frequency Voltage C≤10μF (10V min.) 1±0.1kHz 1.0±0.2Vrms C≤10μF (6.3V max.) 1±0.1kHz 0.5±0.1Vrms C>10μF 120±24Hz 0.5±0.1Vrms					
9	Capacitar Temperat Character	ure	Char. Temp. Range (°C) Reference Temp. Cap.Change R7 -55 to +125 25°C Within ±15% C7 -55 to +125 25°C Within ±22%	The capacitance change should be measured after 5 min. at each specified temperature stage. Step Temperature (°C) 1 25±2 2 -55±3 3 25±2 4 125±3 5 25±2					
				The ranges of capacitance change compared with the 25°C value over the temperature ranges shown in the table should be within the specified ranges.					
10	Adhesive of Termin		No removal of the terminations or other defect should occur.	Solder the capacitor to the test jig (glass epoxy board) using a eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *LLL18 and LLA/LLM Series: 5N					
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in					
		Capacitance	Within the specified tolerance	the same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion					
11	Vibration Resistance	D.F.	W.V.: 25V min.; 0.025 max. W.V.: 16V max.; 0.035 max. *1	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).					
12	Solderab Terminati	-	75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C, or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.					
		Appearance	No marking defects	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse					
	Docietanas	Capacitance Change	Within ±7.5%	the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds. Let sit at room					
13	Resistance to Soldering Heat	D.F.	W.V.: 25V min.; 0.025 max. W.V.: 16V max.; 0.035 max. *1	temperature for 24±2 hours, then measure. • Initial measurement.					
		I.R.	More than 10,000M Ω or 500 Ω · F (Whichever is smaller)	Perform a heat treatment at 150 $^{+0}_{-10}$ °C for one hour and then					
		Dielectric Strength	No failure	let sit for 24±2 hours at room temperature. Perform the initial measurement.					



LLL/LLA/LLM Series Specifications and Test Methods (1)

No.	Ite	em	Specifications	Test Method						
		Appearance Capacitance Change	No marking defects Within ±7.5% *1	Fix the capacitor to the supporting jig in the same manner a under the same conditions as (10). Perform the five cycles according to the four heat treatmen listed in the following table. Let sit for 24±2 hours at room						
		D.F.	W.V.: 25V min.; 0.025 max. W.V.: 16V max.; 0.035 max. *1	temperature, then measure. Step 1 2 3 4						
14	Temperature Cycle	I.R.	More than 10,000M Ω or 500 Ω · F (Whichever is smaller)	Temp. (°C) Min. Operating Room Temp. $\stackrel{+3}{\sim}$ Temp. $\stackrel{+3}{\sim}$ Temp. $\stackrel{+3}{\sim}$ Temp.						
	3,500	Dielectric Strength	No failure	Time (min.) 30±3 2 to 3 30±3 2 to 3 • Initial measurement. Perform a heat treatment at 150±0 °C for one hour and to let sit for 24±2 hours at room temperature. Perform the in measurement.						
		Appearance	No marking defects							
15	Humidity (Steady	Capacitance Change	Within ±12.5% *1	Sit the capacitor at 40±2°C and 90 to 95% humidity for 500 hours. Remove and let sit for 24±2 hours at room tempera						
	State)	D.F.	0.05 max. *1	then measure.						
		I.R.	More than 1,000M Ω or 50 Ω · F (Whichever is smaller)							
		Appearance	No marking defects							
		Capacitance Change	Within ±12.5% *1	Apply the rated voltage at 40±2°C and 90 to 95% humidity						
16	Humidity	D.F.	0.05 max. *1	500±12 hours. Remove and let sit for 24±2 hours at room						
	Load	I.R.	More than $500M\Omega$ or $25\Omega \cdot F$ *1 (Whichever is smaller)	temperature, then measure. The charge/discharge current less than 50mA.						
		Dielectric Strength	No failure							
		Appearance	No marking defects	Apply 200% of the rated voltage for 1000±12 hours at the						
		Capacitance Change	Within ±12.5% *1	maximum operating temperature ±3°C. Let sit for 24±2 ho at room temperature, then measure. The charge/discharge						
17	High Temperature	D.F.	W.V.: 25V min.; 0.04 max. W.V.: 16V max.; 0.05 max. *1	current is less than 50mA. •Initial measurement.						
	Load	I.R. More than $1,000M\Omega$ or $50\Omega \cdot F *1$ (Whichever is smaller)		Apply 200% of the rated DC voltage for one hour at the maximum operating temperature ±3°C. Remove and let s						
		Dielectric Strength	No failure	24±2 hours at room temperature ±3°C. Remove and let sit to 24±2 hours at room temperature. Perform initial measurement. (*1)						

^{*1:} The figure indicates typical inspection.Please refer to individual specifications.

LLL/LLA/LLM Series Specifications and Test Methods (2)

No.	Ite	em		Spe	cifications		Te	est Method			
1	Operating Temperat Range	,	R7, C7: -55 C8: -55 to -								
2	Rated Vo	ltage	See the pre	vious pages.			The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{O-P} , whichever is larger, should be maintained within the rated voltage range.				
3	Appearar	nce	No defects of	or abnormalities			Visual inspection				
4	Dimensio	ns	Within the s	pecified dimension	on		Using calipers				
5	Dielectric	Strength	No defects of	or abnormalities			No failure should be observed is applied between the term provided the charge/discharge.	ninations for 1 to	5 seconds,		
6	Insulation Resistance		50Ω · F min.				The insulation resistance s not exceeding the rated vol within 1 minute of charging	tage at 25°C and	•		
7	Capacita	nce	Within the s	pecified tolerance	Э		The capacitance/D.F. shou frequency and voltage show		at 25°C at the		
8	Dissipatio (D.F.)	n Factor	R7, C7, C8:	0.120 max.			Capacitance Frequency Voltage C≤10μF (10V min.) 1±0.1kHz 1.0±0.2Vrms C≤10μF (6.3V max.) 1±0.1kHz 0.5±0.1Vrms C>10μF 120±24Hz 0.5±0.1Vrms				
9	Capacitar Temperat Character	ure	Char. R7 C7 C8	Temp. Range (°C) -55 to +125 -55 to +125 -55 to +105	Reference Temp. 25°C	Cap.Change Within ±15% Within ±22% Within ±22%	The capacitance change st each specified temperature The ranges of capacitance value over the temperature be within the specified range	stage. change compare ranges shown ir	ed with the 25°C		
10	Adhesive of Termin		No removal	of the termination	ns or other defe	ct should occur.	Solder the capacitor to the eutectic solder. Then apply jig for 10±1 sec. The solde iron or using the reflow met care so that the soldering is heat shock.	10N* force in pa ring should be do thod and should s uniform and fre	rallel with the test one either with an be conducted with		
		Appearance	No defects of	or abnormalities			Solder the capacitor to the test jig (glass epoxy board) in				
		Capacitance	Within the s	pecified tolerance			the same manner and under		, ,		
11	Vibration	D.F.	R7, C7, C8:	0.120 max.			capacitor should be subject having a total amplitude of uniformly between the appr frequency range, from 10 to be traversed in approximate applied for a period of 2 ho perpendicular directions (to	1.5mm, the frequency formate limits of the contract of 55Hz and returnely 1 minute. Thingurs in each of 3 minutes	uency being varied 10 and 55Hz. The n to 10Hz, should s motion should be		
12	Solderab Terminati		75% of the te	erminations are to	be soldered eve	enly	Immerse the capacitor in a rosin (JIS-K-5902) (25% ro 80 to 120°C for 10 to 30 se eutectic solder solution for Sn-3.0Ag-0.5Cu solder solu	sin in weight pro conds. After prel 2±0.5 seconds a	portion). Preheat at heating, immerse in at 230±5°C, or		
		Appearance	No marking	defects			Preheat the capacitor at 12				
	Resistance	Capacitance Change	R7, C7, C8: Within ±7.5%				the capacitor in a eutectic s solution at 270±5°C for 10: Let sit at room temperature	±0.5 seconds.			
13	to Soldering	D.F.	R7, C7, C8:	0.120 max.			- Initial magazine				
	Heat	I.R.	50Ω · F min				Initial measurement. Perform a heat treatment.	at 150 ^{±2} 0°C for	one hour and then		
		Dielectric Strength	No failure				let sit for 24±2 hours at romeasurement.				





LLL/LLA/LLM Series Specifications and Test Methods (2)

lo.	Item	Specifications	Test Method							
	Appearance Capacitance Change	No marking defects R7, C7, C8: Within ±12.5%	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10).Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room temperature,							
	D.F.	R7, C7, C8: 0.120 max.	then measure.							
Temperatu	e I.R.	$50Ω \cdot F$ min.	Step 1 2 3 4							
14 Sudden Change			Temp. (°C) Min. Operating Temp. ±3 Room Temp. ±3 Temp. ±3 Temp.							
	Dielectric		Time (min.) 30±3 2 to 3 30±3 2 to 3							
	Strength	No failure	 Initial measurement Perform a heat treatment at 150 ± 20 °C for one hour and there let sit for 24±2 hours at room temperature. Perform the initial measurement. 							
	Appearance	No marking defects	Apply the rated voltage at 40±2°C and 90 to 95% humidity for							
High	Capacitance Change	R7, C7, C8: Within ±12.5%	500±12 hours. The charge/discharge current is less than 50mA.							
Temperat	D.F.	R7, C7, C8: 0.2 max.	•Initial measurement							
High Humidity (Steady State)	I.R.	12.5 Ω · F min.	Perform a heat treatment at 150±9°° C for one hour and ther let sit for 24±2 hours at room temperature. Perform the initia measurement. •Measurement after test Perform a heat treatment at 150±9°° C for one hour and ther let sit for 24±2 hours at room temperature, then measure.							
	Appearance	No marking defects	Apply 150% of the rated voltage for 1000±12 hours at the							
	Capacitance Change	R7, C7, C8: Within ±12.5%	maximum operating temperature ±3°C. The charge/discharge current is less than 50mA.							
	D.F.	R7, C7, C8: 0.2 max.	•Initial measurement							
16 Durabili	, , , , , , , , , , , , , , , , , , , ,		Perform a heat treatment at 150 ± γ _o °C for one hour and ther let sit for 24±2 hours at room temperature. Perform the initia measurement. •Measurement after test Perform a heat treatment at 150 ± γ _o °C for one hour and there							

let sit for 24 \pm 2 hours at room temperature, then measure.

Chip Monolithic Ceramic Capacitors

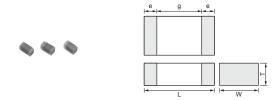
High-Q GJM Series

■ Features

- 1. Mobile telecommunications and RF module, mainly
- 2. Quality improvement of telephone call, low power consumption, yield ratio improvement

■ Applications

VCO, PA, Mobile telecommunications



Part Number		Dimensions (mm)						
Part Number	L	W	T	е	g min.			
GJM03	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2			
GJM15	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4			

Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance (Capacitan	nce part numbering code) and T (mm) Dimension (T Dime	ension part numbering code)
0.20pF(R20)	0.3(3)	
0.30pF(R30)	0.3(3)	0.5(5)
0.40pF(R40)	0.3(3)	0.5(5)
0.50pF(R50)	0.3(3)	0.5(5)
0.60pF(R60)	0.3(3)	0.5(5)
0.70pF(R70)	0.3(3)	0.5(5)
0.75pF(R75)	0.3(3)	0.5(5)
0.80pF(R80)	0.3(3)	0.5 (5)
0.90pF(R90)	0.3(3)	0.5 (5)
1.0pF(1R0)	0.3(3)	0.5(5)
1.1pF(1R1)	0.3(3)	0.5(5)
1.2pF(1R2)	0.3(3)	0.5(5)
1.3pF(1R3)	0.3(3)	0.5 (5)
1.4pF(1R4)	0.3(3)	0.5(5)
1.5pF(1R5)	0.3(3)	0.5(5)
1.6pF(1R6)	0.3(3)	0.5(5)
1.7pF(1R7)	0.3(3)	0.5(5)
1.8pF(1R8)	0.3(3)	0.5(5)
1.9pF(1R9)	0.3(3)	0.5(5)
2.0pF(2R0)	0.3(3)	0.5(5)
2.1pF(2R1)	0.3(3)	0.5(5)
2.2pF(2R2)	0.3(3)	0.5(5)
2.3pF(2R3)	0.3(3)	0.5(5)
2.4pF(2R4)	0.3(3)	0.5(5)
2.5pF(2R5)	0.3(3)	0.5(5)
2.6pF(2R6)	0.3(3)	0.5(5)
2.7pF(2R7)	0.3(3)	0.5(5)
2.8pF(2R8)	0.3(3)	0.5(5)
2.9pF(2R9)	0.3(3)	0.5(5)
3.0pF(3R0)	0.3(3)	0.5(5)
3.1pF(3R1)	0.3(3)	0.5(5)
3.2pF(3R2)	0.3(3)	0.5(5)
3.3pF(3R3)	0.3(3)	0.5(5)

Continued from the preceding page.

Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance (Capacitance pa	art numbering code) and T (mm) Dimension ((T Dimension part numbering code)
3.4pF(3R4)	0.3(3)	0.5(5)
3.5pF(3R5)	0.3(3)	0.5(5)
3.6pF(3R6)	0.3(3)	0.5(5)
3.7pF(3R7)	0.3(3)	0.5(5)
3.8pF(3R8)	0.3(3)	0.5(5)
3.9pF(3R9)	0.3(3)	0.5(5)
4.0pF(4R0)	0.3(3)	0.5(5)
4.1pF(4R1)	0.3(3)	0.5(5)
4.2pF(4R2)	0.3(3)	0.5(5)
4.3pF(4R3)	0.3(3)	0.5(5)
4.4pF(4R4)	0.3(3)	0.5(5)
4.5pF(4R5)	0.3(3)	0.5(5)
4.5pF(4R6)	0.3(3)	0.5(5)
4.6pF(4R7)	0.3(3)	0.5(5)
4.7pF(4R7) 4.8pF(4R8)	0.3(3)	0.5(5)
4.9pF(4R9)	0.3(3)	0.5(5)
5.0pF(5R0)	0.3(3)	0.5(5)
5.1pF(5R1)	0.3(3)	0.5(5)
5.2pF(5R2)	0.3(3)	0.5(5)
5.3pF(5R3)	0.3(3)	0.5(5)
5.4pF(5R4)	0.3(3)	0.5(5)
5.5pF(5R5)	0.3(3)	0.5(5)
5.6pF(5R6)	0.3(3)	0.5(5)
5.7pF(5R7)	0.3(3)	0.5(5)
5.8pF(5R8)	0.3(3)	0.5(5)
5.9pF(5R9)	0.3(3)	0.5(5)
6.0pF(6R0)	0.3(3)	0.5(5)
6.1pF(6R1)	0.3(3)	0.5(5)
6.2pF(6R2)	0.3(3)	0.5(5)
6.3pF(6R3)	0.3(3)	0.5(5)
6.4pF(6R4)	0.3(3)	0.5(5)
6.5pF(6R5)	0.3(3)	0.5(5)
6.6pF(6R6)	0.3(3)	0.5(5)
6.7pF(6R7)	0.3(3)	0.5(5)
6.8pF(6R8)	0.3(3)	0.5(5)
6.9pF(6R9)		0.5(5)
7.0pF(7R0)		0.5(5)
7.1pF(7R1)		0.5(5)
7.2pF(7R2)		0.5(5)
7.3pF(7R3)		0.5(5)
7.4pF(7R4)		0.5(5)
7.5pF(7R5)		0.5(5)
7.6pF(7R6)		0.5(5)
7.7pF(7R7)		0.5(5)
7.8pF(7R8)		0.5(5)
7.9pF(7R9)		0.5(5)
8.0pF(8R0)		0.5(5)
8.1pF(8R1)		0.5(5)
8.2pF(8R2)		0.5(5)
8.3pF(8R3)		0.5(5)
8.4pF(8R4)		0.5(5)
8.5pF(8R5)		0.5 (5)

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Continued from the preceding page.

Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance (Capac	citance part numbering code) and T (mm) Dimension (T Dimen	sion part numbering code)
8.6pF(8R6)		0.5(5)
8.7pF(8R7)		0.5(5)
8.8pF(8R8)		0.5(5)
8.9pF(8R9)		0.5(5)
9.0pF(9R0)		0.5(5)
9.1pF(9R1)		0.5(5)
9.2pF(9R2)		0.5(5)
9.3pF(9R3)		0.5(5)
9.4pF(9R4)		0.5(5)
9.5pF(9R5)		0.5(5)
9.6pF(9R6)		0.5(5)
9.7pF(9R7)		0.5(5)
9.8pF(9R8)		0.5(5)
9.9pF(9R9)		0.5(5)
10pF(100)		0.5(5)
12pF(120)		0.5(5)
15pF(150)		0.5(5)
18pF(180)		0.5 (5)

The part numbering code is shown in $\,$ ().

Dimensions are shown in mm and Rated Voltage in Vdc.

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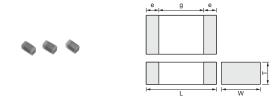
Tight Tolerance High-Q GJM Series

■ Features

- 1. Mobile telecommunications and RF module, mainly
- 2. Quality improvement of telephone call, low power consumption, yield ratio improvement

■ Applications

VCO, PA, Mobile telecommunications



Part Number	Dimensions (mm)						
Part Number	L	W	T	е	g min.		
GJM03	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2		
GJM15	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4		

Part Number		GJM03	GJM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	pacitano	ce Tolerance and T Dimension	
0.10pF(R10)	W, B		0.5(5)
0.20pF(R20)	W, B	0.3(3)	0.5(5)
0.30pF(R30)	W, B	0.3(3)	0.5(5)
0.40pF(R40)	W, B	0.3(3)	0.5(5)
0.50pF(R50)	W, B	0.3(3)	0.5(5)
0.60pF(R60)	W, B	0.3(3)	0.5(5)
0.70pF(R70)	W, B	0.3(3)	0.5(5)
0.80pF(R80)	W, B	0.3(3)	0.5(5)
0.90pF(R90)	W, B	0.3(3)	0.5(5)
1.0pF(1R0)	W, B	0.3(3)	0.5(5)
1.1pF(1R1)	W, B	0.3(3)	0.5(5)
1.2pF(1R2)	W, B	0.3(3)	0.5(5)
1.3pF(1R3)	W, B	0.3(3)	0.5(5)
1.4pF(1R4)	W, B	0.3(3)	0.5(5)
1.5pF(1R5)	W, B	0.3(3)	0.5(5)
1.6pF(1R6)	W, B	0.3(3)	0.5(5)
1.7pF(1R7)	W, B	0.3(3)	0.5(5)
1.8pF(1R8)	W, B	0.3(3)	0.5(5)
1.9pF(1R9)	W, B	0.3(3)	0.5(5)
2.0pF(2R0)	W, B	0.3(3)	0.5(5)
2.1pF(2R1)	W, B	0.3(3)	0.5(5)
2.2pF(2R2)	W, B	0.3(3)	0.5(5)
2.3pF(2R3)	W, B	0.3(3)	0.5(5)
2.4pF(2R4)	W, B	0.3(3)	0.5(5)
2.5pF(2R5)	W, B	0.3(3)	0.5(5)
2.6pF(2R6)	W, B	0.3(3)	0.5(5)
2.7pF(2R7)	W, B	0.3(3)	0.5(5)
2.8pF(2R8)	W, B	0.3(3)	0.5(5)
2.9pF(2R9)	W, B	0.3(3)	0.5(5)
3.0pF(3R0)	W, B	0.3(3)	0.5(5)
3.1pF(3R1)	W, B	0.3(3)	0.5(5)
3.2pF(3R2)	W, B	0.3(3)	0.5(5)
3.3pF(3R3)	W, B	0.3(3)	0.5(5)

 $\begin{tabular}{|c|c|c|c|c|c|} \hline \end{tabular}$ Continued from the preceding page.

Part Number		GJM03	GJM15		
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]		
тс		C0G (5C)	C0G (5C)		
Rated Volt.		25 (1E)	50 (1H)		
Capacitance, Capa	acitance Tolerand	e and T Dimension			
3.4pF(3R4)	W, B	0.3(3)	0.5(5)		
3.5pF(3R5)	W, B	0.3(3)	0.5(5)		
3.6pF(3R6)	W, B	0.3(3)	0.5(5)		
3.7pF(3R7)	W, B	0.3(3)	0.5(5)		
3.8pF(3R8)	W, B	0.3(3)	0.5(5)		
3.9pF(3R9)	W, B	0.3(3)	0.5(5)		
4.0pF(4R0)	W, B	0.3(3)	0.5(5)		
4.1pF(4R1)	W, B	0.3(3)	0.5(5)		
4.2pF(4R2)	W, B	0.3(3)	0.5(5)		
4.3pF(4R3)	W, B	0.3(3)	0.5(5)		
4.4pF(4R4)	W, B	0.3(3)	0.5(5)		
4.5pF(4R5)	W, B	0.3(3)	0.5(5)		
4.6pF(4R6)	W, B	0.3(3)	0.5(5)		
4.7pF(4R7)	W, B	0.3(3)	0.5(5)		
4.8pF(4R8)	W, B	0.3(3)	0.5(5)		
4.9pF(4R9)	W, B	0.3(3)	0.5(5)		
5.0pF(5R0)	W, B	0.3(3)	0.5(5)		
5.1pF(5R1) W	V, B, C	0.3(3)	0.5(5)		
5.2pF(5R2) W	V, B, C	0.3(3)	0.5(5)		
5.3pF(5R3) W	V, B, C	0.3(3)	0.5(5)		
5.4pF(5R4) W	V, B, C	0.3(3)	0.5(5)		
5.5pF(5R5) W	V, B, C	0.3(3)	0.5(5)		
5.6pF(5R6) W	V, B, C	0.3(3)	0.5(5)		
5.7pF(5R7) W	V, B, C	0.3(3)	0.5(5)		
5.8pF(5R8) W	V, B, C	0.3(3)	0.5(5)		
5.9pF(5R9) W	V, B, C	0.3(3)	0.5(5)		
6.0pF(6R0) W	V, B, C	0.3(3)	0.5(5)		
6.1pF(6R1) W	V, B, C	0.3(3)	0.5(5)		
	V, B, C	0.3(3)	0.5(5)		
6.3pF(6R3) W	V, B, C	0.3(3)	0.5(5)		
6.4pF(6R4) W	V, B, C	0.3(3)	0.5(5)		
6.5pF(6R5) W	V, B, C	0.3(3)	0.5(5)		
6.6pF(6R6) W	V, B, C	0.3(3)	0.5(5)		
6.7pF(6R7) W	V, B, C	0.3(3)	0.5(5)		
6.8pF(6R8) W	V, B, C	0.3(3)	0.5(5)		
6.9pF(6R9) W	V, B, C		0.5(5)		
7.0pF(7R0) W	V, B, C		0.5(5)		
7.1pF(7R1) W	V, B, C		0.5(5)		
7.2pF(7R2) W			0.5(5)		
7.3pF(7R3) W			0.5(5)		
7.4pF(7R4) W			0.5(5)		
7.5pF(7R5) W			0.5(5)		
7.6pF(7R6) W			0.5(5)		
7.7pF(7R7) W			0.5(5)		
7.8pF(7R8) W			0.5(5)		
7.9pF(7R9) W			0.5(5)		
8.0pF(8R0) W			0.5(5)		
8.1pF(8R1) W			0.5(5)		
8.2pF(8R2) W	V, B, C		0.5(5)		
8.3pF(8R3) W	V, B, C		0.5(5)		
			0.5(5)		
8.4pF(8R4) W	V, B, C		0.5(5)		

Continued from the preceding page.

Part Number		GJM03	GJM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	apacitanc	e Tolerance and T Dimension	
8.6pF(8R6)	W, B, C		0.5(5)
8.7pF(8R7)	W, B, C		0.5(5)
8.8pF(8R8)	W, B, C		0.5(5)
8.9pF(8R9)	W, B, C		0.5(5)
9.0pF(9R0)	W, B, C		0.5(5)
9.1pF(9R1)	W, B, C		0.5(5)
9.2pF(9R2)	W, B, C		0.5(5)
9.3pF(9R3)	W, B, C		0.5(5)
9.4pF(9R4)	W, B, C		0.5(5)
9.5pF(9R5)	W, B, C		0.5(5)
9.6pF(9R6)	W, B, C		0.5(5)
9.7pF(9R7)	W, B, C		0.5(5)
9.8pF(9R8)	W, B, C		0.5(5)
9.9pF(9R9)	W, B, C		0.5(5)

The part numbering code is shown in $\ (\).$

Dimensions are shown in mm and Rated Voltage in Vdc.

			Specifications				
No.	Ite	em	Temperature Compensating Type	Test Method			
1	Operating Temperature Range		−55 to +125°C	Reference Temperature: 25°C (2C, 3C, 4C: 20°C)			
2	Rated Voltage		See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p-p} or V ^{c-p} , whichever is larger, should be maintained within the rated voltage range.			
3	Appearar	nce	No defects or abnormalities	Visual inspection			
4	Dimensio	ns	Within the specified dimensions	Using calipers			
5	Dielectric	Strength	No defects or abnormalities	No failure should be observed when 300% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.			
6	Insulation (I.R.)	Resistance	10,000M Ω min. or 500 Ω · F min. (Whichever is smaller)	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°c and 75%RH max. and within 2 minutes of charging.			
7	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at 25°C at the frequency and voltage shown in the table.			
0	0		30pF max.: Q≥400+20C	Frequency 1±0.1MHz			
8	Q		C: Nominal Capacitance (pF)	Voltage 0.5 to 5Vrms			
		Capacitance Change	Within the specified tolerance (Table A)	The capacitance change should be measured after 5 min. at each specified temperature stage.			
		Temperature Coefficient	Within the specified tolerance (Table A)	Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference.			
9		Capacitance Drift	perature racteristics Capacitance	mperature haracteristics Capacitance With	Within ±0.2% or ±0.05pF (Whichever is larger.)	When cycling the temperature sequentially from step 1 throug 5, (5C: +25 to 125°C: other temp. coeffs.: +20 to 125°C) the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in step 1, 3 and 5 by the capacitance value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 -55±3 3 Reference Temp. ±2	
				4 125±3			
				5 Reference Temp. ±2			
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 1 using a eutectic solder. Then apply a 5N* force in parallel with the test jig for 10±1 sec. The soldering should be done eithe with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *2N (GJM0: Solder resist Baked electrode or copper foil Type GJM03 O.3 O.9 O.3 GJM15 O.4 I.5 O.5 (in mm)			





			Specifications				
0.	Ite	em	Temperature Compensating Type	Test Method			
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the			
	Vibration Resistance	Capacitance	Within the specified tolerance	same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motio having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz.			
		Q	Q≥400+20C C: Nominal Capacitance (pF)	The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).			
			No cracking or marking defects should occur.	Solder the capacitor to the test jig (glass epoxy boards) showr in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and shoul be conducted with care so that the soldering is uniform and fre			
12	Deflection		Type a b c GJM03 0.3 0.9 0.3 GJM15 0.4 1.5 0.5 Fig. 2	of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/sec. Pressurize R230 Pressurize Flexure: ≤1 Capacitance meter 45 (in mm)			
			Ç .	Fig. 3			
3		Solderability of 75% of the terminations are to be soldered evenly and continuously.		Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5% or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5℃			
			The measured and observed characteristics should satisfy the specifications in the following table.				
		Appearance	No marking defects				
4	Resistance to Soldering	Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu			
7	Heat	Q	Q≥400+20C C: Nominal Capacitance (pF)	solder solution at 270±5°C for 10±0.5 seconds. Let sit at room temperature for 24±2 hours.			
		I.R.	More than 10,000M Ω or 500 Ω · F (Whichever is smaller)				
		Dielectric Strength	No failure				
		The measured and observed characteristics should satisfy the specifications in the following table.		Fix the capacitor to the supporting jig in the same manner and			
		Appearance	No marking defects	under the same conditions as (10). Perform the five cycles			
_	Temperature	Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	according to the four heat treatments listed in the following table Let sit for 24±2 hours at room temperature, then measure.			
5	Cycle	Q	Q≥400+20C C: Nominal Capacitance (pF)	Step 1 2 3 4 Temp. (°C) Min. Operating Room Max. Operating Room			
		I.R.	More than $10,000M\Omega$ or $500\Omega \cdot F$ (Whichever is smaller)	Temp3 Temp. Temp. Temp.			
		Dielectric Strength	No failure	Time (min.) 30±3 2 to 3 30±3 2 to 3			
		<u> </u>	The measured and observed characteristics should satisfy the specifications in the following table.				
		Appearance	No marking defects	1			
	Humidity,	Capacitance	Within ±5% or ±0.5pF	Let the capacitor sit at 40±2℃ and 90 to 95% humidity for			
6	Steady State	Change Q	(Whichever is larger) 10pF and over, 30pF and below: Q≥275+ 5 C 10pF and below: Q≥200+10C	500±12 hours. Remove and let sit for 24±2 hours (temperature compensatin type) at room temperature, then measure.			
		I.R.	C: Nominal Capacitance (pF) More than $10,000M\Omega$ or $500\Omega \cdot F$ (Whichever is smaller)	_			



Continued from the preceding page.

NIo	Ita		Specifications	Toot Mathed				
No.	Ite	em	Temperature Compensating Type	Test Method				
			The measured and observed characteristics should satisfy the specifications in the following table.					
		Appearance	No marking defects					
17	Humidity	Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	Apply the rated voltage at 40±2℃ and 90 to 95% humidity for 500±12 hours.				
17	Load	Q	30pF and below: Q≥100+ ¹⁰ / ₃ C C: Nominal Capacitance (pF)	Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.				
		I.R.	More than $500 \text{M}\Omega$ or $25 \Omega \cdot \text{F}$ (Whichever is smaller)					
		Dielectric Strength	No failure					
		The measured and observed characteristics should satisfy the specifications in the following table.						
		Appearance	No marking defects					
	High	Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	Apply 200% of the rated voltage for 1000±12 hours at the maximum operating temperature ±3°C. Let sit for 24±2 hours				
18	Temperature Load	Q	10pF and over, 30pF and below: Q≥275+ ½ C 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	(temperature compensating type) at room temperature, then measure. The charge/discharge current is less than 50mA.				
		I.R.	More than 1,000M Ω or 50 Ω · F (Whichever is smaller)					
		Dielectric Strength	No failure					
19	ESR		0.5pF≦C≦1pF: 350mΩ below 1pF <c≦5pf: 300mω="" below<br="">5pF<c≦10pf: 250mω="" below<="" td=""><td>The ESR should be measured at room temperature, and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.</td></c≦10pf:></c≦5pf:>	The ESR should be measured at room temperature, and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.				
	Loix		10pF <c≦20pf: 400mω="" below<="" td=""><td>The ESR should be measured at room temperature, and frequency 500±50MHz with the equivalent of HP8753B.</td></c≦20pf:>	The ESR should be measured at room temperature, and frequency 500±50MHz with the equivalent of HP8753B.				

Table A

Char. Code	T	Capacitance Change from 25℃ Value (%)						
	Temp. Coeff. (ppm/℃) *1	− 55℃		-30℃		−10°C		
	(ppiii/ G) - 1	Max.	Min.	Max.	Min.	Max.	Min.	
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11	

^{*1:} Nominal values denote the temperature coefficient within a range of 25 to 125°C.

(2)

(2)									
	Naminal Value	Capacitance Change from 20℃ Value (%)							
Char.	Nominal Values (ppm/℃) *2	− 55℃		−25°C		− 10℃			
		Max.	Min.	Max.	Min.	Max.	Min.		
2C	0±60	0.82	-0.45	0.49	-0.27	0.33	-0.18		
3C	0±120	0.37	-0.90	0.82	-0.54	0.55	-0.36		
4C	0±250	0.56	-0.88	1.54	-1.13	1.02	-0.75		

^{*2:} Nominal values denote the temperature coefficient within a range of 20 to 125°C.



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High Frequency GQM Series

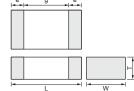
■ Features

- 1. HiQ and low ESR at VHF, UHF, Microwave
- 2. Feature improvement, low power consumption for mobile telecommunications (Base station, terminal, etc.)

■ Applications

High frequency circuit (Mobile telecommunications, etc.)





Part Number	Dimensions (mm)							
Part Number	L	W	Т	е	g min.			
GQM188	1.6 ±0.1	0.8 ±0.1	0.8 ±0.1	0.2 to 0.5	0.5			
GQM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7			

Part Number	GQM1	8	GQM21			
LxW	1.6x0.8		2.0x1.25			
тс	C0G (5C)		C00 (5C	G :)		
Rated Volt.	100 (2A)	50 (1H)	100 (2A)	50 (1H)		
Capacitance (Capac	citance part numbering code) an	d T (mm) Dimension (T Dimen	sion part numbering code)			
0.50pF(R50)	0.8(8)		0.85(9)			
0.75pF(R75)	0.8(8)		0.85(9)			
1.0pF(1R0)	0.8(8)		0.85(9)			
1.1pF(1R1)	0.8(8)		0.85(9)			
1.2pF(1R2)	0.8(8)		0.85(9)			
1.3pF(1R3)	0.8(8)		0.85(9)			
1.5pF(1R5)	0.8(8)		0.85(9)			
1.6pF(1R6)	0.8(8)		0.85(9)			
1.8pF(1R8)	0.8(8)		0.85(9)			
2.0pF(2R0)	0.8(8)		0.85(9)			
2.2pF(2R2)	0.8(8)		0.85(9)			
2.4pF(2R4)	0.8(8)		0.85(9)			
2.7pF(2R7)	0.8(8)		0.85(9)			
3.0pF(3R0)	0.8(8)		0.85(9)			
3.3pF(3R3)	0.8(8)		0.85(9)			
3.6pF(3R6)	0.8(8)		0.85(9)			
3.9pF(3R9)	0.8(8)		0.85(9)			
4.0pF(4R0)	0.8(8)		0.85(9)			
4.3pF(4R3)	0.8(8)		0.85(9)			
4.7pF(4R7)	0.8(8)		0.85(9)			
5.0pF(5R0)	0.8(8)		0.85(9)			
5.1pF(5R1)	0.8(8)		0.85(9)			
5.6pF(5R6)	0.8(8)		0.85(9)			
6.0pF(6R0)	0.8(8)		0.85(9)			
6.2pF(6R2)	0.8(8)		0.85(9)			
6.8pF(6R8)	0.8(8)		0.85(9)			
7.0pF(7R0)		0.8(8)	0.85(9)			
7.5pF(7R5)		0.8(8)	0.85(9)			
8.0pF(8R0)		0.8(8)	0.85(9)			
8.2pF(8R2)		0.8(8)	0.85(9)			
9.0pF(9R0)		0.8(8)	0.85(9)			
9.1pF(9R1)		0.8(8)	0.85(9)			
10pF(100)		0.8(8)	0.85(9)			



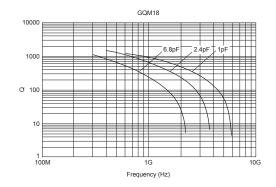
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Part Number	GQN	118	GQM21			
x W	1.6x	0.8	2.0x1.25			
с	C0G (5C)		C0G (5C)			
Rated Volt.	100 (2A)	50 (1H)	100 (2A)	50 (1H)		
Capacitance (Capacita	nce part numbering code)	and T (mm) Dimension (T Dimens	sion part numbering code)			
11pF(110)		0.8(8)	0.85 (9)			
12pF(120)		0.8(8)	0.85 (9)			
13pF(130)		0.8(8)	0.85(9)			
15pF(150)		0.8(8)	0.85(9)			
16pF(160)		0.8(8)	0.85(9)			
18pF(180)		0.8(8)	0.85(9)			
20pF(200)		0.8(8)		0.85(9)		
22pF(220)		0.8(8)		0.85(9)		
24pF(240)		0.8(8)		0.85(9)		
27pF(270)		0.8(8)		0.85(9)		
30pF(300)		0.8(8)		0.85(9)		
33pF(330)		0.8(8)		0.85(9)		
36pF(360)		0.8(8)		0.85(9)		
39pF(390)		0.8(8)		0.85(9)		
43pF(430)		0.8(8)		0.85(9)		
47pF(470)		0.8(8)		0.85(9)		
51pF(510)		0.8(8)		0.85(9)		
56pF(560)		0.8(8)		0.85(9)		
62pF(620)		0.8(8)		0.85(9)		
68pF(680)		0.8(8)		0.85(9)		
75pF(750)		0.8(8)		0.85(9)		
82pF(820)		0.8(8)		0.85(9)		
91pF(910)		0.8(8)		0.85(9)		
100pF(101)		0.8(8)		0.85(9)		

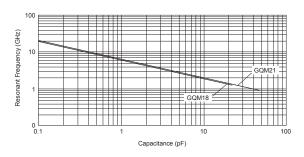
The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

■ Q - Frequency Characteristics



■ Resonant Frequency - Capacitance



No.	No. Item		Specifications		Test Method			
1	Operating Temperatu	ıre	-55 to 125℃	Reference Temperature: 25°C (2C, 3C, 4C: 20°C)				
2	2 Rated Voltage		See the previous page.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{o,p} , whichever is larger, should be maintained within the rated voltage range.				
3	Appearar	nce	No defects or abnormalities	Visual inspection				
4	Dimensio	n	Within the specified dimensions	Using calipers				
5	5 Dielectric Strength		No defects or abnormalities	No failure should be is applied between the provided the charge/	ne termination	ns for 1 to 5 se	conds,	
6	Insulation	Resistance	More than 10,000M Ω (Whichever is smaller)	The insulation resistation voltage not exceedin max. and within 2 mi	g the rated v	oltage at 25℃ a		
7	Capacita	nce	Within the specified tolerance	The capacitance/Q s			at the	
8	Q		30pF min.: Q≥1400 30pF max.: Q≥800+20C	Frequency Frequency	ge shown in t	1±0.1MHz		
			C: Nominal Capacitance (pF)	Voltage		0.5 to 541118		
		Capacitance Change	Within the specified tolerance (Table A)	The temperature coefficient is determined using the cameasured in step 3 as a reference. When cycling the temperature sequentially from step 1 the capacitance should be within the specified tolerance temperature coefficient and capacitance change as in			•	
		Temperature Coefficient	Within the specified tolerance (Table A)				erance for the	
9		Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger)	between the maximu	rift is calculated by dividing the difference num and minimum measured values in the the capacitance value in step 3. Temperature (°C) Reference Temp. ±2 -55±3 Reference Temp. ±2 125±3 Reference Temp. ±2		values in the p 3.	
	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor t	o the test jig (glass epoxy bo	ard) shown in	
10			Solder resist Baked electrode or copper foil	Fig. 1 using a eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *5N (GQM18 Type a b c GQM18 1.0 3.0 1.2 GQM21 1.2 4.0 1.65 (in mm) Fig. 1				
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the			ooard) in the	
11	Vibration Resistance	30pF mmr.: Q≥800+20C	30pF min.: Q≥1400	same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motio having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of the control of the should be applied.				
				3 mutually perpendicular directions (total of 6 hours).				

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\searrow	Continued fr	om the prec	eding page.	
No.	Ite	em	Specifications	Test Method
12	2 Deflection		No crack or marked defect should occur.	Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/sec. Pressurize Flexure: ≤1 Capacitance meter 45 Fig. 3
13	Solderabi Terminati		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5℃ or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5℃.
			The measured and observed characteristics should satisfy the specifications in the following table.	61 6.0 kg 6.0 cd 66.0 cf. 60.0 cf. 10 2 2 6.0 60.0 cf. 2 10 2 5 6.0 cf. 2
		Appearance	No marking defects	
		Capacitance Change	Within ±2.5% or ±0.25 pF (Whichever is larger)	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the
14	Resistance to Soldering Heat	Q	30pF min.: Q≥1400 30pF max.: Q≥800+20C	capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds. Let sit at room temperature for 24±2 hours.
			C: Nominal Capacitance (pF)	
		I.R.	More than 10,000M Ω	-
		Dielectric Strength	No failure The measured and observed characteristics should satisfy the	
			specifications in the following table.	
		Appearance	No marking defects	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10).
	Tomport	Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	Perform the five cycles according to the four heat treatments listed in the following table.
15	Temperature Cycle	Q	30pF min.: Q≥1400 30pF max.: Q≥800+20C	Let sit for 24±2 hours at room temperature, then measure. Step 1 2 3 4 Tomp (%) Min. Operating Room Max. Operating Room
			C: Nominal Capacitance (pF)	Temp. +0/-3 Temp. Temp. +3/-0 Temp.
		I.R. Dielectric	More than $10,000M\Omega$ No failure	Time (min.) 30±3 2 to 3 30±3 2 to 3
		Strength	The measured and observed characteristics should satisfy the specifications in the following table.	
		Appearance	No marking defects	-
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	
16	Humidity Steady State	Q	30pF min.: Q≥350 10pF and over, 30pF and below: Q≥275+5C/2 10pF max.: Q≥200+10C	Let the capacitor sit at 40±2°C and 90 to 95% humidity for 500±12 hours. Remove and let sit for 24±2 hours (temperature compensating type) at room temperature, then measure.
			C: Nominal Capacitance (pF)	
		I.R.	More than 1,000MΩ	_
		Dielectric Strength	No failure	Continued on the following page.

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No.	Ite	em	Specifications	Test Method		
			The measured and observed characteristics should satisfy the specifications in the following table.			
		Appearance	No marking defects			
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	Apply the rated voltage at 40±2°C and 90 to 95% humidity for		
17	Humidity Load	Q	30pF min.: Q≥200 30pF max.: Q≥100+10C/3	500±12 hours. Remove and let sit for 24±2 hours at room temperature then measure. The charge/discharge current is less than 50mA.		
			C: Nominal Capacitance (pF)			
		I.R.	More than $500 M\Omega$			
		Dielectric Strength	No failure			
			The measured and observed characteristics should satisfy the specifications in the following table.			
		Appearance	No marking defects			
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	Apply 200% of the rated voltage for 1000±12 hours at the		
18	High Temperature Load	Q	30pF min.: Q≥350 10pF and over, 30pF and below: Q≥275+5C/2 10pF max.: Q≥200+10C	maximum operating temperature ±3°C. Let sit for 24±2 hours (temperature compensating type) at room temperature, then measure. The charge/discharge current is less than 50mA.		
			C: Nominal Capacitance (pF)			
		I.R.	More than 1,000M Ω			
		Dielectric Strength	No failure			

Table A

(1)								
	Nominal Values (ppm/°c) *1	Capacitance Change from 25℃ (%)						
Char.		− 55℃		-30℃		-10°C		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11	

^{*1:} Nominal values denote the temperature coefficient within a range of 25 to 125°C.

Chip Monolithic Ceramic Capacitors

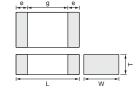


High Frequency Type ERB Series

■ Features (ERB Series)

- 1. Negligible inductance is achieved by its monolithic structure so the series can be used at frequencies above 1GHz.
- 2. Nickel barriered terminations of ERB series improve solderability and decrease solder leaching.
- 3. ERB18/21 series are designed for both flow and reflow soldering and ERB32 series are designed for reflow soldering.





	Part Number	Dimensions (mm)							
	Part Number	L	W	T max.	e min.	g min.			
	ERB188	1.6±0.1	0.8±0.1	0.9	0.2	0.5			
	ERB21B	2.0±0.3	1.25±0.3	1.35	0.25	0.7			
	ERB32Q	3.2±0.3	2.5±0.3	1.7	0.3	1.0			

■ Applications

High frequency and high-power circuits

Part Number	ERI	B18	ERB21				ER	B32				
LxW	1.6	8.0x		2.0x1.25			3.2x2.5					
тс		C0G (5C)		C0G (5C)		C0G (5C)						
Rated Volt.	250 (2E)	200 (2D)	250 (2E)	200 (2D)	100 (2A)	50 (1H)	500 (2H)	300 (YD)	250 (2E)	200 (2D)	100 (2A)	50 (1H)
Capacitance (Ca	pacitance	part numb	ering code)	and T (mm) Dimensio	n (T Dimer	sion part nu	umbering c	ode)			
0.50pF(R50)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
0.75pF(R75)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.0pF(1R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.1pF(1R1)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.2pF(1R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.3pF(1R3)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.5pF(1R5)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.6pF(1R6)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.8pF(1R8)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.0pF(2R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.2pF(2R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.4pF(2R4)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.7pF(2R7)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.0pF(3R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.3pF(3R3)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.6pF(3R6)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.9pF(3R9)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
4.0pF(4R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
4.3pF(4R3)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
4.7pF(4R7)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
5.0pF(5R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
5.1pF(5R1)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
5.6pF(5R6)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
6.0pF(6R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
6.2pF(6R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
6.8pF(6R8)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
7.0pF(7R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
7.5pF(7R5)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
8.0pF(8R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
8.2pF(8R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
9.0pF(9R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
9.1pF(9R1)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					

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Part Number	ER	B18		ER	B21				ER	B32		
LxW	1.6	x0.8	2.0x1.25			3.2x2.5						
тс	C	0G iC)		C	DG C)				C	0G (C)		
Rated Volt.	250 (2E)	200 (2D)	250 (2E)	200 (2D)	100 (2A)	50 (1H)	500 (2H)	300 (YD)	250 (2E)	200 (2D)	100 (2A)	50 (1H)
Capacitance (Ca	pacitance	part numb	ering code)	and T (mm	n) Dimensio	n (T Dimen	sion part n	umbering o	ode)			
10pF(100)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
11pF(110)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
12pF(120)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
13pF(130)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
15pF(150)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
16pF(160)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
18pF(180)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
20pF(200)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
22pF(220)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
24pF(240)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
27pF(270)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
30pF(300)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
33pF(330)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
36pF(360)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
39pF(390)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
43pF(430)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
47pF(470)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
51pF(510)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
56pF(560)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
62pF(620)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
68pF(680)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
75pF(750)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
82pF(820)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
91pF(910)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
100pF(101)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
110pF(111)					1.35(B)		1.7(Q)					
120pF(121)					1.35(B)		1.7(Q)					
130pF(131)					1.35(B)			1.7(Q)				
150pF(151)						1.35(B)		1.7(Q)				
160pF(161)						1.35(B)			1.7(Q)	1.7(Q)		
180pF(181)									1.7(Q)	1.7(Q)		
200pF(201)									1.7(Q)	1.7(Q)		
220pF(221)									1.7(Q)	1.7(Q)		
240pF(241)											1.7(Q)	
270pF(271)											1.7(Q)	
300pF(301)											1.7(Q)	
330pF(331)											1.7(Q)	
360pF(361)											1.7(Q)	
390pF(391)											1.7(Q)	
430pF(431)											1.7(Q)	
470pF(471)											1.7(Q)	
510pF(511)												1.7(Q)
560pF(561)												1.7(Q)
620pF(621)												1.7(Q)
680pF(681)												1.7(Q)
750pF(751)												1.7(Q)
820pF(821)												1.7(Q)
910pF(911)												1.7(Q)
1000pF(102)												1.7(Q)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

No.	Ite	em	Specifications		Test Metl	nod	
1	Operating Temperatu	ıre Range	−55 to +125°C	Reference Temperature: 25°C			
2	Rated Vo	Itage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V whichever is larger, should be maintained within the rated voltage range.			e, V ^{p-p} or V ^{o-p} ,
3	Appearar	nce	No defects or abnormalities	Visual inspection			
4	Dimensio	ns	Within the specified dimension	Using calipers			
5	Dielectric	Dielectric Strength No defects or abnormalities No defects or abnormalities		erminations for 1 to 5 seconds,			
6	Insulation (I.R.)	Resistance	1,000,000MΩ min. (C≦470pF) 100,000MΩ min. (C>470pF)	The insulation resistate voltage not exceeding humidity and within 2	g the rated vo	ltage at 25℃ a	
7	Capacita	nce	Within the specified tolerance The capacitance/Q should be measured at 25°C at		at the		
8	Q		C≦ 220pF : Q≧10,000 220pF <c≦ 470pf="" 5,000<br="" :="" q≧="">470pF<c≦1,000pf 3,000<br="" :="" q≧="">C: Nominal Capacitance (pF)</c≦1,000pf></c≦>	frequency and voltage shown in the table. Frequency 1±0.1MHz Voltage 1±0.2Vrms			
		Capacitance Change	Within the specified tolerance (Table A-6)	The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling			
		Temperature Coefficent	Within the specified tolerance (Table A-6)	the temperature sequentially from step 1 through 5, the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table.			nce for the
9	Capacitance Temperature			The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in step 1, 3 and 5 by the capacitance value in step 3.			
	Characteristics			Step	Tei	mperature (°C)	
		Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger)	1		25±2	
		Dill	(vviliditevel is larger)	2	-55±3		
				3		25±2	
				5		125±3	
			5		25±2		
			No removal of the terminations or other defects should occur.	Solder the capacitor in Fig. 1 using an eut Then apply 10N* forc The soldering should reflow method and standarding is uniform a	ectic solder. ce in parallel w be done eithe nould be cond	rith the test jig er with an iron ucted with car	for 10±1sec. or using the e so that the
10	Adhesive of Termin	0		Type	а	b	С
				ERB18	1.0	3.0	1.2
			Solder Resist	EDB21	1.2	4.0	1.65

Copper Foil

Fig.1

Baked Electrode or

ERB21

ERB32

1.2

2.2

Continued on the following page.

4.0

5.0

1.65

2.9

(in mm) *5N (ERB188)

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ш	Continued	from t	ha n	rocodina	naga

No.	lo. Item Specifications		Specifications	Test Method
		Appearance Capacitance	No defects or abnormalities Within the specified tolerance	Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10).
11	Vibration Resistance	Satisfies the initial value.		The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).
12	12 Deflection		No crack or marked defect should occur. 20 50 Pressurizing speed : 1.0mm/sec. Pressurize 04.5	Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 2a using an eutectic solder. Then apply a force in the direction shown in Fig. 3a. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.

Flexure : ≤1 Capacitance mete 45 Fig.3a Fig. 2a

Type b ERB18 1.0 3.0 1.2 ERB21 1.2 4.0 1.65 ERB32 2.2 5.0 2.9 (in mm)

Solderability of 95% of the terminations are to be soldered evenly and Termination continuously.

specifications in the following table.

Immerse the capacitor in a solution of isopropyl alcohol and rosin (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in an eutectic solder or Sn-3.0Ag-0.5Cu solder solution for 5±0.5 seconds at 245±5℃.

Resistance to Soldering Heat

Temperature

Humidity

15 Cycle

Item	Specifications		
Appearance	No marked defect		
Capacitance	Within ±2.5% or ±0.25pF		
Change	(Whichever is larger)		
	C≦ 220pF : Q≥10,000		
Q	220pF <c≤ 470pf="" 5,000<="" :="" q≥="" td=""></c≤>		
	470pF <c≦1,000pf 3,000<="" :="" q≥="" td=""></c≦1,000pf>		
Dielectric Strength	No failure		

The measured and observed characteristics should satisfy the

Preheat according to the conditions listed in the table below. Immerse the capacitor in an eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5℃ for 10±0.5 seconds. Let sit at room temperature for 24±2 hours.

Chip Size	Preheat Condition
2.0×1.25mm max.	1minute at 120 to 150℃
3.2×2.5mm	Each 1 minute at 100 to 120℃ and then 170 to 200℃

The measured and observed characteristics should satisfy the specifications in the following table.

Item	Specifications	
Appearance	No marked defect	
Capacitance	Within ±5% or ±0.5pF	
Change	(Whichever is larger)	
_	C≧30pF : Q≥350	
Q	10pF≦C<30pF : Q≥275+ 5 C	
	C<10pF : Q≥200+10C	
I.R.	1,000MΩ min.	
Dielectric Strength	No failure	

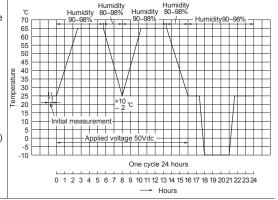
Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles $\,$ according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room temperature, then measure.

Step	1	2	3	4
Temp. (℃)	Min. Operating Temp. +0/-3	Room Temp.	Max. Operating Temp. +3/-0	Room Temp.
Time (min.)	30±3	5 max.	30±3	5 max.

The measured and observed characteristics should satisfy the specifications in the following table.

Item	Specifications			
Appearance	No marked defect			
Capacitance	Within ±5% or ±0.5pF			
Change	(Whichever is larger)			
	C≧30pF : Q≥350			
Q	10pF≦C<30pF : Q≥275+ 5 C			
	C<10pF : Q≥200+10C			
I.R.	1,000MΩ min.			

Apply the 24-hour heat (−10 to +65°C) and humidity (80 to 100%) treatment shown below, 10 consecutive times. Remove, let sit for 24±2 hours at room temperature, and measure.



C: Nominal Capacitance (pF)

C: Nominal Capacitance (pF)

C: Nominal Capacitance (pF)

Continued from the preceding page.

No.	Item	Specifications		Test Method
		The measured and observed characteristics should satisfy the specifications in the following table.		
		Item	Specifications	
		Appearance	No marked defect	
		Capacitance	Within ±3% or ±0.3pF	Apply 200% (500V only 150%) of the rated voltage for 1,000±12
17	High Temperature	Change	(Whichever is larger)	hours at 125±3℃.
17	Load	Q	C≧30pF : Q≧350 10pF≦C<30pF : Q≧275+ 5 C C<10pF : Q≧200+10C	Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.
		I.R.	1,000MΩ min.	
		Dielectric Strength	No failure	
		C: Nominal Capacitance (pF)		

Table A-6

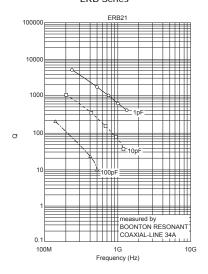
Char.	Nominal Values (ppm/°C) Note 1	Capacitance Change from 25℃ (%)					
		-55		-30		-10	
	(ppili/ c) Note i	Max.	Min.	Max.	Min.	Max.	Min.
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11

Note 1: Nominal values denote the temperature coefficient within a range of 25 to 125℃ (for 5C)

ERB Series Data

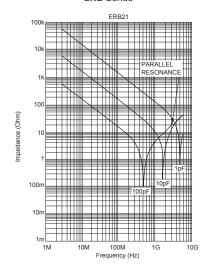
■ Q - Frequency Characteristics

ERB Series



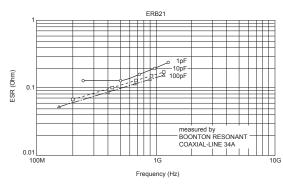
■ Impedance - Frequency Characteristics

ERB Series



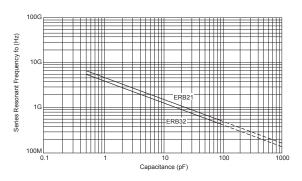
■ ESR - Frequency Characteristics

ERB Series

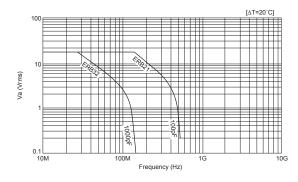


■ Resonant Frequency - Capacitance

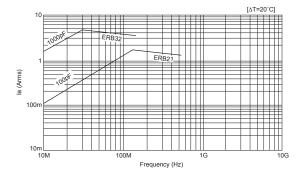
ERB Series



■ Allowable Voltage - Frequency



■ Allowable Current - Frequency



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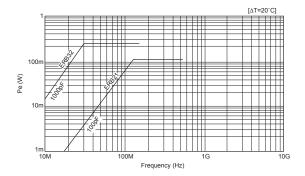
ERB Series Data

\(\) Continued from the preceding page.

■ Allowable Apparent Power - Frequency

[ΔT=20°C] Pa (VA) Frequency (Hz)

■ Allowable Effective Power - Frequency





■ Minimum Quantity Guide

Part Number		Dimensions (mm)		ø180mm Reel			ty (pcs.)			
				Т	Ø 180mm Reel		ø330mm Reel Paper Tape Embossed Tape		Bulk Case	Bulk Bag
5			- 00	•				·		Bulk : B
Packaging	g Code				D	L	J	K	С	Tray : T
	GRM02	0.4	0.2	0.2	20,000	-	-	-	-	1,000
	GRM03	0.6	0.3	0.3	15,000	-	50,000	-	-	1,000
	GRM15	1.0	0.5	0.25	10,000	-	50,000	-	-	1,000
				0.5	10,000	-	50,000	-	50,000	1,000
	GRM18	1.6	8.0	0.8	4,000	-	10,000	-	15,000 1)	1,000
	ODMO	2.0	4.05	0.6	4,000	-	10,000	-	10,000	1,000
	GRM21	2.0	1.25	0.85/1.0 1.25	4,000	3,000	10,000	10,000	5,000 2)	1,000
				0.6/0.85	4,000	3,000	10,000	10,000	5,000	1,000
	GRM31	3.2	1.6	1.15	-	3,000	-	10,000	-	1,000
	Ortino i	0.2	1.0	1.6	_	2,000	_	6,000	_	1,000
For General				0.85	_	4,000	_	10,000	_	1,000
Purpose				1.15	-	3,000	-	10,000	-	1,000
	GRM32	3.2	2.5	1.35	-	2,000	-	8,000	-	1,000
				1.6	-	2,000	-	6,000	-	1,000
				1.8/2.0 2.5	-	1,000	-	4,000	-	1,000
			3.2	1.15	-	1,000	-	5,000	-	1,000
	GRM43	4.5		1.35/1.6 1.8/2.0	-	1,000	-	4,000	-	1,000
	OKWI43	7.5		2.5	-	500	-	2,000	-	1,000
				2.8	-	500	-	1,500	-	500
	GRM55 5.7			1.15	-	1,000	-	5,000	-	1,000
		5.7	5.7 5.0	1.35/1.6 1.8/2.0	-	1,000	-	4,000	-	1,000
				2.5	-	500	-	2,000	-	500
	0.18400	-	0.0	3.2	-	300	-	1,500	-	500
ligh Power Type	GJM03 GJM15	0.6	0.3	0.3	15,000	-	50,000	-	50,000	1,000
	GQM18	1.0	0.8	0.8	10,000 4,000	-	50,000 10,000	-	-	1,000
	GQM21	2.0	1.25	0.85	4,000	_	10,000	-		1,000
ligh Frequency	ERB18	1.6	0.8	0.9 max.	4,000	_	10,000	_	_	1,000
g	ERB21	2.0	1.25	1.35 max.	-	3,000	-	10,000	_	1,000
	ERB32	3.2	2.5	1.7 max.	-	2,000	-	8,000	-	1,000
For Ultrasonic	GRM21	2.0	1.25	0.85	4,000	-	10,000	-	-	1,000
N.4:	GMA05	0.5	0.5	0.35	-	-	-	-	-	400 3)
Microchip	GMA08	0.8	0.8	0.5	-	-	-	-	-	400 3)
	GNM1M	1.37	1.0	0.6	4,000	-	10,000	-	-	1,000
Array	GNM21	2.0	1.25	0.6/0.85	4,000	-	10,000	-	-	1,000
rinay	GNM31	3.2	1.6	0.8	4,000	-	10,000	-	-	1,000
				1.0	-	3,000	-	10,000	-	1,000
	LLL15	0.5	1.0	0.3	10,000	-	50,000	- 40.555	-	1,000
	LLL18	8.0	1.6	0.5	-	4,000	-	10,000	-	1,000
	LLL21	1.25	2.0	0.5/0.6	-	4,000	-	10,000	-	1,000
				0.85	-	3,000 4,000	-	10,000 10,000	-	1,000
	LLL31	1.6	1.6 3.2	1.15	-	3,000	-	10,000	-	1,000
	LLA18	1.6	0.8	0.5		4,000	-	10,000	-	1,000
				0.5	-	4,000	-	10,000	-	1,000
Low ESL	LLA21	2.0	1.25	0.85	-	3,000	-	10,000	-	1,000
				0.5	-	4,000	-	10,000	-	1,000
	LLA31	3.2	3.2 1.6	0.85	-	3,000	-	10,000	-	1,000
				1.15	-	3,000	-	10,000	-	1,000
	LL MO4	2.0	1.05	0.5	-	4,000	•	10,000	-	1,000
	LLM21	2.0	1.25	0.85	-	3,000	-	10,000	-	1,000
	LLM31	3.2	1.6	0.5	-	4,000	-	10,000	-	1,000
	LLIVI3 I	3.2	0.1	1.15	-	3,000	-	10,000	-	1,000

muRata



¹⁾ $68,000 pF/0.1 \mu F$ of 50V R7 rated are not available by bulk case.

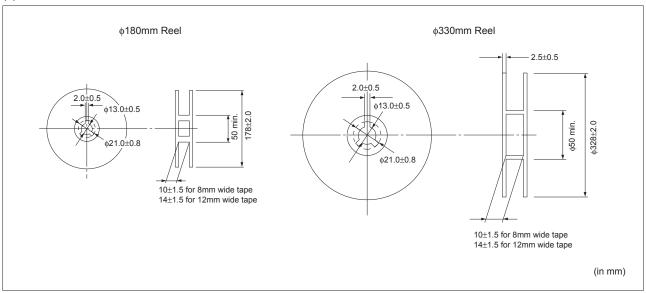
²⁾ Dimension tolerance $\pm 0.15 \text{mm}$ rated are not available by bulk case.

³⁾ Tray

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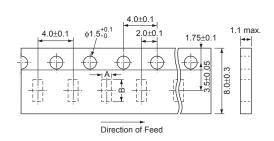
■ Tape Carrier Packaging

(1) Dimensions of Reel



(2) Dimensions of Paper Tape





Part Number	А	В
LLL15	0.65	1.15
GRM18 GQM18 ERB18	1.05±0.1	1.85±0.1
GNM1M	1.17±0.05	1.55±0.05
GRM21 (T≦0.85mm) GQM21 GNM21	1.55±0.15	2.3±0.15
GRM31 (T≦0.85mm) GNM31 (T≦0.8mm)	2.0±0.2	3.6±0.2
GRM32 (T≦0.85mm)	2.8±0.2	3.6±0.2

8mm width 2mm pitch Tape	
0.4 max. (GRM02) 0.5 max. (GRM03/GJM03) 0.8 max. (GRM5/GJM15)	
Direction of Feed	

Part Number	A*	B*
GRM02	0.25	0.45
GJM03 GRM03	0.37	0.67
GJM15 GRM15	0.65	1.15

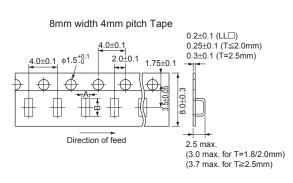
*Nominal Value

Continued on the following page. $\hfill \hfill \h$

(in mm)

Continued from the preceding page.

(3) Dimensions of Embossed Tape



Part Number	А	В
LLL18, LLA18	1.05±0.1	1.85±0.1
GRM21, ERB21 (T≥1.0mm) LLL21 LLA21, LLM21	1.45±0.2	2.25±0.2
GRM31 (T≥1.15mm) LLL31 LLA31, LLM31 GNM31 (T≥1.0mm)	1.9±0.2	3.5±0.2
GRM32, ERB32 (T≥1.0mm)	2.8±0.2	3.5±0.2

*Nominal Value

12mm width 8mm pitch Tape .75±0.1 Direction of feed 2.5 max for GRM43/55 (3.7 max. for T=2.5mm) (4.7 max. for T≥3.0mm)

Part Number	A*	B*
GRM43	3.6	4.9
GRM55	5.2	6.1

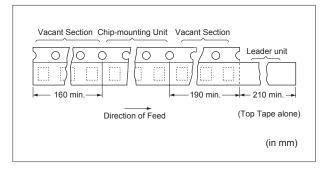
*Nominal Value

(in mm)

(4) Taping Method

- 1 Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
- 2 Part of the leader and part of the empty tape should be attached to the end of the tape as follows.
- 3 The top tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 4 Missing capacitors number within 0.1% of the number per reel or 1 pc, whichever is greater, and are not continuous.
- 5 The top tape and bottom tape should not protrude beyond the edges of the tape and should not cover sprocket holes.
- 6 Cumulative tolerance of sprocket holes, 10 pitches: ±0.3mm.
- 7 Peeling off force: 0.1 to 0.6N* in the direction shown below. *GRM02 GRM03 : 0.05 to 0.5N

GJM03

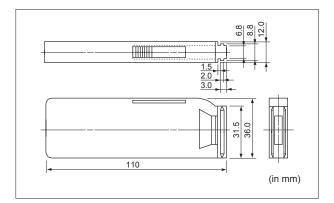






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■ Dimensions of Bulk Case Packaging The bulk case uses antistatic materials. Please contact Murata for details.





1 Caution

■ Storage and Operating Conditions

Chip monolithic ceramic capacitors (chips) can experience degradation of termination solderability when subjected to high temperature or humidity, or if exposed to sulfur or chlorine gases.

Storage environment must be at an ambient temperature of 5-40 degree C and an ambient humidity of 20-70%RH. Use chip within 6 months. If 6 months or more have elapsed, check solderability before use.

Use of Sn-Zn based solder will deteriorate reliability of MLCC.

Please contact Murata factory for the use of Sn-Zn based solder in advance.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.

■ Handling

1. Inspection

Thrusting force of the test probe can flex the PCB, resulting in cracked chips or open solder joints. Provide support pins on the back side of the PCB to prevent warping or flexing.

- 2. Board Separation (or depanalization)
- (1) Board flexing at the time of separation causes cracked chips or broken solder.
- (2) Severity of stresses imposed on the chip at the time of board break is in the order of: Pushback<Slitter<V Slot<Perforator.
- (3) Board separation must be performed using special jigs, not with hands.

3. Reel and bulk case

In the handling of reel and case, please be careful and do not drop it.

Do not use chips from a case which has been dropped.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND FUMING WHEN THE PRODUCT IS USED.

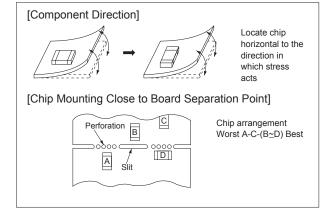




■ **(**Caution (Soldering and Mounting)

1. Mounting Position

Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.

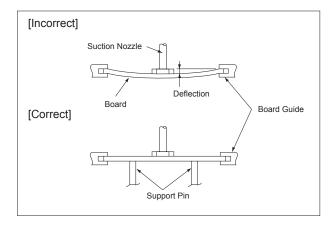


(Reference Data 2. Board bending strength for solder fillet height) (Reference Data 3. Temperature cycling for solder fillet height) (Reference Data 4. Board bending strength for board material)

2. Chip Placing

- An excessively low bottom dead point of the suction nozzle imposes great force on the chip during mounting. causing cracked chips. So adjust the suction nozzle's bottom dead point by correcting warp in the board. Normally, the suction nozzle's bottom dead point must be set on the upper surface of the board. Nozzle pressure for chip mounting must be a 1 to 3N static load.
- Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving smoothly. This imposes great force on the chip during mounting, causing cracked chips. And the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked and replaced periodically.

(Reference Data 5. Break strength)





⚠Caution

☐ Continued from the preceding page

3. Reflow Soldering

- When sudden heat is applied to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity inside components. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in table 1. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible.
- Solderability of Tin plating termination chip might be deteriorated when low temperature soldering profile where peak solder temperature is below the Tin melting point is used. Please confirm the solderability of Tin plating termination chip before use.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference (ΔT) between the component and solvent within the range shown in the table 1.

Table 1

Part Number	Temperature Differential
GRM02/03/15/18/21/31	
GJM03/15	
LLL15/18/21/31	ΔT≦190℃
ERB18/21	
GQM18/21	
GRM32/43/55	
LLA18/21/31	
LLM21/31	ΔΤ≦130℃
GNM	
ERB32	

Recommended Conditions

	Pb-Sn S	Lead Free Solder		
	Infrared Reflow	Vapor Reflow	Lead Free Solder	
Peak Temperature	230-250°C	230-240°C	240-260°C	
Atmosphere	Air	Air	Air or N2	

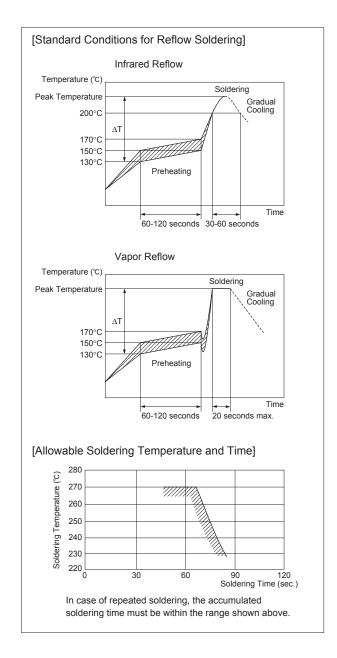
Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

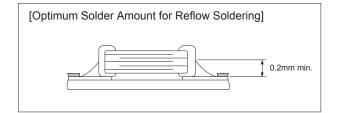
Optimum Solder Amount for Reflow Soldering

- Overly thick application of solder paste results in excessive fillet height solder.
 - This makes the chip more susceptible to mechanical and thermal stress on the board and may cause cracked chips.
- Too little solder paste results in a lack of adhesive strength on the outer electrode, which may result in chips breaking loose from the PCB.
- Make sure the solder has been applied smoothly to the end surface to a height of 0.2mm min.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.







☐ Continued from the preceding page

4. Leaded Component Insertion

If the PCB is flexed when leaded components (such as transformers and ICs) are being mounted, chips may crack and solder joints may break.

Before mounting leaded components, support the PCB using backup pins or special jigs to prevent warping.

5. Flow Soldering

- When sudden heat is applied to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity inside components. And an excessively long soldering time or high soldering temperature results in leaching of the outer electrodes, causing poor adhesion or a reduction in capacitance value due to loss of contact between electrodes and end termination.
- In order to prevent mechanical damage in the components, preheating shoud be required for the both components and the PCB board. Preheating conditions are shown in table 2. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible.

When components are immersed in solvent after mounting, be sure to maintain the temperature difference between the component and solvent within the range shown in Table 2.

Do not apply flow soldering to chips not listed in Table 2.

Table 2

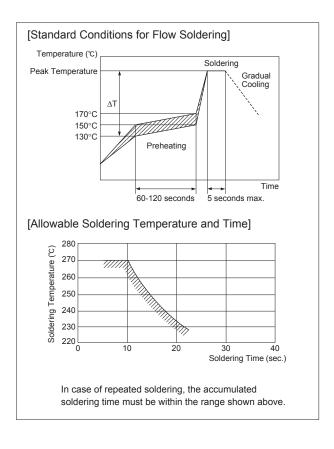
Part Number	Temperature Differential	
GRM18/21/31		
LLL21/31	ΛT≤150℃	
ERB18/21	Δ1≥150 C	
GQM18/21		

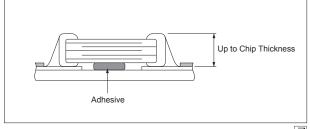
Recommended Conditions

	Pb-Sn Solder	Lead Free Solder
Peak Temperature	240-250°C	250-260°C
Atmosphere	Air	N ₂

Ph-Sn Solder: Sn-37Ph Lead Free Solder: Sn-3.0Ag-0.5Cu

 Optimum Solder Amount for Flow Soldering The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions.











1 Caution

- Continued from the preceding page.
- 6. Correction with a Soldering Iron
- (1) For Chip Type Capacitors
- When sudden heat is applied to the components by soldering iron, the mechanical strength of the components should go down because remarkable temperature change causes deformity inside components. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in table 3. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible. After soldering, it is not allowed to cool it down rapidly.

Table 3

Table 5			
Part Number	Temperature Differential	Peak Temperature	Atmosphere
GRM15/18/21/31 GJM15		300°C max.	
LLL15/18/21/31 GQM18/21 ERB18/21	ΔΤ≦190℃	3 seconds max. / termination	Air
GRM32/43/55 GNM LLA18/21/31 LLM21/31 ERB32	ΔT≦130°C	270°C max. 3 seconds max. / termination	Air

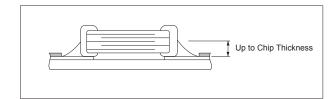
*Applicable for both Pb-Sn and Lead Free Solder.

Pb-Sn Solder: Sn-37Pb

Lead Free Solder: Sn-3.0Aq-0.5Cu

 Optimum Solder Amount when Corrections Are Made Using a Soldering Iron

The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions. Soldering iron ø3mm or smaller should be required. And it is necessary to keep a distance between the soldering iron and the components without direct touch. Thread solder with ø0.5mm or smaller is required for soldering.



7. Washing

Excessive output of ultrasonic oscillation during cleaning causes PCBs to resonate, resulting in cracked chips or broken solder. Take note not to vibrate PCBs.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND FUMING WHEN THE PRODUCT IS USED.



Rating

Die Bonding/Wire Bonding (GMA Series)

- 1. Die Bonding of Capacitors
- •Use the following materials Brazing alloy: Au-Sn (80/20) 300 to 320 degree C in N2 atmosphere
- Mounting
- (1) Control the temperature of the substrate so that it matches the temperature of the brazing
- (2) Place brazing alloy on substrate and place the capacitor on the alloy. Hold the capacitor and gently apply the load. Be sure to complete the operation in 1 minute.

- 2. Wire Bonding
- Wire

Gold wire:

20 micro m (0.0008 inch), 25 micro m (0.001 inch) diameter

- Bonding
- (1) Thermocompression, ultrasonic ball bonding.
- (2) Required stage temperature: 200 to 250 degree C
- (3) Required wedge or capillary weight: 0.5N to 2N.
- (4) Bond the capacitor and base substrate or other devices with gold wire.



■ Notice (Soldering and Mounting)

1. PCB Design

(1) Notice for Pattern Forms

Unlike leaded components, chip components are susceptible to flexing stresses since they are mounted directly on the substrate.

They are also more sensitive to mechanical and thermal stresses than leaded components.

Excess solder fillet height can multiply these stresses and cause chip cracking. When designing substrates, take land patterns and dimensions into consideration to eliminate the possibility of excess solder fillet height.

Pattern Forms

	Placing Close to Chassis	Placing of Chip Components and Leaded Components	Placing of Leaded Components after Chip Component	Lateral Mounting
Prohibited	Chassis Solder (ground) Electrode Pattern	Lead Wire	Soldering Iron Lead Wire	
Correct	Solder Resist	Solder Resist	Solder Resist	Solder Resist





- Ontinued from the preceding page.
- (2) Land Dimensions

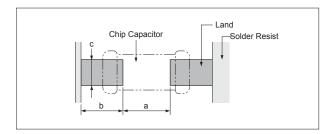


Table 1 Flow Soldering Method

Dimensions Part Number	Dimensions (L×W)	а	b	С	
GRM18	4.0240.0	0.0.4.0	0.0.00	0.0.00	
GQM18	1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8	
GRM21	2.024.05	40.40	0.0.4.0	0.0.44	
GQM21	2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1	
GRM31	3.2×1.6	2.2-2.6	1.0-1.1	1.0-1.4	
LLL21	1.25×2.0	0.4-0.7	0.5-0.7	1.4-1.8	
LLL31	1.6×3.2	0.6-1.0	0.8-0.9	2.6-2.8	
ERB18	1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8	
ERB21	2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1	

(in mm)

Table 2 Reflow Soldering Method

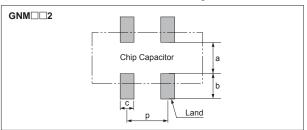
Dimensions Part Number	Dimensions (LXW)	a	b	С	
GRM02	0.4×0.2	0.16-0.2	0.12-0.18	0.2-0.23	
GRM03 GJM03	0.6×0.3	0.2-0.3	0.2-0.35	0.2-0.4	
GRM15 GJM15	1.0×0.5	0.3-0.5	0.35-0.45	0.4-0.6	
GRM18 GQM18	1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	
GRM21 GQM21	2.0×1.25	1.0-1.2	0.6-0.7	0.8-1.1	
GRM31	3.2×1.6	2.2-2.4	0.8-0.9	1.0-1.4	
GRM32	3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	
GRM43	4.5×3.2	3.0-3.5	1.2-1.4	2.3-3.0	
GRM55	5.7×5.0	4.0-4.6	1.4-1.6	3.5-4.8	
LLL15	0.5×1.0	0.15-0.2	0.2-0.3	0.7-1.0	
LLL18	0.8×1.6	0.2-0.4	0.3-0.4	1.0-1.4	
LLL21	1.25×2.0	0.4-0.6	0.3-0.5	1.4-1.8	
LLL31	1.6×3.2	0.6-0.8	0.6-0.7	2.6-2.8	
ERB18	1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	
ERB21	2.0×1.25	1.0-1.2	0.6-0.7	0.8-1.1	
ERB32	3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	

(in mm)



Continued from the preceding page.

GNM, LLA Series for Reflow Soldering Method



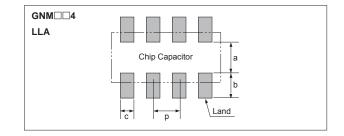


Table 3 GNM, LLA Series for Reflow Soldering Land Dimensions

Part Number	Dimensions (mm)							
Part Number	L	W	a	b	С	р		
GNM1M2	1.37	1.0	0.4 to 0.5	0.35 to 0.45	0.3 to 0.35	0.64		
GNM212	2.0	1.25	0.6 to 0.7	0.5 to 0.7	0.4 to 0.5	1.0		
GNM214	2.0	1.25	0.6 to 0.7	0.5 to 0.7	0.25 to 0.35	0.5		
GNM314	3.2	1.6	0.8 to 1.0	0.7 to 0.9	0.3 to 0.4	0.8		
LLA18	1.6	0.8	0.3 to 0.4	0.25 to 0.4	0.2 to 0.28	0.4		
LLA21	2.0	1.25	0.7 to 0.8	0.4 to 0.6	0.2 to 0.3	0.5		
LLA31	3.2	1.6	0.8 to 1.0	0.7 to 0.9	0.3 to 0.4	0.8		

LLM Series for Reflow Soldering Method

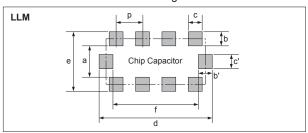


Table 4 LLM Series for Reflow Soldering Land Dimensions

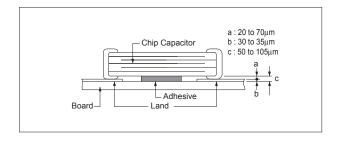
Part Number	Dimensions (mm)							
	а	b, b'	c, c'	d	е	f	р	
LLM21	0.6 to 0.8	(0.3 to 0.5)	0.3	2.0 to 2.6	1.3 to 1.8	1.4 to 1.6	0.5	
LLM31	1.0	(0.3 to 0.5)	0.4	3.2 to 3.6	1.6 to 2.0	2.6	0.8	

b=(c-e)/2, b'=(d-f)/2

2. Adhesive Application

- Thin or insufficient adhesive causes chips to loosen or become disconnected when flow soldered. The amount of adhesive must be more than dimension c shown in the drawing at right to obtain enough bonding strength. The chip's electrode thickness and land thickness must be taken into consideration.
- Low viscosity adhesive causes chips to slip after mounting. Adhesive must have a viscosity of 5000Pa ·s (500ps) min. (at 25°C)
- Adhesive Coverage*

Traincoive ouverage	
Part Number	Adhesive Coverage*
GRM18, GQM18	0.05mg min.
GRM21, LLL21, GQM21	0.1mg min.
GRM31, LLL31	0.15mg min.



*Nominal Value





Continued from the preceding page.

3. Adhesive Curing

Insufficient curing of the adhesive causes chips to disconnect during flow soldering and causes deteriorated insulation resistance between outer electrodes due to moisture absorption.

Control curing temperature and time in order to prevent insufficient hardening.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.

4. Flux Application

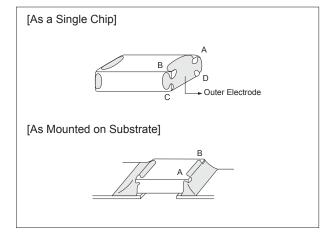
- An excessive amount of flux generates a large quantity of flux gas, causing deteriorated solderability. So apply flux thinly and evenly throughout. (A foaming system is generally used for flow soldering).
- Flux containing too high a percentage of halide may cause corrosion of the outer electrodes unless sufficiently

cleaned. Use flux with a halide content of 0.2wt% max. But do not use strong acidic flux.

Wash thoroughly because water soluble flux causes deteriorated insulation resistance between outer electrodes unless sufficiently cleaned.

5. Flow Soldering

 Set temperature and time to ensure that leaching of the outer electrode does not exceed 25% of the chip end area as a single chip (full length of the edge A-B-C-D shown below) and 25% of the length A-B shown below as mounted on substrate.



(Reference Data 6. Thermal shock) (Reference Data 7. Solder heat resistance)

■ Others

1. Resin Coating

When selecting resin materials, select those with low contraction.

2. Circuit Design

These capacitors in this catalog are not safety recognized products

3. Remarks

The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions. Select optimum conditions for operation as they determine the reliability of the product after assembly. The data herein are given in typical values, not guaranteed ratings.



1. Solderability

(1) Test Method

Subject the chip capacitor to the following conditions. Then apply flux (an ethanol solution of 25% rosin) to the chip and dip it in 230°C eutectic solder for 2 seconds. Conditions:

Expose prepared at room temperature (for 6 months and 12 months, respectively)

Prepared at high temperature (for 100 hours at 85℃) Prepared left at high humidity (for 100 hours under 90%RH to 95%RH at 40°C)

(2) Test Samples

GRM21: Products for flow/reflow soldering.

(3) Acceptance Criteria

With a 60-power optical microscope, measure the surface area of the outer electrode that is covered with solder.

(4) Results

Refer to Table 1.

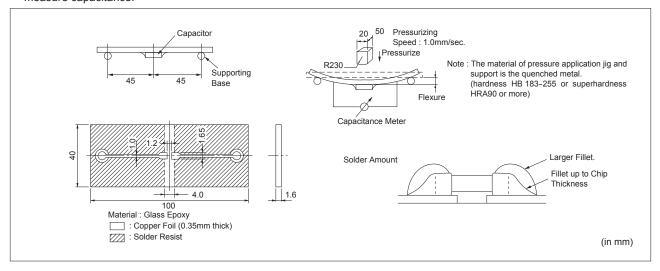
Table 1

Sample	Initial State	Prepared at Room Temperature		Prepared at High Temperature for	Prepared at High Humidity for 100 Hours at 90 to	
Sample	Illitial State	6 months	12 months	100 Hours at 85℃	95% RH and 40°C	
GRM21 for flow/reflow soldering	95 to 100%	95 to 100%	95%	90 to 95%	95%	

2. Board Bending Strength for Solder Fillet Height

(1) Test Method

Solder the chip capacitor to the test PCB with the amount of solder paste necessary to achieve the fillet heights. Then bend the PCB using the method illustrated and measure capacitance.



(2) Test Samples

GRM21: 5C/R7/F5 Characteristics T=0.6mm

(3) Acceptance Criteria

Products should be determined to be defective if the change in capacitance has exceeded the values specified in Table 2.

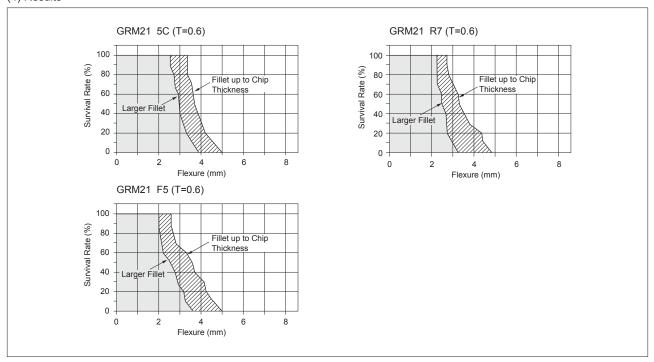
Table 2

Table 2				
Characteristics Change in Capacitance				
5C	Within ±5% or ±0.5pF, whichever is greater			
R7	Within ±12.5%			
F5	Within ±20%			



Continued from the preceding page.

(4) Results



3. Temperature Cycling for Solder Fillet Height

(1) Test Method

Solder the chips to the substrate of various test fixtures using sufficient amounts of solder to achieve the required fillet height. Then subject the fixtures to the cycle illustrated below 200 times.

① Solder Amount

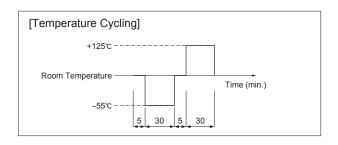
Alumina substrates are typically designed for reflow soldering.

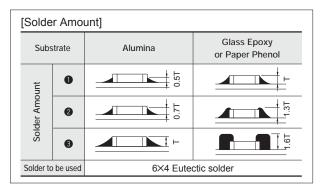
Glass epoxy or paper phenol substrates are typically used for flow soldering.

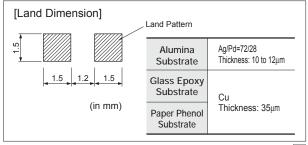
② Material

Alumina (Thickness: 0.64mm) Glass epoxy (Thickness: 1.64mm) Paper phenol (Thickness: 1.64mm)

3 Land Dimension







Continued from the preceding page.

(2) Test Samples

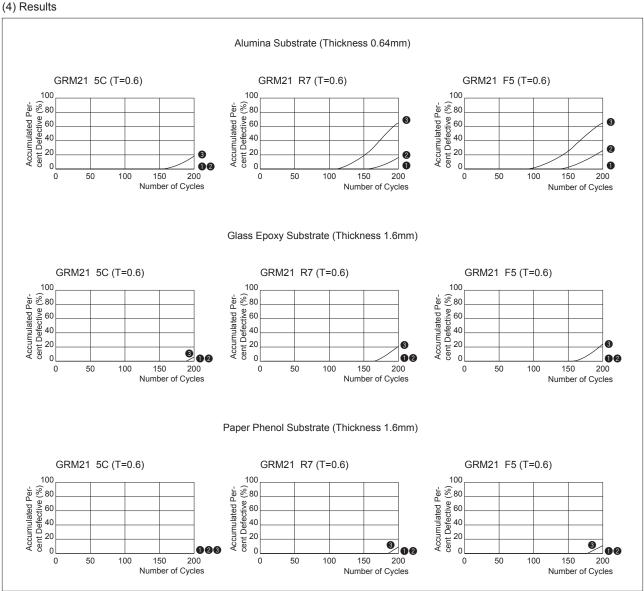
GRM21 5C/R7/F5 Characteristics T=0.6mm

(3) Acceptance Criteria

Products are determined to be defective if the change in capacitance has exceeded the values specified in Table 3.

Table 3

Characteristics	Change in Capacitance
5C	Within ±2.5% or ±0.25pF, whichever is greater
R7	Within ±7.5%
F5	Within ±20%



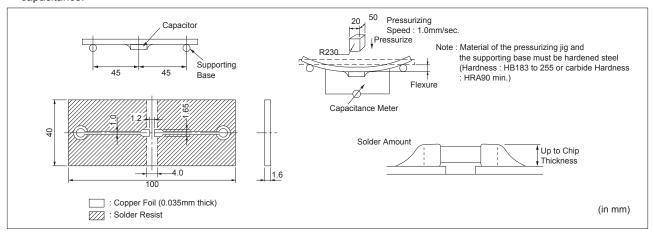


Continued from the preceding page.

4. Board Bending Strength for Board Material

(1) Test Method

Solder the chip to the test board. Then bend the board using the method illustrated below, to measure capacitance.



(2) Test Samples GRM21 5C/R7/F5 Characteristics T=0.6mm typical

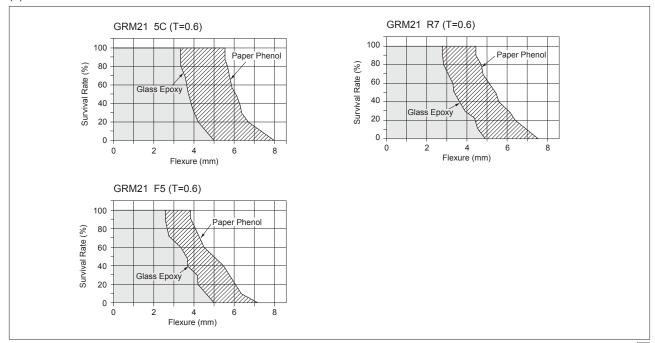
(3) Acceptance Criteria

Products should be determined to be defective if the change in capacitance has exceeded the values specified in Table 4.

Table 4

Characteristics	Change in Capacitance
5C	Within ±5% or ±0.5pF, whichever is greater
R7	Within ±12.5%
F5	Within ±20%

(4) Results



Continued from the preceding page

5. Break Strength

(1) Test Method

Place the chip on a steel plate as illustrated on the right. Increase load applied to a point near the center of the test sample.

(2) Test Samples

GRM21 5C/R7/F5 Characteristics GRM31 5C/R7/F5 Characteristics

(3) Acceptance Criteria

Define the load that has caused the chip to break or crack, as the bending force.

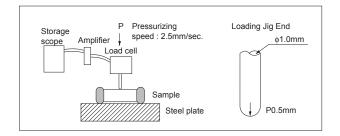
(4) Explanation

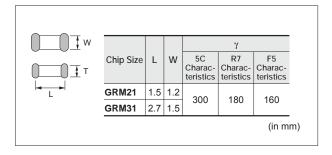
Break strength, P, is proportionate to the square of the thickness of the ceramic element and is expressed as a curve of secondary degree.

The formula is:

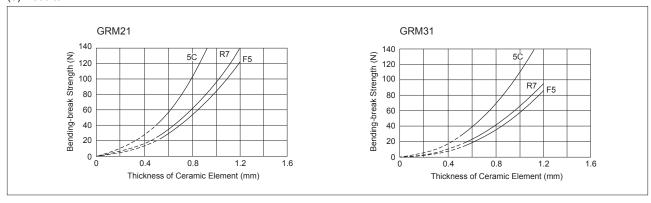
$$P = \frac{2\gamma WT^2}{3I} \quad (N)$$

W: Width of ceramic element (mm) T: Thickness of element (mm) L: Distance between fulcrums (mm) γ: Bending stress (N/mm²)





(5) Results



6. Thermal Shock

(1) Test method

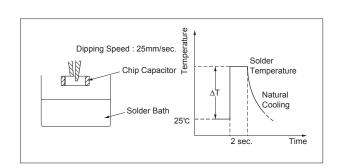
After applying flux (an ethanol solution of 25% rosin), dip the chip in a solder bath (6×4 eutectic solder) in accordance with the following conditions:

(2) Test samples

GRM21 5C/R7/F5 Characteristics T=0.6mm typical

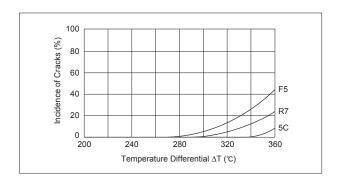
(3) Acceptance criteria

Visually inspect the test sample with a 60-power optical microscope. Chips exhibiting breaks or cracks should be determined to be defective.





- Continued from the preceding page.
- (4) Results



7. Solder Heat Resistance

(1) Test Method

① Reflow soldering:

Apply about 300 μm of solder paste over the alumina substrate. After reflow soldering, remove the chip and check for leaching that may have occurred on the outer electrode.

2 Flow soldering:

After dipping the test sample with a pair of tweezers in wave solder (eutectic solder), check for leaching that may have occurred on the outer electrode.

(2) Test samples

GRM21: For flow/reflow soldering T=0.6mm

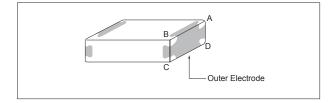
(3) Acceptance criteria

The starting time of leaching should be defined as the time when the outer electrode has lost 25% of the total edge length of A-B-C-D as illustrated:

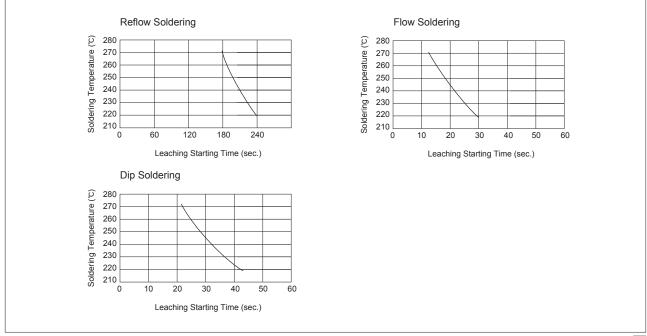
3 Dip soldering:

After dipping the test sample with a pair of tweezers in static solder (eutectic solder), check for leaching that may have occurred on the outer electrode.

4 Flux to be used: An ethanol solution of 25% rosin.



(4) Results

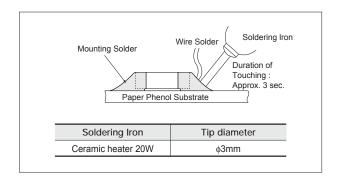


- Continued from the preceding page.
- 8. Thermal Shock when Making Corrections with a Soldering Iron
- (1) Test Method

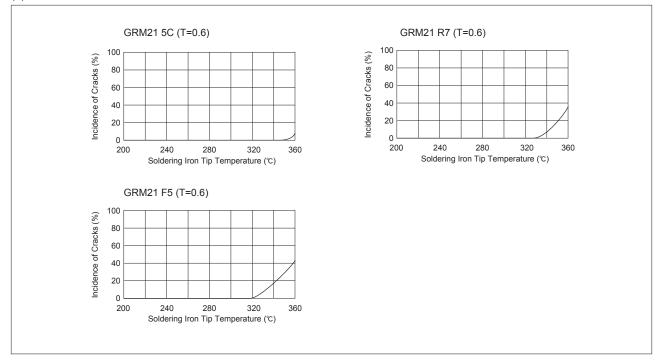
Apply a soldering iron meeting the conditions below to the soldered joint of a chip that has been soldered to a paper phenol board, while supplying wire solder. (Note: the soldering iron tip should not directly touch the ceramic element of the chip.)

(2) Test Samples GRM21 5C/R7/F5 Characteristics T=0.6mm

(3) Acceptance Criteria for Defects Observe the appearance of the test sample with a 60-power optical microscope. Those units displaying any breaks or cracks are determined to be defective.



(4) Results





Chip Monolithic Ceramic Capacitors



Medium Voltage Low Dissipation Factor

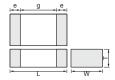
■ Features

- 1. Low-loss and suitable for high frequency circuits
- 2. Murata's original internal electrode structure realizes high flash-over voltage.
- A new monolithic structure for small, surfacemountable devices capable of operating at high voltage levels
- 4. Sn-plated external electrodes realize good solderability.
- 5. Use the GRM21/31 type with flow or reflow soldering, and other types with reflow soldering only.

Applications

Ideal for use on high frequency pulse circuits such as snubber circuits for switching power supplies, DC-DC converters, ballasts (inverter fluorescent lamps), etc.





Part Number	Dimensions (mm)						
Part Number	L W T		e min.	g min.			
GRM21A	2.0 ±0.2	1.25 ±0.2	1.0 +0 0.3		0.7		
GRM31A	3.2 ±0.2	1.6 +0.2	,				
GRM31B	3.2 ±0.2	1.6 ±0.2	1.25 + 0, -0.3		1.5*		
GRM32A	3.2 ±0.2	2.5 ±0.2	1.0 +0,-0.3	0.3	1.5		
GRM32B	3.2 ±0.2	2.5 ±0.2	1.25 + 0, -0.3				
GRM42A	4.5 ±0.3	2.0 ±0.2	1.0 +0,-0.3		2.9		

^{*} GRM31A7U3D, GRM32A7U3D, GRM32B7U3D: 1.8mm min.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM21A7U2E101JW31D	DC250	U2J (EIA)	100 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E151JW31D	DC250	U2J (EIA)	150 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E221JW31D	DC250	U2J (EIA)	220 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E331JW31D	DC250	U2J (EIA)	330 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E471JW31D	DC250	U2J (EIA)	470 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E681JW31D	DC250	U2J (EIA)	680 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E102JW31D	DC250	U2J (EIA)	1000 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E152JW31D	DC250	U2J (EIA)	1500 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E222JW31D	DC250	U2J (EIA)	2200 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM31A7U2E332JW31D	DC250	U2J (EIA)	3300 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2E472JW31D	DC250	U2J (EIA)	4700 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31B7U2E682JW31L	DC250	U2J (EIA)	6800 ±5%	3.2	1.6	1.25	1.5	0.3 min.
GRM31B7U2E103JW31L	DC250	U2J (EIA)	10000 ±5%	3.2	1.6	1.25	1.5	0.3 min.
GRM31A7U2J100JW31D	DC630	U2J (EIA)	10 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J150JW31D	DC630	U2J (EIA)	15 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J220JW31D	DC630	U2J (EIA)	22 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J330JW31D	DC630	U2J (EIA)	33 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J470JW31D	DC630	U2J (EIA)	47 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J680JW31D	DC630	U2J (EIA)	68 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J101JW31D	DC630	U2J (EIA)	100 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J151JW31D	DC630	U2J (EIA)	150 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J221JW31D	DC630	U2J (EIA)	220 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J331JW31D	DC630	U2J (EIA)	330 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J471JW31D	DC630	U2J (EIA)	470 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J681JW31D	DC630	U2J (EIA)	680 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J102JW31D	DC630	U2J (EIA)	1000 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM32A7U2J152JW31D	DC630	U2J (EIA)	1500 ±5%	3.2	2.5	1.0	1.5	0.3 min.
GRM32A7U2J222JW31D	DC630	U2J (EIA)	2200 ±5%	3.2	2.5	1.0	1.5	0.3 min.
GRM31A7U3A100JW31D	DC1000	U2J (EIA)	10 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A150JW31D	DC1000	U2J (EIA)	15 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A220JW31D	DC1000	U2J (EIA)	22 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A330JW31D	DC1000	U2J (EIA)	33 ±5%	3.2	1.6	1.0	1.5	0.3 min.

Continued from the preceding page.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM31A7U3A470JW31D	DC1000	U2J (EIA)	47 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A680JW31D	DC1000	U2J (EIA)	68 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A101JW31D	DC1000	U2J (EIA)	100 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A151JW31D	DC1000	U2J (EIA)	150 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A221JW31D	DC1000	U2J (EIA)	220 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A331JW31D	DC1000	U2J (EIA)	330 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31B7U3A471JW31L	DC1000	U2J (EIA)	470 ±5%	3.2	1.6	1.25	1.5	0.3 min.
GRM31A7U3D100JW31D	DC2000	U2J (EIA)	10 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D120JW31D	DC2000	U2J (EIA)	12 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D150JW31D	DC2000	U2J (EIA)	15 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D180JW31D	DC2000	U2J (EIA)	18 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D220JW31D	DC2000	U2J (EIA)	22 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D270JW31D	DC2000	U2J (EIA)	27 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D330JW31D	DC2000	U2J (EIA)	33 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D390JW31D	DC2000	U2J (EIA)	39 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D470JW31D	DC2000	U2J (EIA)	47 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D560JW31D	DC2000	U2J (EIA)	56 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D680JW31D	DC2000	U2J (EIA)	68 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM32A7U3D820JW31D	DC2000	U2J (EIA)	82 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32A7U3D101JW31D	DC2000	U2J (EIA)	100 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32A7U3D121JW31D	DC2000	U2J (EIA)	120 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32A7U3D151JW31D	DC2000	U2J (EIA)	150 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32B7U3D181JW31L	DC2000	U2J (EIA)	180 ±5%	3.2	2.5	1.25	1.8	0.3 min.
GRM32B7U3D221JW31L	DC2000	U2J (EIA)	220 ±5%	3.2	2.5	1.25	1.8	0.3 min.
GRM42A7U3F270JW31L	DC3150	U2J (EIA)	27 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F330JW31L	DC3150	U2J (EIA)	33 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F390JW31L	DC3150	U2J (EIA)	39 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F470JW31L	DC3150	U2J (EIA)	47 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F560JW31L	DC3150	U2J (EIA)	56 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F680JW31L	DC3150	U2J (EIA)	68 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F820JW31L	DC3150	U2J (EIA)	82 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F101JW31L	DC3150	U2J (EIA)	100 ±5%	4.5	2.0	1.0	2.9	0.3 min.

No.	Ite	em	Specifications	Test Method				
1	Operating Temperatu	ure Range	-55 to +125℃	-				
2	Appearar	nce	No defects or abnormalities	Visual inspection				
3	Dimensio	ns	Within the specified dimension	Using calipers				
4	Dielectric	Strength	No defects or abnormalities	No failure should be observed when voltage in Table is applied between the terminations for 1 to 5 sec., provided the charge/ discharge current is less than 50mA. Rated voltage Test voltage DC250V 200% of the rated voltage DC630V 150% of the rated voltage DC1kV, DC2kV 120% of the rated voltage DC3.15kV DC4095V				
5	Insulation F (I.R.)	Resistance	More than $10,000 M\Omega$	The insulation resistance should be measured with DC500±50V (DC250±25V in case of rated voltage: DC250V) and within 60±5 sec. of charging.				
6	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at the frequency and				
7	7 Q		1,000 min.	voltage shown as follows. Capacitance Frequency Voltage C<1,000pF				
8	Capacitance 8 Temperature Characteristics		Temp. Coefficient -750±120 ppm/℃ (Temp. Range: +25 to +125℃) -750+120, -347 ppm/℃ (Temp. Range: -55 to +25℃)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2				
9	9 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Glass Epoxy Board Fig. 1				
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).				
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion				
10	Vibration Resistance	in .		having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board				

\Box	Continued fr	om the prec	eding page.					
No.	Ite	em	Specifications	Test Method				
11	Deflection	n	No cracking or marking defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s Pressurize 20 Flexure=1 Capacitance meter 45 (in mm) Fig. 3				
12	Solderabi Terminati	,	75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder				
		Appearance	No marking defects	Preheat the capacitor at 120 to 150°C° for 1 min.				
	Resistance	Capacitance Change	Within ±2.5% 1,000 min.	Immerse the capacitor in solder solution at 260±5°C for 10±1 sec. Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s				
13	to Soldering Heat	I.R.	More than 10,000M Ω	*Preheating for more than 3.2×2.5mm				
		Dielectric Strength	In accordance with item No.4	Step Temperature Time 1 100 to 120°C 1 min. 2 170 to 200°C 1 min.				
		Appearance	No marking defects	Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table.				
		Capacitance Change	Within ±2.5%					
		Q I.R.	500 min. More than 10,000MΩ	Let sit for 24±2 hrs. at room condition*, then measure. Step Temperature (°C) Time (min.)				
14	Temperature Cycle	Dielectric Strength	In accordance with item No.4	1 Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30±3 4 Room Temp. 2 to 3 4 Solder resist Glass Epoxy Board Fig. 4				
		Appearance	No marking defects					
	Humidity	Capacitance Change	Within ±5.0%	Let the capacitor sit at 40±2°C and relative humidity of 90 to 95%				
15	(Steady	Q	350 min.	for 500^{+20}_{-0} hrs. Remove and let sit for 24 ± 2 hrs. at room condition*, then				
	State)	I.R.	More than 1,000MΩ	measure.				
		Dielectric Strength	In accordance with item No.4					
		Appearance	No marking defects	-				
		Capacitance Change	Within ±3.0%	Apply 120% of the rated voltage for 1,000 $^{+48}_{-0}$ hrs. at maximum operating temperature $\pm 3^{\circ}$ C.				
16	Life	Q I.R.	350 min. More than 1,000M $Ω$	Remove and let sit for 24±2 hrs. at room condition*, then measure.				
		Dielectric Strength	In accordance with item No.4	The charge/discharge current is less than 50mA.				

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

muRata

Medium Voltage High Capacitance for General Use

■ Features

- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 2. Sn-plated external electrodes realizes good solderability.
- Use the GRM18/21/31 types with flow or reflow soldering, and other types with reflow soldering only.

■ Applications

- Ideal for use on diode-snubber circuits for switching power supplies
- Ideal for use as primary-secondary coupling for DC-DC converter
- 3. Ideal for use on line filters and ringer detectors for telephones, facsimiles and modems





Part Number	Dimensions (mm)								
	L	W	T	е	g min.				
GRM188	1.6 ±0.1	0.8 ±0.1	0.8 ±0.1	0.2 to 0.5	0.4				
GRM21A	2.0 +0.2	1.25 +0.2	1.0 +0,-0.3		0.7				
GRM21B	2.0 ±0.2	1.25 ±0.2	1.25 ±0.2		0.7				
GRM31B	3.2 +0.2	1.6 ±0.2	1.25 +0,-0.3		1.2				
GRM31C	3.2 ±0.2		1.6 ±0.2	0.3 min.					
GRM32Q	3.2 ±0.3	2.5 +0.2	1.5 +0,-0.3						
GRM32D	3.2 ±0.3	2.5 ±0.2	2.0 +0,-0.3						
GRM43Q	4.5 ±0.4	3.2 ±0.3	1.5 +0,-0.3		2.2				
GRM43D	4.5 ±0.4	3.2 ±0.3	2.0 +0,-0.3		2.2				
GRM55D	5.7 ±0.4	5.0 ±0.4	2.0 +0,-0.3		3.2				

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM188R72E221KW07D	DC250	X7R (EIA)	220pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E331KW07D	DC250	X7R (EIA)	330pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E471KW07D	DC250	X7R (EIA)	470pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E681KW07D	DC250	X7R (EIA)	680pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E102KW07D	DC250	X7R (EIA)	1000pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM21AR72E102KW01D	DC250	X7R (EIA)	1000pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM188R72E152KW07D	DC250	X7R (EIA)	1500pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM21AR72E152KW01D	DC250	X7R (EIA)	1500pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM188R72E222KW07D	DC250	X7R (EIA)	2200pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM21AR72E222KW01D	DC250	X7R (EIA)	2200pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21AR72E332KW01D	DC250	X7R (EIA)	3300pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21AR72E472KW01D	DC250	X7R (EIA)	4700pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21AR72E682KW01D	DC250	X7R (EIA)	6800pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21BR72E103KW03L	DC250	X7R (EIA)	10000pF ±10%	2.0	1.25	1.25	0.7	0.3 min.
GRM31BR72E153KW01L	DC250	X7R (EIA)	15000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72E223KW01L	DC250	X7R (EIA)	22000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31CR72E333KW03L	DC250	X7R (EIA)	33000pF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM31CR72E473KW03L	DC250	X7R (EIA)	47000pF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM31BR72E683KW01L	DC250	X7R (EIA)	68000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM32QR72E683KW01L	DC250	X7R (EIA)	68000pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM31CR72E104KW03L	DC250	X7R (EIA)	0.10μF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM32DR72E104KW01L	DC250	X7R (EIA)	0.10μF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43QR72E154KW01L	DC250	X7R (EIA)	0.15μF ±10%	4.5	3.2	1.5	2.2	0.3 min.
GRM32DR72E224KW01L	DC250	X7R (EIA)	0.22μF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43DR72E224KW01L	DC250	X7R (EIA)	0.22μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM43DR72E334KW01L	DC250	X7R (EIA)	0.33μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR72E334KW01L	DC250	X7R (EIA)	0.33μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM43DR72E474KW01L	DC250	X7R (EIA)	0.47μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR72E474KW01L	DC250	X7R (EIA)	0.47μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM55DR72E105KW01L	DC250	X7R (EIA)	1.0μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM31BR72J102KW01L	DC630	X7R (EIA)	1000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J152KW01L	DC630	X7R (EIA)	1500pF ±10%	3.2	1.6	1.25	1.2	0.3 min.

Continued from the preceding page.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM31BR72J222KW01L	DC630	X7R (EIA)	2200pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J332KW01L	DC630	X7R (EIA)	3300pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J472KW01L	DC630	X7R (EIA)	4700pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J682KW01L	DC630	X7R (EIA)	6800pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J103KW01L	DC630	X7R (EIA)	10000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31CR72J153KW03L	DC630	X7R (EIA)	15000pF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM32QR72J223KW01L	DC630	X7R (EIA)	22000pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM32DR72J333KW01L	DC630	X7R (EIA)	33000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM32DR72J473KW01L	DC630	X7R (EIA)	47000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43QR72J683KW01L	DC630	X7R (EIA)	68000pF ±10%	4.5	3.2	1.5	2.2	0.3 min.
GRM43DR72J104KW01L	DC630	X7R (EIA)	0.10μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR72J154KW01L	DC630	X7R (EIA)	0.15μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM55DR72J224KW01L	DC630	X7R (EIA)	0.22μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM31BR73A471KW01L	DC1000	X7R (EIA)	470pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A102KW01L	DC1000	X7R (EIA)	1000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A152KW01L	DC1000	X7R (EIA)	1500pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A222KW01L	DC1000	X7R (EIA)	2200pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A332KW01L	DC1000	X7R (EIA)	3300pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A472KW01L	DC1000	X7R (EIA)	4700pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM32QR73A682KW01L	DC1000	X7R (EIA)	6800pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM32QR73A103KW01L	DC1000	X7R (EIA)	10000pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM32DR73A153KW01L	DC1000	X7R (EIA)	15000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM32DR73A223KW01L	DC1000	X7R (EIA)	22000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43DR73A333KW01L	DC1000	X7R (EIA)	33000pF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM43DR73A473KW01L	DC1000	X7R (EIA)	47000pF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR73A104KW01L	DC1000	X7R (EIA)	0.10μF ±10%	5.7	5.0	2.0	3.2	0.3 min.

No.	Ite	em	Specifications	Test Method			
1	Operating Temperatu	ure Range	−55 to +125°C	-			
2	Appearan	nce	No defects or abnormalities	Visual inspection			
3	Dimensio	ns	Within the specified dimensions	Using calipers			
4	Dielectric Strength		No defects or abnormalities	No failure should be observed when 150% of the rated voltage (200% of the rated voltage in case of rated voltage: DC250V, 120% of the rated voltage in case of rated voltage: DC1kV) is applied between the terminations for 1 to 5 sec., provided the charge/discharge current is less than 50mA.			
5	Insulation Resistance (I.R.)		C≥0.01μF: More than 100MΩ • μF C<0.01μF: More than 10,000MΩ	The insulation resistance should be measured with DC500 \pm 50V (DC250 \pm 25V in case of rated voltage: DC250V) and within 60 \pm 5 sec. of charging.			
6	Capacitar	nce	Within the specified tolerance	The capacitance/D.E. should be measured at a frequency of			
7	Dissipation Factor (D		0.025 max.	The capacitance/D.F. should be measured at a frequency of 1±0.2kHz and a voltage of AC1±0.2V(r.m.s.)			
8	Capacitance Temperature Characteristics		Cap. Change Within ±15% (Temp. Range: −55 to +125°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150 $^{+0}_{-10}$ °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.			
9	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N (5N : Size 1.6×0.8mm only), 10±1s Glass Epoxy Board Fig. 1			
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).			
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied			
10	Vibration Resistance	D.F.	0.025 max.	uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board			
			·				

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa





No.	Ite	em		S	pecification	ns			Test Method			
			No cracking or	marking de	efects should	d occur.		Solder the cap	pacitor to the testing jig (glass	epoxy board) shown		
			\$\frac{b}{4.5}\$ \$\frac{1}{4}\$					Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s 11 Pressurize				
11	1 Deflection	n	LXW (mm) 1.6X0.8 2.0X1.25	a 1.0 1.2	Dimens b 3.0 4.0	c 1.2 1.65	d		R230 Flexure:	=1		
			3.2×1.6 3.2×2.5 4.5×3.2	2.2 2.2 3.5	5.0 5.0 7.0	2.0 2.9 3.7	1.0		l * 45 *l* 45 *l Fig. 3	(in mm)		
			5.7×5.0	4.5	8.0 Fig. 2	5.6						
12	Solderab Terminati	-	75% of the termi	% of the terminations are to be soldered evenly and continuously				rosin (JIS-K-5) Immerse in so Immersing spe	capacitor in a solution of ethano 902) (25% rosin in weight propoler solution for 2±0.5 sec. eed: 25±2.5mm/s er: 245±5°C Lead Free Solder 235±5°C H60A or H63A Eu	ortion).		
		Appearance	No marking defects					Preheat the capacitor at 120 to 150°C° for 1 min. Immerse the capacitor in solder solution at 260±5°C for 10±1				
		Capacitance Change	Within ±10%					sec. Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s •Pretreatment				
13	Resistance to Soldering Heat	D.F.	0.025 max. C≥0.01μF: More than 100MΩ • μF C<0.01μF: More than 10,000MΩ					Perform a heat treatment at 150 ± 18 °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.				
		Dielectric Strength	In accordance v	with item N	lo.4			*Preheating fo	or more than 3.2×2.5mm Temperature 100 to 120℃ 170 to 200℃	Time 1 min. 1 min.		
		Appearance	No marking def	ects					tor to the supporting jig (glass	epoxy board) shown		
		Capacitance Change	Within ±7.5%					in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table.				
		D.F.	0.025 max.						2 hrs. at room condition*, then Temperature (°C)	measure. Time (min.)		
		I.R.	C≥0.01μF: Mor C<0.01μF: Mor					Step 1 2	Min. Operating Temp.±3 Room Temp.	30±3 2 to 3		
	Temperature							3 4	Max. Operating Temp.±2 Room Temp.	30±3 2 to 3		
14	Cycle		In accordance with item No.4				eat treatment at 150±₁8°C for e2 hrs. at room condition*.	60±5 min. and then				
		Strength	In accordance with item No.4						Solde Glass Epoxy Board Fig. 4	r resist		
		Appearance	No marking def	ects					<u> </u>			
		Capacitance Change	Within ±15%					for 500 ±24 hr		-		
15	Humidity (Steady	D.F.	0.05 max.					Remove and I measure.	et sit for 24±2 hrs. at room co	ndition*, then		
	State)	I.R.	C≥0.01μF: Mor C<0.01μF: Mor					Pretreatmen Perform a he	eat treatment at 150 ± 18 ℃ for	60±5 min. and then		
		Dielectric			lo.4		let sit for 24±2 hrs. at room condition*.					

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^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

Continued from the preceding page.

No.	. Item		Specifications	Test Method			
		Appearance	No marking defects	Apply 120% of the rated voltage (150% of the rated voltage in			
16		Capacitance Change	Within ±15% (rated voltage: DC250V, DC630V) Within ±20% (rated voltage: DC1kV)	case of rated voltage: DC250V, 110% of the rated voltage in case of rated voltage: DC1kV) for 1,000 ± 48 hrs. at maximum			
	Life	D.F.	0.05 max.	operating temperature ±3°C. Remove and let sit for 24 ±2 hrs. at room condition*, then measure.			
	Elic	I.R.	C≧0.01μF: More than 10MΩ • μF C<0.01μF: More than 1,000MΩ	The charge/discharge current is less than 50mA. •Pretreatment			
		Dielectric Strength	In accordance with item No.4	Apply test voltage for 60±5 min. at test temperature. Remove and let sit for 24±2 hrs. at room condition*.			
		Appearance	No marking defects				
	Humidity Loading	Capacitance Change	Within ±15%	Apply the rated voltage at 40±2°C and relative humidity of 90 to 95% for 500 \pm 26 hrs.			
17	(Application:	D.F.	0.05 max.	Remove and let sit for 24±2 hrs. at room condition*, then measure.			
17	DC250V, DC630V item)	I.R.	C≥0.01μF: More than 10MΩ • μF C<0.01μF: More than 1,000MΩ	Pretreatment Apply test voltage for 60±5 min. at test temperature.			
	item)	Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.			

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



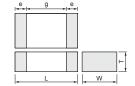


Only for LCD Backlight Inverter Circuit

■ Features

- 1. Low-loss and suitable for high frequency circuits
- 2. Murata's original internal electrode structure realizes high flash-over voltage.
- 3. A new monolithic structure for small, surfacemountable devices capable of operating at high voltage levels.
- 4. Sn-plated external electrodes realize good solderability.
- 5. Only for reflow soldering
- 6. The capacitors less than 22pF can be applied maximum 4.0kV peak to peak at 100kHz or less only for the ballast or the resonance usage in the LCD backlight inverter circuit.





Part Number		Dim	ensions (mm)	
Part Number	L	W	T	e min.	g min.
GRM42A	4.5 ±0.3	2.0 ±0.2	1.0 +0, -0.3	0.3	2.9

■ Applications

Ideal for use as the ballast in LCD backlight inverter.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM42A5C3F050DW01L	DC3150	COG (EIA)	5.0 ±0.5pF	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F100JW01L	DC3150	C0G (EIA)	10 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F120JW01L	DC3150	C0G (EIA)	12 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F150JW01L	DC3150	COG (EIA)	15 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F180JW01L	DC3150	COG (EIA)	18 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F220JW01L	DC3150	C0G (EIA)	22 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F270JW01L	DC3150	COG (EIA)	27 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F330JW01L	DC3150	C0G (EIA)	33 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F390JW01L	DC3150	C0G (EIA)	39 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F470JW01L	DC3150	COG (EIA)	47 ±5%	4.5	2.0	1.0	2.9	0.3 min.

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No.	Ite	em	Specifications	Test Method
1	Operating Temperatu	ıre Range	−55 to +125℃	-
2	Appearar		No defects or abnormalities	Visual inspection
3	Dimensio	ns	Within the specified dimension	Using calipers
4	Dielectric	Strength	No defects or abnormalities	No failure should be observed when DC4095V is applied between the terminations for 1 to 5 sec., provided the charge/ discharge current is less than 50mA.
5	Insulation F	Resistance	More than 10,000M Ω	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.
6	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at a frequency of
7	Q		1,000 min.	1±0.2MHz and a voltage of AC0.5 to 5V(r.m.s.)
8	Capacitance 8 Temperature Characteristics		Temp. Coefficient 0±30 ppm/°C (Temp. Range: +25 to +125°C) 0+30, −72 ppm/°C (Temp. Range: −55 to +25°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2
9	9 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Glass Epoxy Board Fig. 1
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).
10	Vibration Resistance	Capacitance Q	Within the specified tolerance 1,000 min.	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board
			No cracking or marking defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown
11	1 Deflection		Dimension (mm)	in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s Pressurize Pressurize Capacitance meter 45 (in mm) Fig. 3

Continued from the preceding page.

	Continued if	on the piec	eding page.					
No.	Ite	em	Specifications	Test Method				
12	Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder				
		Appearance	No marking defects	Preheat the capacitor as table.				
		Capacitance Change	Within ±2.5%	Immerse the capacitor in solder solution at 260±5°C for 10±1 sec Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s				
13	Resistance to Soldering	Q	1,000 min.	.				
13	Heat	I.R.	More than 10,000M Ω	*Preheating				
		Dielectric Strength	In accordance with item No.4	Step Temperature Time 1 100 to 120℃ 1 min. 2 170 to 200℃ 1 min.				
		Appearance	No marking defects	Fix the capacitor to the supporting jig (glass epoxy board) shown				
		Capacitance Change	Within ±2.5%	in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table.				
		Q	1,000 min.	Let sit for 24±2 hrs. at room condition*, then measure.				
		I.R.	More than 10,000M Ω	Step Temperature (°C) Time (min.)				
14	Temperature Cycle	Dielectric Strength	In accordance with item No.4	1 Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30±3 4 Room Temp. 2 to 3 4 Room Temp. 2 to 3				
		Appearance	No marking defects					
	Humidity	Capacitance Change	Within ±5.0%	Let the capacitor sit at 40±2°C and relative humidity of 90 to 95%				
15	(Steady	Q	350 min.	for 500 ±26 hrs. Remove and let sit for 24±2 hrs. at room condition*, then				
	State)	I.R.	More than 1,000M Ω	measure.				
		Dielectric Strength	In accordance with item No.4					
		Appearance	No marking defects					
		Capacitance Change	Within ±3.0%	Apply 120% of the rated voltage for 1,000 $^{+48}_{0}$ hrs. at maximum operating temperature $\pm 3^{\circ}$ C.				
16	Life	Q	350 min.	Remove and let sit for 24±2 hrs. at room condition*, then				
		I.R.	More than 1,000M Ω	measure. The charge/discharge current is less than 50mA.				
		Dielectric Strength	In accordance with item No.4					

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



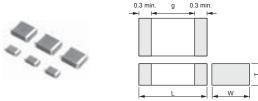
Only for Information Devices/Tip & Ring

■ Features

- These items are designed specifically for telecommunications devices (IEEE802.3) in Ethernet LAN and primary-secondary coupling for DC-DC converter.
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 3. Sn-plated external electrodes realizes good solderability.
- 4. Only for reflow soldering
- The low-profile type (thickness: 1.5mm max.) is available. Fit for use on thinner type equipment.

■ Applications

- Ideal for use on telecommunications devices in Ethernet LAN
- Ideal for use as primary-secondary coupling for DC-DC converter



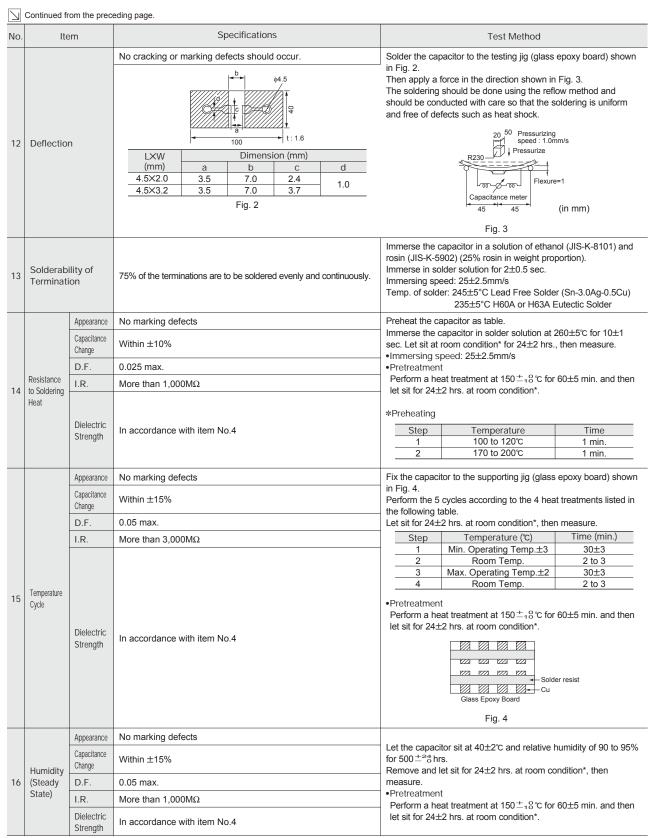
Dant Normalian	Dimensions (mm)						
Part Number	L	W	Т	g min.			
GR442Q	4.5 ±0.3 2.0 ±0.2		1.5 +0, -0.3				
GR443D	4.5 +0.4	3.2 +0.3	2.0 +0, -0.3	2.5			
GR443Q	4.5 ±0.4	3.2 ±0.3	1.5 +0, -0.3				
GR455D	5.7 ±0.4	5.0 ±0.4	2.0 +0, -0.3	3.2			

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GR442QR73D101KW01L	DC2000	X7R (EIA)	100 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D121KW01L	DC2000	X7R (EIA)	120 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D151KW01L	DC2000	X7R (EIA)	150 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D181KW01L	DC2000	X7R (EIA)	180 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D221KW01L	DC2000	X7R (EIA)	220 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D271KW01L	DC2000	X7R (EIA)	270 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D331KW01L	DC2000	X7R (EIA)	330 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D391KW01L	DC2000	X7R (EIA)	390 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D471KW01L	DC2000	X7R (EIA)	470 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D561KW01L	DC2000	X7R (EIA)	560 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D681KW01L	DC2000	X7R (EIA)	680 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D821KW01L	DC2000	X7R (EIA)	820 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D102KW01L	DC2000	X7R (EIA)	1000 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D122KW01L	DC2000	X7R (EIA)	1200 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D152KW01L	DC2000	X7R (EIA)	1500 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR443QR73D182KW01L	DC2000	X7R (EIA)	1800 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D222KW01L	DC2000	X7R (EIA)	2200 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D272KW01L	DC2000	X7R (EIA)	2700 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D332KW01L	DC2000	X7R (EIA)	3300 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D392KW01L	DC2000	X7R (EIA)	3900 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443DR73D472KW01L	DC2000	X7R (EIA)	4700 ±10%	4.5	3.2	2.0	2.5	0.3 min.
GR455DR73D103KW01L	DC2000	X7R (EIA)	10000 ±10%	5.7	5.0	2.0	3.2	0.3 min.

No.	Ite	em	Specifications	Test Method
1	Operating Temperatu	ıre Range	-55 to +125℃	-
2	Appearan	nce	No defects or abnormalities	Visual inspection
3	Dimensio	ns	Within the specified dimensions	Using calipers
4	Dielectric	ic Strength No defects or abnormalities		No failure should be observed when voltage in table is applied between the terminations, provided the charge/discharge current is less than 50mA. Rated voltage Test Voltage Time
				DC2kV 120% of the rated voltage 60±1 sec.
5	Pulse Vol	tage	No self healing breakdowns or flash-overs have taken place in the capacitor.	AC1500V(r.m.s.) 60±1 sec. 10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60 sec. Applied Voltage: 2.5kV zero to peak
6	Insulation F (I.R.)	Resistance	More than $6{,}000M\Omega$	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.
7	Capacita	nce	Within the specified tolerance	The capacitance/D.F. should be measured at a frequency of
8	Dissipation Factor (D		0.025 max.	1±0.2kHz and a voltage of AC1±0.2V(r.m.s.)
9	Capacitance 9 Temperature Characteristics		Cap. Change within ±15% (Temp. Range: −55 to +125°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150 ⁺⁰ / ₋₁₀ °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Glass Epoxy Board Fig. 1
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion
11	Vibration Resistance	D.F.	0.025 max.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa





^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page.

No.	Ite	em	Specifications	Test Method
		Appearance	No marking defects	
		Capacitance Change	Within ±20%	Apply 110% of the rated voltage for 1,000 ±4% hrs. at maximum operating temperature ±3°C. Remove and let sit for 24 ±2 hrs. at room condition*, then measure.
17	Life	D.F.	0.05 max.	The charge/discharge current is less than 50mA.
		I.R.	More than $2{,}000M\Omega$	Pretreatment Apply test voltage for 60±5 min. at test temperature.
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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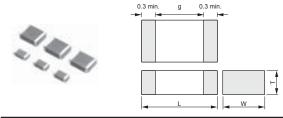
Only for Camera Flash Circuit

■ Features

- 1. Suitable for the trigger of the flash circuit, because real capacitance is stable during operating voltage
- 2. The thin type fit for thinner camera.
- 3. Sn-plated external electrodes realizes good solderability.
- 4. For flow and reflow soldering

Applications

For strobe circuit



Dort Number		Dimensions (mm)					
Part Number	L W T		Т	g min.			
GR731A			1.0 +0, -0.3				
GR731B	3.2 ±0.2	1.6 ±0.2	1.25 +0, -0.3	1.2			
GR731C			1.6 ±0.2				

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GR731AW0BB103KW01D	DC350	-	10000 ±10%	3.2	1.6	1.0	1.2	0.3 min.
GR731AW0BB153KW01D	DC350	-	15000 ±10%	3.2	1.6	1.0	1.2	0.3 min.
GR731BW0BB223KW01L	DC350	-	22000 ±10%	3.2	1.6	1.25	1.2	0.3 min.
GR731BW0BB333KW01L	DC350	-	33000 ±10%	3.2	1.6	1.25	1.2	0.3 min.
GR731CW0BB473KW03L	DC350	-	47000 ±10%	3.2	1.6	1.6	1.2	0.3 min.

No.	Ite	m	Specifications	Test Method
1	Operating Temperatu	ıre Range	-55 to +125°C	-
2	Appearan	ice	No defects or abnormalities	Visual inspection
3	Dimensio	ns	Within the specified dimensions	Using calipers
4	Dielectric Strength		No defects or abnormalities	No failure should be observed when DC500V is applied between the terminations for 1 to 5 sec., provided the charge/discharge current is less than 50mA.
5	Insulation F (I.R.)	Resistance	C≥0.01μF: More than 100M Ω • μF C<0.01μF: More than 10,000M Ω	The insulation resistance should be measured with DC250±50V and within 60±5 sec. of charging.
6	Capacitar	nce	Within the specified tolerance	The conscitous of D. C. should be measured at a frequency of
7	Dissipation Factor (D.		0.025 max.	The capacitance/D.F. should be measured at a frequency of 1±0.2kHz and a voltage of AC1±0.2V(r.m.s.)
8	Capacitance Temperature Characteristics		Cap. Change Within ±10% (Apply DC350V bias) Within ±33 % (No DC bias) (Temp. Range: -55 to +125℃)	The capacitance measurement should be made at each step specified in Table. Step Temperature (℃) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150 ⁺⁰ / ₋₁₀ ℃ for 60±5 min. and then let sit for 24±2 hrs. at room condition*.
9	9 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Glass Epoxy Board Fig. 1
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion
10	Vibration Resistance	D.F.	0.025 max.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page Specifications No. Item Test Method Solder the capacitor to the testing jig (glass epoxy board) shown No cracking or marking defects should occur. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed: 1.0mm/s Deflection Pressurize R230 LXW Dimension (mm) (mm) d Flexure=1 3.2X1.6 22 5.0 20 10 Capacitance mete Fig. 2 (in mm) Fig. 3 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Solderability of 12 75% of the terminations are to be soldered evenly and continuously. Immersing speed: 25±2.5mm/s Termination Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder Appearance No marking defects Preheat the capacitor at 120 to 150°C* for 1 min. Capacitance Within ±10% Immerse the capacitor in solder solution at 260±5℃ for 10±1 Change sec. Let sit at room condition* for 24±2 hrs., then measure. Resistance 0.025 max. D.F. •Immersing speed: 25±2.5mm/s 13 to Soldering C≥0.01 μ F: More than 100M Ω • μ F Pretreatment Heat I.R. C<0.01 μF : More than 10,000 $\!M\Omega$ Perform a heat treatment at 150 ⁺_{−10} °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Dielectric In accordance with item No.4 Strength No marking defects Fix the capacitor to the supporting jig (glass epoxy board) shown Appearance in Fig. 4. Capacitance Within ±7.5% Perform the 5 cycles according to the 4 heat treatments listed in Change the following table. D.F. 0.025 max. Let sit for 24±2 hrs. at room condition*, then measure. Step Temperature (℃) Time (min.) $C{\ge}0.01\mu\text{F}{:}$ More than $100\text{M}\Omega$ • μF I.R. 30 ± 3 C<0.01 μ F: More than 10,000M Ω 1 Min. Operating Temp.±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30 ± 3 Room Temp 4 2 to 3 Temperature 14 Cycle Pretreatment Perform a heat treatment at 150 ⁺₁° ℃ for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Dielectric In accordance with item No.4 Strength Solder resist Cu Glass Epoxy Board Fig. 4 Appearance No marking defects Let the capacitor sit at 40±2℃ and relative humidity of 90 to 95% Capacitance Within ±15% for 500 ±24 hrs. Change Remove and let sit for 24±2 hrs. at room condition*, then Humidity D.F. 0.05 max. 15 (Steady measure. C≥0.01 μ F: More than 10M Ω • μ F State) Pretreatment I.R. C<0.01 μ F: More than 1,000M Ω Perform a heat treatment at 150 ± 10 °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Dielectric In accordance with item No.4

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^{* &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

Continued from the preceding page.

No.	Ite	em	Specifications	Test Method		
		Appearance	No marking defects			
		Capacitance Change	Within ±15%	Apply DC350V for 1,000 $\pm \frac{48}{6}$ hrs. at maximum operating temperature $\pm 3^{\circ}$ C. Remove and let sit for 24 ± 2 hrs. at room		
16	Life	D.F.	0.05 max.	condition*, then measure. The charge/discharge current is less than 50mA.		
	Liic	I.R.	C≥0.01μF: More than 10MΩ • μF C<0.01μF: More than 1,000MΩ	Pretreatment Apply test voltage for 60±5 min. at test temperature.		
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.		
		Appearance	No marking defects			
		Capacitance Change	Within ±15%	Apply the rated voltage at 40±2°C and relative humidity of 90 to 95% for 500 \pm 26 hrs.		
17	Humidity	D.F.	0.05 max.	Remove and let sit for 24±2 hrs. at room condition*, then measure.		
17	Loading	I.R.	C≥0.01μF: More than 10MΩ • μF C<0.01μF: More than 1,000MΩ	Pretreatment Apply test voltage for 60±5 min. at test temperature.		
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.		

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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AC250V (r.m.s.) Type (Which Meet Japanese Law)

■ Features

- 1. Chip monolithic ceramic capacitor for AC lines
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- Sn-plated external electrodes realizes good solderability.
- 4. Only for reflow soldering
- 5. Capacitance 0.01 to 0.1uF for connecting lines and 470 to 4700pF for connecting lines to earth

■ Applications

Noise suppression filters for switching power supplies, telephones, facsimiles, modems

■ Reference standard

GA2 series obtains no safety approval. This series is based on JIS C 5102, JIS C 5150, and the standards of the electrical appliance and material safety law of Japan (separated table 4).





			-				
Part Number	Dimensions (mm)						
Part Number	L	W	Т	e min.	g min.		
GA242Q	4.5 ±0.3	2.0 ±0.2	1.5 +0, -0.3				
GA243D	4.5 ±0.4	3.2 +0.3	2.0 +0, -0.3	0.3	2.5		
GA243Q	4.3 ±0.4	3.2 ±0.3	1.5 +0, -0.3	0.3			
GA255D	5.7 ±0.4	5.0 ±0.4	2.0 +0, -0.3		3.2		

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA242QR7E2471MW01L	AC250 (r.m.s.)	X7R (EIA)	470pF ±20%	4.5	2.0	1.5	2.5	0.3 min.
GA242QR7E2102MW01L	AC250 (r.m.s.)	X7R (EIA)	1000pF ±20%	4.5	2.0	1.5	2.5	0.3 min.
GA243QR7E2222MW01L	AC250 (r.m.s.)	X7R (EIA)	2200pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243QR7E2332MW01L	AC250 (r.m.s.)	X7R (EIA)	3300pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243DR7E2472MW01L	AC250 (r.m.s.)	X7R (EIA)	4700pF ±20%	4.5	3.2	2.0	2.5	0.3 min.
GA243QR7E2103MW01L	AC250 (r.m.s.)	X7R (EIA)	10000pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243QR7E2223MW01L	AC250 (r.m.s.)	X7R (EIA)	22000pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243DR7E2473MW01L	AC250 (r.m.s.)	X7R (EIA)	47000pF ±20%	4.5	3.2	2.0	2.5	0.3 min.
GA255DR7E2104MW01L	AC250 (r.m.s.)	X7R (EIA)	0.10μF ±20%	5.7	5.0	2.0	3.2	0.3 min.

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No.	Ite	em	Specifications	Test Method
1	Operating Temperatu	ure Range	−55 to +125℃	-
2	Appearan	nce	No defects or abnormalities	Visual inspection
3	Dimensio	ns	Within the specified dimensions	Using calipers
4			No defects or abnormalities	No failure should be observed when voltage in table is applied between the terminations for 60±1 sec., provided the charge/discharge current is less than 50mA. Nominal Capacitance Test voltage C≥10,000pF AC575V (r.m.s.) C<10,000pF AC1500V (r.m.s.)
5	Insulation F	Resistance	More than $2{,}000M\Omega$	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.
6	Capacitar	nce	Within the specified tolerance	
7	Dissipation Factor (D	on	0.025 max.	The capacitance/D.F. should be measured at a frequency of 1±0.2kHz and a voltage of AC1±0.2V (r.m.s.)
8	Capacitance 8 Temperature Characteristics		Cap. Change Within ±15% (Temp. Range: −55 to +125°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150±18°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.
9	Discharge Test (Application: Nominal Capacitance C<10,000pF)	Appearance	No defects or abnormalities	As in Fig., discharge is made 50 times at 5 sec. intervals from the capacitor (Cd) charged at DC voltage of specified. R3 R1 T 10kV V Cd Cd Ct Ct Capacitor under test Cd: 0.001μF R1: 1,000Ω R2: 100MΩ R3: Surge resistance
10	O Adhesive Strength of Termination		No removal of the terminations or other defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Glass Epoxy Board Fig. 1
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied
11	Vibration Resistance	D.F.	0.025 max.	uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.).
				Solder resist Glass Epoxy Board

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page Specifications No. Item Test Method Solder the capacitor to the testing jig (glass epoxy board) shown No cracking or marking defects should occur. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed: 1.0mm/s Pressurize 12 Deflection R230 t: 1.6 Flexure=1 Dimension (mm) LXW (mm) Capacitance mete d 4.5×2.0 3.5 7.0 2.4 (in mm) 4.5×3.2 3.5 7.0 3.7 1.0 Fig. 3 5.7×5.0 4.5 8.0 5.6 Fig. 2 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Solderability of 13 75% of the terminations are to be soldered evenly and continuously. Immersing speed: 25±2.5mm/s Termination Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder Appearance No marking defects Capacitance Within ±15% Change The capacitor should be subjected to 40±2°C, relative humidity of Humidity 14 D.F 0.05 max. 90 to 98% for 8 hrs., and then removed in room condition* for 16 Insulation hrs. until 5 cycles. I.R. More than 1,000M Ω Dielectric In accordance with item No.4 Strength No marking defects Appearance Preheat the capacitor as table. Immerse the capacitor in solder solution at 260±5℃ for 10±1 Capacitance Within ±10% sec. Let sit at room condition* for 24±2 hrs., then measure. Change •Immersing speed: 25±2.5mm/s D.F. 0.025 max. Pretreatment Resistance Perform a heat treatment at 150 ⁺₁₀ °C for 60±5 min. and then I.R. More than 2,000M Ω 15 to Soldering let sit for 24±2 hrs. at room condition*. Heat *Preheating Dielectric In accordance with item No.4 Step Temperature Time Strength 100 to 120°C 1 min 170 to 200℃ 1 min Appearance No marking defects Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Capacitance Within ±15% Perform the 5 cycles according to the 4 heat treatments listed in Change the following table. D.F. 0.05 max. Let sit for 24±2 hrs. at room condition*, then measure. Time (min.) Temperature (℃) More than $2,000M\Omega$ Step I.R. Min. Operating Temp.±3 30±3 Room Temp. 2 to 3 Max. Operating Temp.±2 3 30 + 34 Room Temp. 2 to 3 Temperature 16 Cycle Pretreatment Perform a heat treatment at 150[±]₁₀ °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Dielectric In accordance with item No.4 Strength M M M M-Glass Epoxy Board Fig. 4



^{* &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

Continued from the preceding page.

No.	Ite	Item Specifications		Test Method			
		Appearance	No marking defects				
	Humidity	Capacitance Change	Within ±15%	Let the capacitor sit at 40±2°C and relative humidity of 90 to 95% for 500±20 hrs. Remove and let sit for 24±2 hrs. at room condition*, then			
17	(Steady	D.F.	0.05 max.	measure.			
	State)	I.R.	More than 1,000M Ω	Pretreatment Perform a heat treatment at 150 ± 10 ° ℃ for 60±5 min. and then			
		Dielectric Strength	In accordance with item No.4	let sit for 24±2 hrs. at room condition*.			
		Appearance	No marking defects	Apply voltage and time as Table at 85±2°C. Remove and let sit			
		Capacitance Change	Within ±20%	for 24 ±2 hrs. at room condition*, then measure. The charge / discharge current is less than 50mA.			
		D.F.	0.05 max.	Nominal Capacitance Test Time Test voltage			
18	Life	I.R.	More than 1,000M Ω	C<10,000pF 1,500 ⁺⁴⁸ _O hrs. AC500V (r.m.s.) *			
		Dielectric Strength	In accordance with item No.4	* Except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 sec. Pretreatment Apply test voltage for 60±5 min. at test temperature. Remove and let sit for 24±2 hrs. at room condition*.			
		Appearance	No marking defects				
		Capacitance Change	Within ±15%	Apply the rated voltage at 40±2°C and relative humidity of 90 to 95% for 500±26 hrs. Remove and let sit for 24±2 hrs. at room condition*, then			
19	Humidity Loading	D.F.	0.05 max.	measure.			
	Loading	I.R.	More than 1,000M Ω	Pretreatment Apply test voltage for 60±5 min. at test temperature.			
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.			

^{* &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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Safety Standard Recognized Type GC (UL, IEC60384-14 Class X1/Y2)

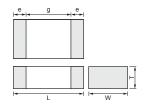
■ Features

- 1. Chip monolithic ceramic capacitor (certified as conforming to safety standards) for AC lines
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 3. Compared to lead type capacitors, this new capacitor is greatly downsized and low-profiled to 1/10 or less in volume, and 1/4 or less in height.
- 4. The type GC can be used as an X1-class and Y2-class capacitor, line-by-pass capacitor of UL1414.
- 5. +125 degree C guaranteed
- 6. Only for reflow soldering

Applications

- Ideal for use as Y capacitor or X capacitor for various switching power supplies
- 2. Ideal for modem applications





Part Number	Dimensions (mm)						
Part Number	L	W	T	e min.	g min.		
GA355D	5.7 ±0.4	5.0 ±0.4	2.0 ±0.3	0.3	4.0		

		Status of R	Rated	
	Standard No.	Type GB	Type GC	Voltage
UL	UL1414	_	0*	
BSI		_	0	
VDE	EN132400	0	0	AC250V
SEV	EN 132400	0	0	(r.m.s.)
SEMKO		0	0	
EN13240	0 Class	X2	X1, Y2	

^{*:} Line By-pass only

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA355DR7GC101KY02L	AC250 (r.m.s.)	X7R (EIA)	100 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GC151KY02L	AC250 (r.m.s.)	X7R (EIA)	150 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GC221KY02L	AC250 (r.m.s.)	X7R (EIA)	220 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GC331KY02L	AC250 (r.m.s.)	X7R (EIA)	330 ±10%	5.7	5.0	2.0	4.0	0.3 min.





Safety Standard Recognized Type GD (IEC60384-14 Class Y3)

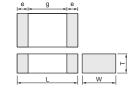
■ Features

- Available for equipment based on IEC/EN60950 and UL1950
- 2. The type GD can be used as a Y3-class capacitor.
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 4. +125 degree C guaranteed
- 5. Only for reflow soldering
- 6. The low-profile type (thickness: 1.5mm max.) is available. Fit for use on thinner type equipment.

Applications

- Ideal for use on line filters and couplings for DAA modems without transformers
- 2. Ideal for use on line filters for information equipment





Part Number	Dimensions (mm)							
Part Number	L	W	Т	e min.	g min.			
GA342A			1.0 +0, -0.3					
GA342D	4.5 ±0.3	2.0 ±0.2	2.0 ±0.3					
GA342Q	1		1.5 +0, -0.3	0.3	2.5			
GA343D	4.5 ±0.4	3.2 +0.3	2.0 +0, -0.3					
GA343Q	4.5 ±0.4	3.2 ±0.3	1.5 +0, -0.3					

	Standard	Class	Status of Recognition	Rated Voltage	
	No.	Class	Type GD		
SEMKO	EN132400	Y3	0	AC250V(r.m.s.)	

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ĸμ	μı	ications	

Size	Switching power supplies	Communication network devices such as a modem
4.5×3.2mm and under	_	0

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA342D1XGD100JY02L	AC250 (r.m.s.)	SL (JIS)	10 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD120JY02L	AC250 (r.m.s.)	SL (JIS)	12 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD150JY02L	AC250 (r.m.s.)	SL (JIS)	15 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD180JY02L	AC250 (r.m.s.)	SL (JIS)	18 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD220JY02L	AC250 (r.m.s.)	SL (JIS)	22 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342A1XGD270JW31L	AC250 (r.m.s.)	SL (JIS)	27 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD330JW31L	AC250 (r.m.s.)	SL (JIS)	33 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD390JW31L	AC250 (r.m.s.)	SL (JIS)	39 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD470JW31L	AC250 (r.m.s.)	SL (JIS)	47 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD560JW31L	AC250 (r.m.s.)	SL (JIS)	56 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD680JW31L	AC250 (r.m.s.)	SL (JIS)	68 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD820JW31L	AC250 (r.m.s.)	SL (JIS)	82 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342QR7GD101KW01L	AC250 (r.m.s.)	X7R (EIA)	100 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD151KW01L	AC250 (r.m.s.)	X7R (EIA)	150 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD221KW01L	AC250 (r.m.s.)	X7R (EIA)	220 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD331KW01L	AC250 (r.m.s.)	X7R (EIA)	330 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD471KW01L	AC250 (r.m.s.)	X7R (EIA)	470 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD681KW01L	AC250 (r.m.s.)	X7R (EIA)	680 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD102KW01L	AC250 (r.m.s.)	X7R (EIA)	1000 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD152KW01L	AC250 (r.m.s.)	X7R (EIA)	1500 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA343QR7GD182KW01L	AC250 (r.m.s.)	X7R (EIA)	1800 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GA343QR7GD222KW01L	AC250 (r.m.s.)	X7R (EIA)	2200 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GA343DR7GD472KW01L	AC250 (r.m.s.)	X7R (EIA)	4700 ±10%	4.5	3.2	2.0	2.5	0.3 min.



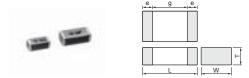
Safety Standard Recognized Type GF (IEC60384-14 Class Y2, X1/Y2)

■ Features

- Available for equipment based on IEC/EN60950 and UL1950. Besides, the GA352/355 types are available for equipment based on IEC/EN60065, UL1492, and UL6500
- 2. The type GF can be used as a Y2-class capacitor.
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 4. +125 degree C guaranteed
- 5. Only for reflow soldering
- 6. The low-profile type (thickness: 1.5mm max.) is available. Fit for use on thinner type equipment.

■ Applications

- Ideal for use on line filters and couplings for DAA modems without transformers
- 2. Ideal for use on line filters for information equipment
- Ideal for use as Y capacitor or X capacitor for various switching power supplies (GA352/355 types only)



Part Number	Dimensions (mm)						
Part Number	L W T		e min.	g min.			
GA342A			1.0 +0, -0.3				
GA342D	4.5 ±0.3	2.0 ±0.2	2.0 ±0.2*		2.5		
GA342Q			1.5 +0, -0.3	0.3			
GA352Q		2.8 ±0.3	1.5 +0, -0.3	0.5			
GA355D	5.7 ±0.4	5.0 +0.4	2.0 +0, -0.3		4.0		
GA355Q		3.0 ±0.4	1.5 +0, -0.3				

^{*} GA342D1X : 2.0±0.3

			Status of R	ecognition		
	Standard	Class	Туре	Rated		
	No.	Size : 4.5×2.0mm		Size: 5.7×2.8mm and over	Voltage	
UL	UL1414	X1, Y2	_	0	AC250V	
SEMKO	EN132400	Y2	0	0	(r.m.s.)	

Size	Switching power supplies	Communication network devices such as a modem	
4.5×2.0mm	_	0	
5.7×2.8mm and over	0	0	

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA342D1XGF100JY02L	AC250 (r.m.s.)	SL (JIS)	10 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF120JY02L	AC250 (r.m.s.)	SL (JIS)	12 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF150JY02L	AC250 (r.m.s.)	SL (JIS)	15 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF180JY02L	AC250 (r.m.s.)	SL (JIS)	18 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF220JY02L	AC250 (r.m.s.)	SL (JIS)	22 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342A1XGF270JW31L	AC250 (r.m.s.)	SL (JIS)	27 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF330JW31L	AC250 (r.m.s.)	SL (JIS)	33 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF390JW31L	AC250 (r.m.s.)	SL (JIS)	39 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF470JW31L	AC250 (r.m.s.)	SL (JIS)	47 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF560JW31L	AC250 (r.m.s.)	SL (JIS)	56 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF680JW31L	AC250 (r.m.s.)	SL (JIS)	68 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF820JW31L	AC250 (r.m.s.)	SL (JIS)	82 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342QR7GF101KW01L	AC250 (r.m.s.)	X7R (EIA)	100 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GF151KW01L	AC250 (r.m.s.)	X7R (EIA)	150 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342DR7GF221KW02L	AC250 (r.m.s.)	X7R (EIA)	220 ±10%	4.5	2.0	2.0	2.5	0.3 min.
GA342DR7GF331KW02L	AC250 (r.m.s.)	X7R (EIA)	330 ±10%	4.5	2.0	2.0	2.5	0.3 min.
GA352QR7GF471KW01L	AC250 (r.m.s.)	X7R (EIA)	470 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA352QR7GF681KW01L	AC250 (r.m.s.)	X7R (EIA)	680 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA352QR7GF102KW01L	AC250 (r.m.s.)	X7R (EIA)	1000 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA352QR7GF152KW01L	AC250 (r.m.s.)	X7R (EIA)	1500 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA355QR7GF182KW01L	AC250 (r.m.s.)	X7R (EIA)	1800 ±10%	5.7	5.0	1.5	4.0	0.3 min.
GA355QR7GF222KW01L	AC250 (r.m.s.)	X7R (EIA)	2200 ±10%	5.7	5.0	1.5	4.0	0.3 min.
GA355QR7GF332KW01L	AC250 (r.m.s.)	X7R (EIA)	3300 ±10%	5.7	5.0	1.5	4.0	0.3 min.
GA355DR7GF472KW01L	AC250 (r.m.s.)	X7R (EIA)	4700 ±10%	5.7	5.0	2.0	4.0	0.3 min.



Safety Standard Recognized Type GB (IEC60384-14 Class X2)

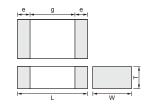
■ Features

- 1. The type GB can be used as an X2-class capacitor.
- Chip monolithic ceramic capacitor (certified as conforming to safety standards) for AC lines
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 4. Compared to lead type capacitors, this new capacitor is greatly downsized and low-profiled to 1/10 or less in volume, and 1/4 or less in height.
- 5. +125 degree C guaranteed
- 6. Only for reflow soldering

Applications

Ideal for use as X capacitor for various switching power supplies





Part Number	Dimensions (mm)						
Part Number	L W T		T	e min.	g min.		
GA355D	5.7 +0.4	5.0 ±0.4	2.0 ±0.3	0.3	4.0		
GA355X	5.7 ±0.4		2.7 ±0.3	0.3			

	Standard No.	Status of R	Rated	
	Standard No.	Type GB	Type GC	Voltage
UL	UL1414	_	0*	
BSI		_	0	
VDE	EN132400	0	0	AC250V
SEV	EN 132400	0	0	(r.m.s.)
SEMKO		0	0	
EN13240	0 Class	X2	X1, Y2	

^{*:} Line By-pass only

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA355DR7GB103KY02L	AC250 (r.m.s.)	X7R (EIA)	10000 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GB153KY02L	AC250 (r.m.s.)	X7R (EIA)	15000 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GB223KY02L	AC250 (r.m.s.)	X7R (EIA)	22000 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355XR7GB333KY06L	AC250 (r.m.s.)	X7R (EIA)	33000 ±10%	5.7	5.0	2.7	4.0	0.3 min.

No.	Ite	em	Specifications	Test Method		
1	Operating Temperatu	ure Range	-55 to +125℃	-		
2	Appearan	nce	No defects or abnormalities	Visual inspection		
3	Dimensio	ns	Within the specified dimensions	Using calipers		
4	Dielectric Strength		No defects or abnormalities	No failure should be observed when voltage in table is applied between the terminations for 60±1 sec., provided the charge/discharge current is less than 50mA. Test Voltage Type GB DC1075V Type GC/GD/GF AC1500V (r.m.s.)		
5	Pulse Vol (Applicati GD/GF)		No self healing breakdowns or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60 sec. Applied Voltage: 2.5kV zero to peak		
6	Insulation F (I.R.)	Resistance	More than $6,000M\Omega$	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.		
7	Capacitar	nce	Within the specified tolerance			
8	Dissipation 3 Factor (D.F.) Q		Char. Specification X7R D.F.≤0.025 SL Q≥400+20C*² (C<30pF)	The capacitance/Q/D.F. should be measured at a frequency of 1±0.2kHz (SL char.: 1±0.2MHz) and a voltage of AC1±0.2V (r.m.s.).		
9	Capacitance 9 Temperature Characteristics		Char. Capacitance Change X7R Within ±15% Temperature characteristic guarantee is −55 to +125°C Char. Temperature Coefficient SL +350 to −1000ppm/°C Temperature characteristic guarantee is +20 to +85°C	The capacitance measurement should be made at each step specified in Table. Step		
		Appearance	No defects or abnormalities	As in Fig., discharge is made 50 times at 5 sec. intervals from		
		I.R.	More than 1,000M Ω	the capacitor (Cd) charged at DC voltage of specified.		
10	Discharge Test (Application: Type GC)	Dielectric Strength	In accordance with item No.4	R3 T 10kV Ct: Capacitor under test Cd: 0.001μF R1: 1,000Ω R2: 100ΜΩ R3: Surge resistance		
11	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Glass Epoxy Board Glass Epoxy Board Glass Epoxy Board Fig. 1		

^{*1 &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



^{*2 &}quot;C" expresses nominal capacitance value (pF).

\square	Continued fr	om the prec	eding page.	
No.	Ite	em	Specifications	Test Method
		Appearance Capacitance	No defects or abnormalities Within the specified tolerance	Solder the capacitor to the test jig (glass epoxy board). The capacitor should be subjected to a simple harmonic motion
12	Vibration Resistance	D.F. Q	Char. Specification X7R D.F.≤0.025 SL Q≥400+20C*² (C<30pF)	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board
13	Deflection	n	No cracking or marking defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s pressurize Pressurize (in mm) Fig. 3
14	Solderab Terminati		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder
15	Appearance Capacitance Change Resistance to Soldering		No marking defects Char. Capacitance Change X7R Within ±10% SL Within ±2.5% or ±0.25pF (Whichever is larger)	Preheat the capacitor as table. Immerse the capacitor in solder solution at 260±5°C for 10±1 sec. Let sit at room condition*¹ for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s •Pretreatment for X7R char. Perform a heat treatment at 150±10°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*¹.
	Heat	I.R. Dielectric Strength	More than 1,000MΩ In accordance with item No.4	*Preheating Step Temperature Time 1

^{*1 &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



^{*2 &}quot;C" expresses nominal capacitance value (pF).

No.	Ite	m	Specifications	Test Method			
		Appearance Capacitance Change	No marking defects Char. Capacitance Change X7R Within ±15% SL Within ±2.5% or ±0.25pF (Whichever is larger)	Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table. Let sit for 24±2 hrs. at room condition*1, then measure. Step Temperature (°C) Time (min.) 1 Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3			
16	Temperature Cycle	D.F. Q	Char. Specification X7R D.F.≤0.05 SL Q≥400+20C*² (C<30pF)	3 Max. Operating Temp.±2 30±3 4 Room Temp. 2 to 3 •Pretreatment for X7R char. Perform a heat treatment at 150±18℃ for 60±5 min. and ther			
		Dielectric Strength	In accordance with item No.4	let sit for 24±2 hrs. at room condition*1.			
		Appearance Capacitance Change	No marking defects Char. Capacitance Change X7R Within ±15% SL Within ±5.0% or ±0.5pF (Whichever is larger)	Before this test, the test shown in the following is performedItem 11 Adhesive Strength of Termination (applied force is 5N) -Item 13 Deflection			
17	Humidity (Steady State)	Steady Char. Specification		Let the capacitor sit at 40±2°C and relative humidity of 90 to 95° for 500±2°6 hrs. Remove and let sit for 24±2 hrs. at room condition*¹, then measure. •Pretreatment for X7R char. Perform a heat treatment at 150±₁8°C for 60±5 min. and ther let sit for 24±2 hrs. at room condition*¹.			
		Dielectric Strength	In accordance with item No.4				
		Appearance Capacitance Change	No marking defects Char. Capacitance Change X7R Within ±20% SL Within ±3.0% or ±0.3pF (Whichever is larger)	Before this test, the test shown in the following is performed. Item 11 Adhesive Strength of Termination (apply force is 5N) Item 13 Deflection Impulse Voltage Each individual capacitor should be subjected to a 2.5kV (Type			
10	1.55-	D.F. Q	Char. Specification X7R D.F.≤0.05 SL Q≥275+5/2C*² (C<30pF)	be subjected to a 2.5kV (Type GC/GF: 5kV) Impulse (the voltage value means zero to peak) for three times. Then the capacitors are applied to life test. Apply voltage as Table for 1,000 hrs. at 125 ± 6 °C, relative			
18	Life	I.R.	More than $3{,}000M\Omega$	humidity 50% max.			
		Dielectric Strength	In accordance with item No.4	Applied Voltage GB AC312.5V (r.m.s.), except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 sec. GC GD AC425V (r.m.s.), except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 sec. Let sit for 24±2 hrs. at room condition*¹, then measure. •Pretreatment for X7R char. Perform a heat treatment at 150±18° c for 60±5 min. and then let sit for 24±2 hrs. at room condition*¹.			

^{*1 &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa





^{*2 &}quot;C" expresses nominal capacitance value (pF).

	1			
$ \lambda $	Continued	from the	preceding	page.

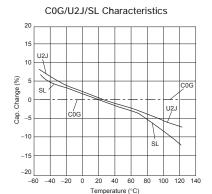
No.	Ite	em	Specifications	Test Method
	Appearance Capacitance Change Humidity Loading D.F. Q I.R.		No marking defects Char. Capacitance Change X7R Within ±15% SL Within ±5.0% or ±0.5pF (Whichever is larger)	Before this test, the test shown in the following is performedItem 11 Adhesive Strength of Termination (apply force is 5N) -Item 13 Deflection
19			$\begin{tabular}{ c c c c c }\hline Char. & Specification \\\hline X7R & D.F. \le 0.05 \\\hline SL & Q \ge 275 + 5/2C^{*2} (C < 30pF) \\\hline Q \ge 350 & (C \ge 30pF) \\\hline More than $3,000M\Omega$\\\hline \end{tabular}$	Apply the rated voltage at 40±2°C and relative humidity of 90 to 95% for 500±2°3 hrs. Remove and let sit for 24±2 hrs. at room condition*1, then measure. •Pretreatment for X7R char. Perform a heat treatment at 150±18°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*1.
		Dielectric Strength	In accordance with item No.4	
20	Strength		The cheesecloth should not be on fire.	The capacitor should be individually wrapped in at least one but not more than two complete layers of cheesecloth. The capacitor should be subjected to 20 discharges. The interval between successive discharges should be 5 sec. The UAC should be maintained for 2 min. after the last discharge. C1,2: 1µF±10% C3: 0.033µF±5% 10kV L1 to 4: 1.5mH±20% 16A Rod core choke Ct: 3µF±5% 10kV R: 1000±2% Cx: Capacitor under test UAC: UR±5% F: Fuse, Rated 16A UR: Rated Voltage Ut: Voltage applied to Ct Ux Type Ui GB, GD 2.5kV GC, GF 5kV
21	Passive Flammab	ility	The burning time should not exceed 30 sec. The tissue paper should not ignite.	The capacitor under test should be held in the flame in the position which best promotes burning. Each specimen should only be exposed once to the flame. Time of exposure to flame: 30 sec. Length of flame: 12±1mm Gas burner : Length 35mm min. Inside Dia. 0.5±0.1mm Outside Dia. 0.9mm max. Gas : Butane gas Purity 95% min. Test Specimen Tissue About 10mm Thick Board

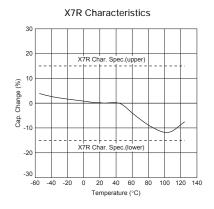
^{*1 &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

^{*2 &}quot;C" expresses nominal capacitance value (pF).

GRM/GR4/GR7/GA2/GA3 Series Data (Typical Example)

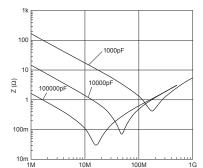
■ Capacitance - Temperature Characteristics





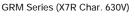
GR4 Series 20 10 Cap. Change (%) -10 -15 -20 -40 -20 40 60 100 120 140 -60 20 80 Temperature (°C)

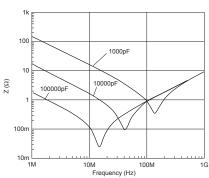
■ Impedance - Frequency Characteristics



Frequency (Hz)

GRM Series (X7R Char. 250V)





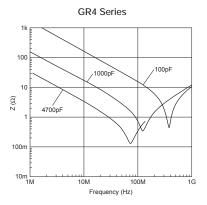


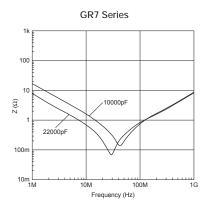


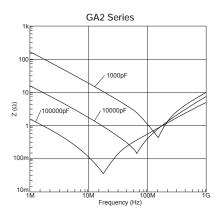
GRM/GR4/GR7/GA2/GA3 Series Data (Typical Example)

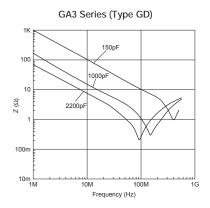
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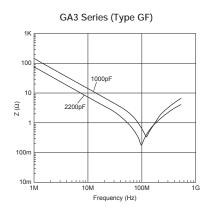
■ Impedance - Frequency Characteristics

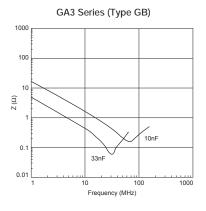








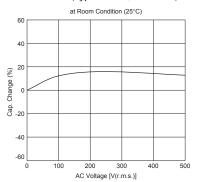




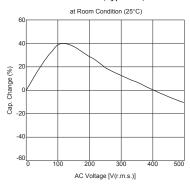
GRM/GR4/GR7/GA2/GA3 Series Data (Typical Example)

■ Capacitance - AC Voltage Characteristics

GA3 Series (Type GD/GF, X7R char.)



GA3 Series (Type GB)



Package

Taping is standard packaging method.

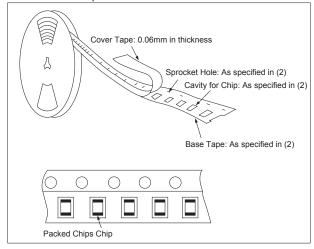
■ Minimum Quantity Guide

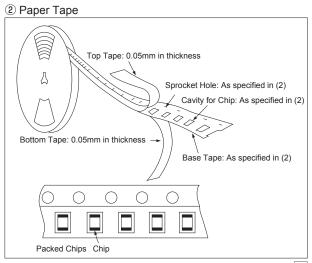
			Dimensions (mm	,	Quantity (pcs.)		
Part Nu	mber		Difficusions (fill)	"	ø180m	m Reel	
		L	W	Т	Paper Tape	Embossed Tape	
	GRM18	1.6	0.8	0.8	4,000	-	
	GRM21	2.0	4.05	1.0	4,000	-	
	GRWIZI	2.0	1.25	1.25	-	3,000	
				1.0	4,000	-	
	GRM31/GR731	3.2	1.6	1.25	-	3,000	
				1.6	-	2,000	
				1.0	4,000	•	
	GRM32	3.2	2.5	1.25	-	3,000	
Medium-voltage	GRIVI32	3.∠	2.5	1.5	-	2,000	
				2.0	-	1,000	
	GRM42/GR442	4.5 2.0		1.0	-	3,000	
			2.0	1.5	-	2,000	
				2.0	-	2,000 2,000	
	GRM43/GR443	4.5		1.5	-	1,000	
			3.2	2.0	-	1,000	
				2.5	-	Reel Embossed Tape 3,000 - 3,000 2,000 - 3,000 2,000 1,000 3,000 2,000 2,000 1,000 3,000 2,000 1,000	
	GRM55/GR455	5.7	5.0	2.0	-	1,000	
	GA242	4.5	2.0	1.5	-	2,000	
AC250V	CA242	4.5	3.2	1.5	-	1,000	
ACZOUV	GA243			2.0	-	1,000	
	GA255	5.7	5.0	2.0	-	1,000	
				1.0	-	3,000	
	GA342	4.5	2.0	1.5	-	2,000	
				2.0	-	2,000	
Safety Std.	GA343	4.5	3.2	1.5	-	1,000	
Recognition	GA343	4.5	3.2	2.0	-	1,000	
	GA352	5.7	2.8	1.5	-	1,000	
				1.5	-	1,000	
	GA355	5.7	5.0	2.0	-	1,000	
				2.7	-	500	

■ Tape Carrier Packaging

(1) Appearance of Taping

① Embossed Tape





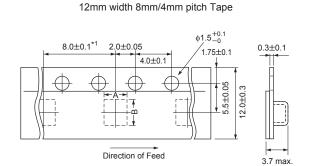


Package

- Continued from the preceding page.
- (2) Dimensions of Tape
- ① Embossed Tape

4.0±0.05 0.25±0.1 2.0±0.05 4.0±0.1 1.75±0.1 8.0±0.3

8mm width 4mm pitch Tape



Part Number	A*	B*
GRM21 (T≧1.25mm)	1.45	2.25
GRM31/GR731 (T≧1.25mm)	2.0	3.6
GRM32 (T≧1.25mm)	2.9	3.6

Direction of Feed

*Nominal Value

2.5 max.

Part Number	A*	B*
GRM42/GR442/GA242/GA342	2.5	5.1
GRM43/GR443/GA243/GA343	3.6	4.9
GA352	3.2	6.1
GRM55/GR455/GA255/GA355	5.4	6.1

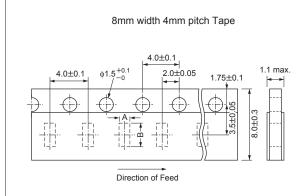
*1 4.0±0.1mm in case of GRM42/GR442/GA242/GA342

(3) Dimensions of Reel

*Nominal Value

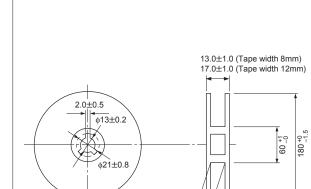
(in mm)

2 Paper Tape



Part Number	A*	B*
GRM18	1.05	1.85
GRM21 (T=1.0mm)	1.45	2.25
GRM31/GR731 (T=1.0mm)	2.0	3.6
GRM32 (T=1.0mm)	2.9	3.6

*Nominal value (in mm)





Continued on the following page.

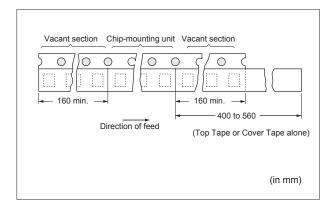
(in mm)

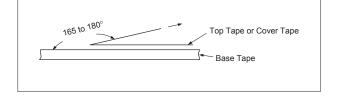
Package

Continued from the preceding page.

(4) Taping Method

- $\ensuremath{\mathbb{1}}$ Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
- 2 Part of the leader and part of the empty tape should be attached to the end of the tape as shown at right.
- 3 The top tape or cover tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 4 Missing capacitors number within 0.1% of the number per reel or 1 pc, whichever is greater, and are not continuous.
- 5 The top tape or cover tape and bottom tape should not protrude beyond the edges of the tape and should not cover sprocket holes.
- 6 Cumulative tolerance of sprocket holes, 10 pitches:
- 7 Peeling off force: 0.1 to 0.6N in the direction shown at right.







■ Storage and Operating Conditions

Operating and storage environment Do not use or store capacitors in a corrosive atmosphere, especially where chloride gas, sulfide gas, acid, alkali, salt or the like are present. And avoid exposure to moisture. Before cleaning, bonding or molding this product, verify that these processes do not affect product quality by testing the performance of a cleaned, bonded or molded product in the intended equipment. Store the capacitors

where the temperature and relative humidity do not exceed 5 to 40 degrees centigrade and 20 to 70%. Use capacitors within 6 months after delivered. Check the solderability after 6 months or more.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.

■ Handling

- 1. Vibration and impact Do not expose a capacitor to excessive shock or vibration during use.
- 2. Do not directly touch the chip capacitor, especially the ceramic body. Residue from hands/fingers may create a short circuit environment.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.



⚠Caution

■ Caution (Rating)

1. Operating Voltage

When DC-rated capacitors are to be used in AC or ripple current circuits, be sure to maintain the Vp-p value of the applied voltage or the Vo-p which contains DC bias within the rated voltage range.

When the voltage is applied to the circuit, starting or stopping may generate irregular voltage for a transit period because of resonance or switching. Be sure to use a capacitor with a rated voltage range that includes these irregular voltages.

Voltage	DC Voltage	DC+AC Voltage	AC Voltage	Pulse Voltage (1)	Pulse Voltage (2)
Positional Measurement	V0-p	Vo-p	Vp-p	Vp-p	Vp-p

- 2. Operating Temperature, Self-generated Heat, and Lead Reduction at High-frequency voltage condition Keep the surface temperature of a capacitor below the upper limit of its rated operating temperature range. Be sure to take into account the heat generated by the capacitor itself. When the capacitor is used in a highfrequency voltage, pulse voltage, it may self-generate heat due to dielectric loss.
- (1) In case of X7R char.

Applied voltage should be the load such as selfgenerated heat is within 20°C on the condition of atmosphere temperature 25°C. When measuring, use a thermocouple of small thermal capacity -K of ø0.1mm in conditions where the capacitor is not affected by radiant heat from other components or surrounding ambient fluctuations. Excessive heat may lead to deterioration of the capacitor's characteristics and reliability. (Never attempt to perform measurement with the cooling fan running. Otherwise, accurate measurement cannot be ensured.)



∆Caution

Continued from the preceding page

(2) In case of COG, U2J char.

Due to the low self-heating characteristics of lowdissipation capacitors, the allowable electric power of these capacitors is generally much higher than that of X7R characteristic capacitors.

When a high frequency voltage which cause 20°C self heating to the capacitor is applied, it will exceed capacitor's allowable electric power.

<C0G char.>

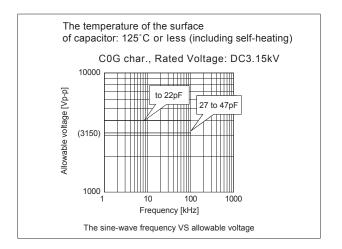
Therefore, in case of COG char., the frequency of the applied sine wave voltage should be less than 100kHz. The applied voltage should be less than the value shown in figure at right. The capacitors less than 22pF can be applied maximum 4.0kV peak to peak at 100kHz or less only for the ballast or the resonance usage in the LCD backlight inverter circuit.

<U2J char.>

In case of U2J char., the frequency of the applied sine wave voltage should be less than 500kHz (less than 100kHz in case of rated voltage: DC3.15kV). The applied voltage should be less than the value shown in figure below.

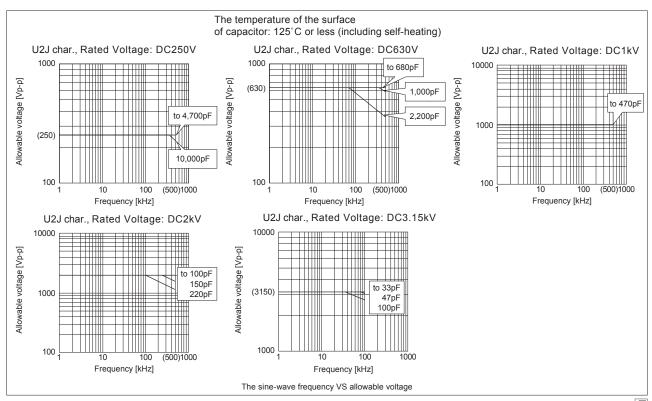
<Capacitor selection tool>

We are also offering free software the "capacitor selection tool: Murata Medium Voltage Capacitors Selection Tool by Voltage Form (*)" which will assist you in selecting a suitable capacitor.



The software can be downloaded from Murata's Internet Website (http://www.murata.com/designlib/mmcsv_e.html). By inputting capacitance values and applied voltage waveform of the specific capacitor series, this software will calculate the capacitor's power consumption and list suitable capacitors (non-sine wave is also available).

- * As of Jul. 2006, subject series are below.
- · Temperature Characteristics C0G, U2J







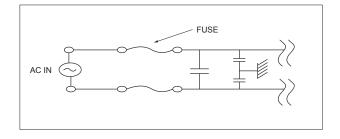
⚠Caution

Continued from the preceding page.

3. Fail-safe

Failure of a capacitor may result in a short circuit. Be sure to provide an appropriate fail-safe function such as a fuse on your product to help eliminate possible electric shock, fire, or fumes.

Please consider using fuses on each AC line if the capacitors are used between the AC input lines and earth (line bypass capacitors), to prepare for the worst case, such as a short circuit.



4. Test condition for AC withstanding Voltage

(1) Test Equipment

Tests for AC withstanding voltage should be made with equipment capable of creating a wave similar to a 50/60 Hz sine wave.

If the distorted sine wave or overload exceeding the specified voltage value is applied, a defect may be caused.

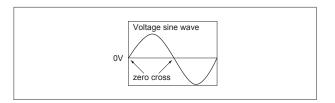
(2) Voltage applied method

The capacitor's leads or terminals should be firmly connected to the output of the withstanding voltage test equipment, and then the voltage should be raised from near zero to the test voltage. If the test voltage is applied directly to the capacitor without raising it from near zero, it should be applied with the zero cross*. At the end of the test time, the test voltage should be reduced to near zero, and then the capacitor's leads or terminals should be taken off the output of the withstanding voltage test equipment. If the test voltage is applied directly to the capacitor without raising it from near zero, surge voltage may occur and cause a defect.

*ZERO CROSS is the point where voltage sine wave pass 0V.

- See the figure at right -

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.







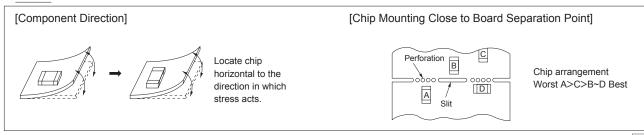
■ Caution (Soldering and Mounting)

1. Vibration and Impact Do not expose a capacitor to excessive shock or vibration during use.

2. Circuit Board Material

In case that ceramic chip capacitor is soldered on the metal board, such as Aluminum board, the stress of heat expansion and contraction might cause the crack of ceramic capacitor, due to the difference of thermal expansion coefficient between metal board and ceramic chip.

3. Land Layout for Cropping PC Board Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.





Continued from the preceding page

4. Reflow Soldering

- When sudden heat is given to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity of components inside. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in Table 1. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as
- Solderability of Tin plating termination chip might be deteriorated when low temperature soldering profile where peak solder temperature is below the Tin melting point is used. Please confirm the solderability of Tin plating termination chip before use.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference (ΔT) between the component and solvent within the range shown in the Table 1.

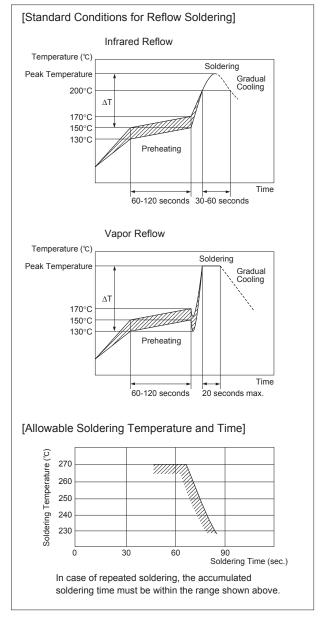
Table 1

Part Number	Temperature Differential
G□□18/21/31	ΔΤ≦190℃
G 32/42/43/52/55	ΔΤ≦130℃

Recommended Conditions

	Pb-Sn S		
	Infrared Reflow	Vapor Reflow	Lead Free Solder
Peak Temperature	230-250°C	230-240°C	240-260°C
Atmosphere	Air	Air	Air or N2

Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

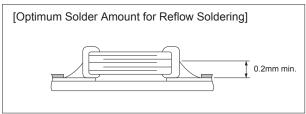


Optimum Solder Amount for Reflow Soldering

- Overly thick application of solder paste results in excessive fillet height solder.
 - This makes the chip more susceptible to mechanical and thermal stress on the board and may cause cracked
- Too little solder paste results in a lack of adhesive strength on the outer electrode, which may result in chips breaking loose from the PCB.
- Make sure the solder has been applied smoothly to the end surface to a height of 0.2mm min.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.





Continued from the preceding page.

5. Flow Soldering

- When sudden heat is given to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity of components inside. And an excessively long soldering time or high soldering temperature results in leaching by the outer electrodes, causing poor adhesion or a reduction in capacitance value due to loss of contact between electrodes and end termination.
- In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in Table 2. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference between the component and solvent within the range shown in Table 2.

Do not apply flow soldering to chips not listed in Table 2.

Table 2

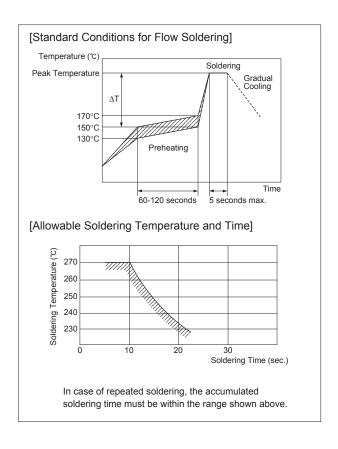
Part Number	Temperature Differential
G□□18/21/31	∆T≦150°C

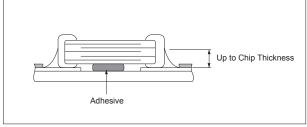
Recommended Conditions

	Pb-Sn Solder	Lead Free Solder
Peak Temperature	240-250°C	250-260°C
Atmosphere	Air	N ₂

Ph-Sn Solder: Sn-37Ph Lead Free Solder: Sn-3.0Ag-0.5Cu

 Optimum Solder Amount for Flow Soldering The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions.







1 Caution

- Continued from the preceding page.
- 6. Correction with a Soldering Iron
- (1) For Chip Type Capacitors
- When sudden heat is applied to the components by soldering iron, the mechanical strength of the components should go down because remarkable temperature change causes deformity of components inside. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in Table 3. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible. After soldering, it should not be allowed to cool down rapidly.

Table 3

Part Number	Temperature Differential	Peak Temperature	Atmosphere
G□□18/21/31	ΔT≦190°C	300°C max. 3 sec. max. / termination (both sides total 6 sec. max.)	Air
G□□32/42/43/ 52/55	ΔΤ≦130℃	270°C max. 3 sec. max. / termination (both sides total 6 sec. max.)	Air

^{*}Applicable for both Pb-Sn and Lead Free Solder.

Pb-Sn Solder: Sn-37Pb

Lead Free Solder: Sn-3.0Ag-0.5Cu

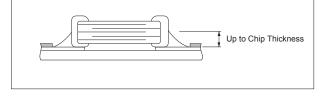
 Optimum Solder Amount when Corrections Are Made Using a Soldering Iron

The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions. Soldering iron ø3mm or smaller should be required. And it is necessary to keep a distance between the soldering iron and the components without direct touch. Thread solder with Ø0.5mm or smaller is required for soldering.



Excessive output of ultrasonic oscillation during cleaning causes PCBs to resonate, resulting in cracked chips or broken solder. Take note not to vibrate PCBs.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND FUMING WHEN THE PRODUCT IS USED.

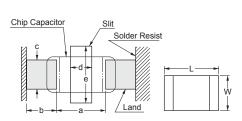


Notice

■ Notice (Soldering and Mounting)

1. Construction of Board Pattern After installing chips, if solder is excessively applied to the circuit board, mechanical stress will cause destruction resistance characteristics to lower. To prevent this, be extremely careful in determining shape and dimension before designing the circuit board diagram.

Construction and Dimensions of Pattern (Example)



Preparing slit helps flux cleaning and resin coating on the back of the capacitor.

Flow Soldering

L×W	а	b	С
1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8
2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1
3.2×1.6	2.2-2.6	1.0-1.1	1.0-1.4

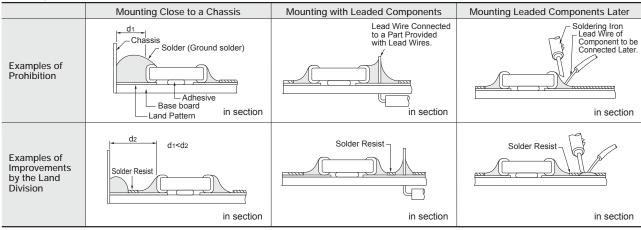
Flow soldering: 3.2×1.6 or less available.

Reflow Soldering

L×W	a	b	С	d	е
1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	-	-
2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1	-	-
3.2×1.6	2.2-2.4	0.8-0.9	1.0-1.4	1.0-2.0	3.2-3.7
3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	1.0-2.0	4.1-4.6
4.5×2.0	2.8-3.4	1.2-1.4	1.4-1.8	1.0-2.8	3.6-4.1
4.5×3.2	2.8-3.4	1.2-1.4	2.3-3.0	1.0-2.8	4.8-5.3
5.7×2.8	4.0-4.6	1.4-1.6	2.1-2.6	1.0-4.0	4.4-4.9
5.7×5.0	4.0-4.6	1.4-1.6	3.5-4.8	1.0-4.0	6.6-7.1

(in mm)

Land Layout to Prevent Excessive Solder







Notice

Continued from the preceding page.

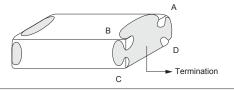
- 2. Mounting of Chips
- Thickness of adhesives applied Keep thickness of adhesives applied (50-105μm or more) to reinforce the adhesive contact considering the thickness of the termination or capacitor (20-70µm) and the land pattern (30-35µm).
- Mechanical shock of the chip placer When the positioning claws and pick-up nozzle are worn, the load is applied to the chip while positioning is concentrated in one position, thus causing cracks, breakage, faulty positioning accuracy, etc. Careful checking and maintenance are necessary to prevent unexpected trouble. An excessively low bottom dead point of the suction nozzle imposes great force on the chip during mounting, causing cracked chips. Please set the suction nozzle's bottom dead point on the upper surface of the board.

3. Soldering

(1) Limit of losing effective area of the terminations and conditions needed for soldering.

Depending on the conditions of the soldering temperature and/or immersion (melting time), effective areas may be lost in some part of the terminations.

To prevent this, be careful in soldering so that any possible loss of the effective area on the terminations will securely remain at a maximum of 25% on all edge length A-B-C-D-A of part with A, B, C, D, shown in the Figure below.



 Please use it after confirming there is no problem in the reliability of the product beforehand with the intended equipment. The residue of flux might cause a decrease in nonconductivity and the corrosion of an external electrode, etc.



Notice

Continued from the preceding page.

4. Cleaning

Please confirm there is no problem in the reliability of the product beforehand when cleaning it with the intended

The residue after cleaning it might cause the decrease in the surface resistance of the chip and the corrosion of the electrode part, etc. As a result it might cause reliability to deteriorate. Please confirm beforehand that there is no problem with the intended equipment in ultrasonic cleansing.

5. Resin Coating

Please use it after confirming there is no influence on the product with a intended equipment beforehand when the resin coating and molding.

A cracked chip might be caused at the cooling/heating cycle by the amount of resin spreading and/or bias

The resin for coating and molding must be selected as the stress is small when stiffening and the hygroscopic is low as possible.

Rating

- 1. Capacitance change of capacitor
- (1) In case of X7R char.

Capacitors have an aging characteristic, whereby the capacitor continually decreases its capacitance slightly if the capacitor is left on for a long time. Moreover, capacitance might change greatly depending on the surrounding temperature or an applied voltage. So, it is not likely to be suitable for use in a time constant circuit. Please contact us if you need detailed information.

(2) In case of any char. except X7R Capacitance might change a little depending on the surrounding temperature or an applied voltage. Please contact us if you intend to use this product in a strict time constant circuit.

2. Performance check by equipment

Before using a capacitor, check that there is no problem in the equipment's performance and the specifications.

Generally speaking, CLASS 2 (X7R char.) ceramic capacitors have voltage dependence characteristics and temperature dependence characteristics in capacitance. So, the capacitance value may change depending on the operating condition in the equipment. Therefore, be sure to confirm the apparatus performance of receiving influence in a capacitance value change of a capacitor, such as leakage current and noise suppression characteristics. Moreover, check the surge-proof ability of a capacitor in the equipment, if needed, because the surge voltage may exceed specific value by the inductance of the circuit.



ISO 9001 Certifications

■ Qualified Standards

The products listed here have been produced by ISO 9001 certified factory.

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